

MSP430F524x、MSP430F523x 混合信号微控制器

1 器件概述

1.1 特性

- 低电源电压范围：
3.6V 到 1.8V
- 超低功耗
 - 激活模式 (AM):
所有系统时钟激活
在 8MHz, 3.0V, 闪存程序执行时为 290μA/MHz (典型值)
在 8MHz, 3.0V, RAM 程序执行时为 150μA/MHz (典型值)
 - 待机模式 (LPM3):
带有晶振的实时时钟 (RTC), 看门狗和电源监视器可用, 完全 RAM 保持, 快速唤醒:
2.2V 时为 1.9μA, 3.0V 时为 2.1μA (典型值)
低功耗振荡器 (VLO), 通用计数器, 看门狗和电源监视器可用, 完全 RAM 保持, 快速唤醒:
3.0V 时为 1.4μA (典型值)
 - 关闭模式 (LPM4):
完全 RAM 保持, 电源监视器可用, 快速唤醒:
3.0V 时为 1.1μA (典型值)
 - 关断模式 (LPM4.5):
3.0V 时为 0.18μA (典型值)
- 在 3.5μs (典型值) 内从待机模式唤醒
- 16 位精简指令集计算机 (RISC) 架构, 扩展内存, 高达 25MHz 的系统时钟
- 灵活的电源管理系统
 - 内置可编程的低压降稳压器 (LDO)
 - 电源电压监控、监视、和临时限电
- 统一时钟系统
 - 针对频率稳定的锁相环 (FLL) 控制环路
 - 低功耗低频内部时钟源 (VLO)
 - 低频修整内部基准源 (REFO)
 - 32kHz 手表晶振 (XT1)
 - 高达 32MHz 的高频晶振 (XT2)
- 具有 5 个捕捉/比较寄存器的 16 位定时器 TA0, Timer_A
- 具有 3 个捕捉/比较寄存器的 16 位定时器 TA1, Timer_A
- 具有 3 个捕捉/比较寄存器的 16 位定时器 TA2, Timer_A
- 具有 7 个捕捉/比较影子寄存器的 16 位定时器 TB0, Timer_B
- 两个通用串行通信接口 (USCI)
 - USCI_A0 和 USCI_A1 均支持:
 - 具有自动波特率检测功能的增强型通用异步收发器 (UART)
 - IrDA 编码和解码
 - 同步串行外设接口 (SPI)
 - USCI_B0 和 USCI_B1 每个都支持:
 - I²C
 - 同步串行外设接口 (SPI)
- 带内部基准、采样与保持功能的 10 位模数转换器 (ADC)
- 比较器
- 硬件乘法器支持 32 位运算
- 串行板上编程, 无需外部编程电压
- 3 通道内部 DMA
- 具有 RTC 特性的基本计时器
- [器件比较](#) 汇总了系列产品成员

1.2 应用

- 模拟传感器系统
- 数字传感器系统
- 数据记录器
- 通用应用

1.3 说明

TI MSP 系列超低功耗微控制器种类繁多，各成员器件配备不同的外设集以满足各类应用的需求。此架构与多种低功耗模式配合使用，是延长便携式测量应用电池寿命的最优选择。该器件具有一个强大的 16 位 RISC CPU，使用 16 位寄存器以及常数发生器，以便获得最高编码效率。此数控振荡器 (DCO) 可使器件在 3.5μs（典型值）内从低功率模式唤醒至激活模式。

MSP430F524x 系列属于微控制器，配有四个 16 位定时器、一个高性能 10 位 ADC、两个 USCI、一个硬件乘法器、DMA、一个比较器以及一个具有报警功能的 RTC 模块。

MSP430F523x 系列微控制器包含 MSP430F524x 系列除 ADC 以外的所有外设。

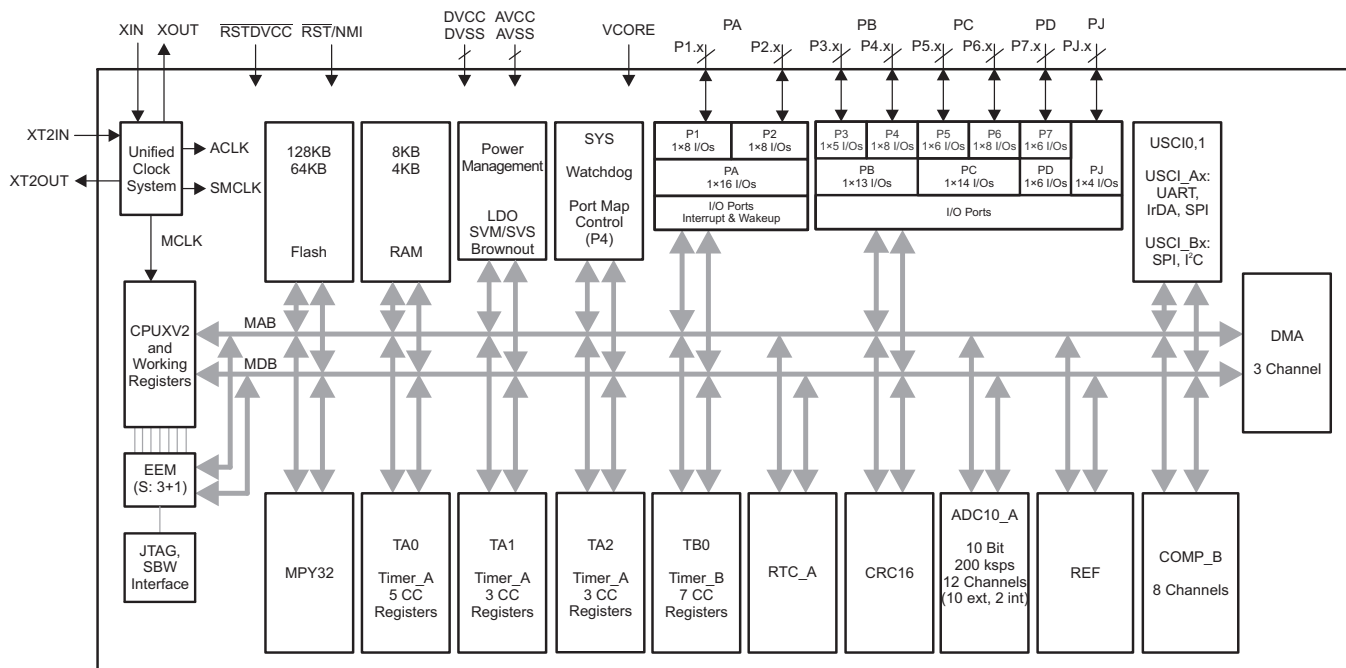
有关完整的模块说明，请参阅《MSP430F5xx 和 MSP430F6xx 系列用户指南》。

器件信息 ⁽¹⁾		
器件型号	封装	封装尺寸 ⁽²⁾
MSP430F5249IRGC	VQFN (64)	9mm x 9mm
MSP430F5249IZQE	BGA (80)	5mm x 5mm
MSP430F5244IRGZ	VQFN (48)	7mm x 7mm

- (1) 要获得所有可用器件的最新部件、封装和订购信息，请参见封装选项附录（节 8）或浏览 TI 网站 www.ti.com.cn。
- (2) 这里显示的尺寸为近似值。要获得包含误差值的封装尺寸，请参见机械数据（节 8）。

1.4 功能方框图

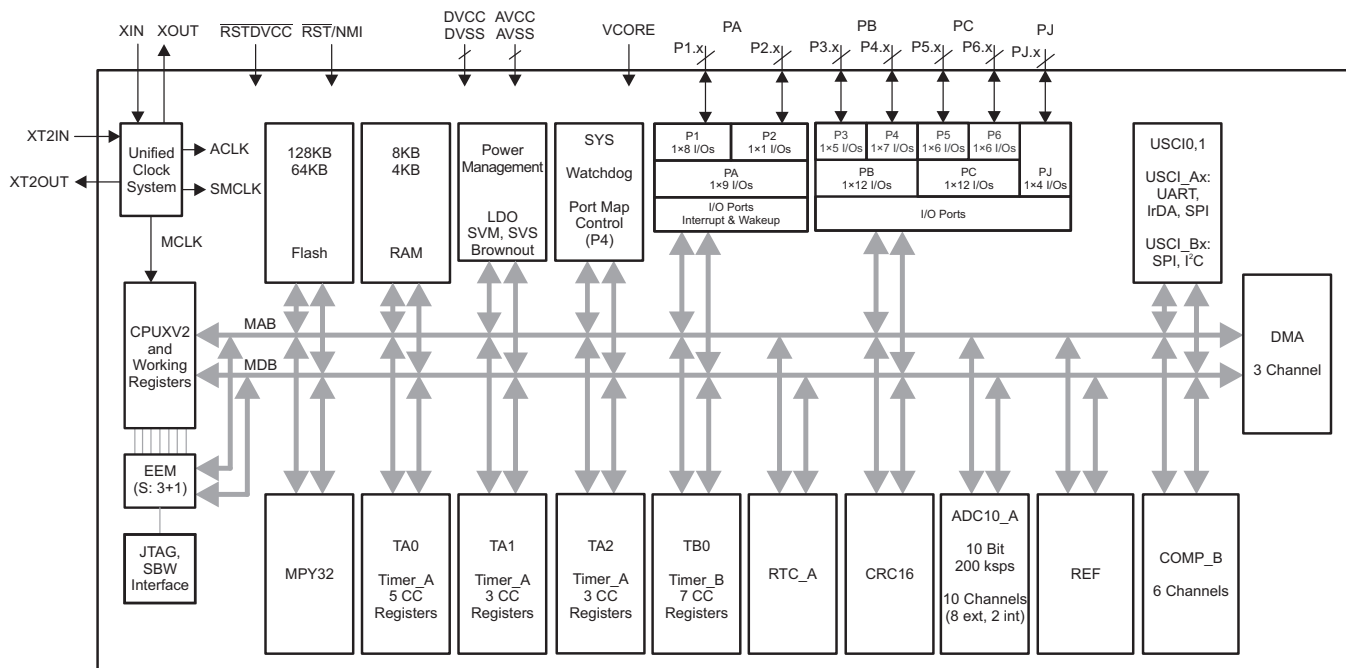
图 1-1 给出了采用 RGC 和 ZQE 封装的 MSP430F5249 和 MSP430F5247 器件的功能方框图。



Copyright © 2016, Texas Instruments Incorporated

图 1-1. 功能方框图 – F5249、F5247 – RGC、ZQE 封装

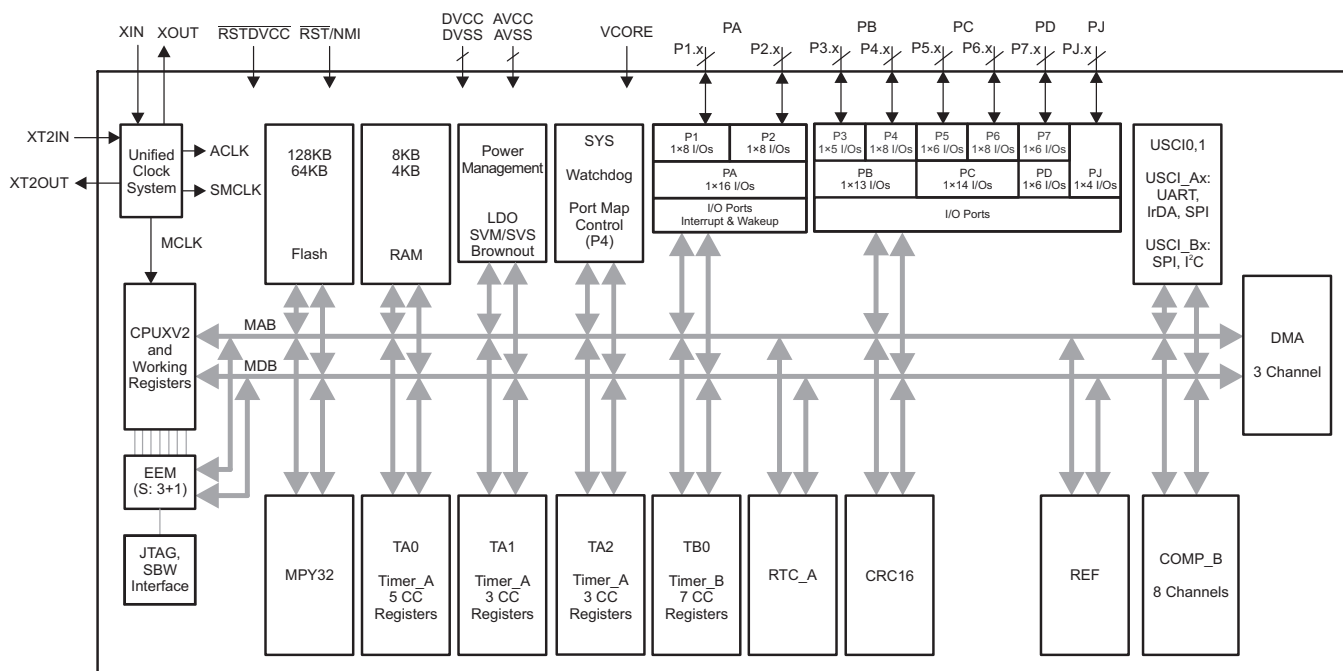
图 1-2 给出了采用 RGZ 封装的 MSP430F5244 和 MSP430F5242 器件的功能方框图。



Copyright © 2016, Texas Instruments Incorporated

图 1-2. 功能方框图 – F5244、F5242 – RGZ 封装

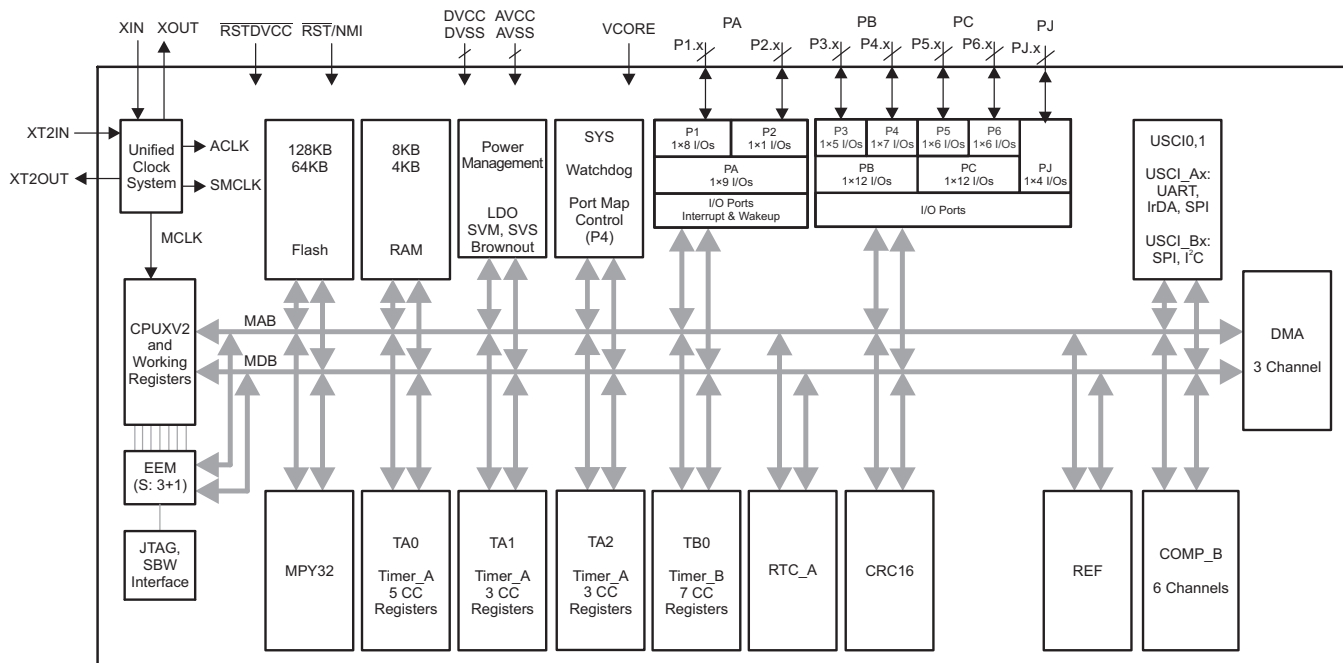
图 1-3 给出了采用 RGC 和 ZQE 封装的 MSP430F5239 和 MSP430F5237 器件的功能方框图。



Copyright © 2016, Texas Instruments Incorporated

图 1-3. 功能方框图 – F5239、F5237 – RGC、ZQE 封装

图 1-4 给出了采用 RGZ 封装的 MSP430F5234 和 MSP430F5232 器件的功能方框图。



Copyright © 2016, Texas Instruments Incorporated

图 1-4. 功能方框图 – F5234、F5232 – RGZ 封装

内容

1	器件概述	1	5.20	PMM, Brownout Reset (BOR)	31
1.1	特性	1	5.21	PMM, Core Voltage	31
1.2	应用	1	5.22	PMM, SVS High Side	32
1.3	说明	2	5.23	PMM, SVM High Side	33
1.4	功能方框图	3	5.24	PMM, SVS Low Side	33
2	修订历史记录	6	5.25	PMM, SVM Low Side	34
3	Device Comparison	7	5.26	Wake-up Times From Low-Power Modes and Reset	34
3.1	Related Products	7	5.27	Timer_A	35
4	Terminal Configuration and Functions	8	5.28	Timer_B	35
4.1	Pin Diagrams	8	5.29	USCI (UART Mode) Clock Frequency	35
4.2	Signal Descriptions	13	5.30	USCI (UART Mode)	35
5	Specifications	18	5.31	USCI (SPI Master Mode) Clock Frequency	36
5.1	Absolute Maximum Ratings	18	5.32	USCI (SPI Master Mode)	36
5.2	ESD Ratings	18	5.33	USCI (SPI Slave Mode)	38
5.3	Recommended Operating Conditions	18	5.34	USCI (I ² C Mode)	40
5.4	Active Mode Supply Current Into V _{CC} Excluding External Current	20	5.35	10-Bit ADC, Power Supply and Input Range Conditions	41
5.5	Low-Power Mode Supply Currents (Into V _{CC}) Excluding External Current	21	5.36	10-Bit ADC, Timing Parameters	41
5.6	Thermal Resistance Characteristics	22	5.37	10-Bit ADC, Linearity Parameters	42
5.7	Schmitt-Trigger Inputs – General-Purpose I/O (P1.0 to P1.7, P2.0 to P2.7, P3.0 to P3.4, P4.0 to P4.7, P5.0 to P5.5, P6.0 to P6.7, P7.0 to P7.5, PJ.0 to PJ.3, RSTDVCC /SBWTDIO, RST /NMI)	23	5.38	REF, External Reference	42
5.8	Inputs – Interrupts (P1.0 to P1.7, P2.0 to P2.7)	23	5.39	REF, Built-In Reference	43
5.9	Leakage Current – General-Purpose I/O (P1.0 to P1.7, P2.0 to P2.7, P3.0 to P3.4, P4.0 to P4.7, P5.0 to P5.5, P6.0 to P6.7, P7.0 to P7.5, PJ.0 to PJ.3)	23	5.40	Comparator_B	44
5.10	Outputs – General-Purpose I/O (Full Drive Strength) (P1.0 to P1.7, P2.0 to P2.7, P3.0 to P3.4, P4.0 to P4.7, P5.0 to P5.5, P6.0 to P6.7, P7.0 to P7.5, PJ.0 to PJ.3)	23	5.41	Flash Memory	45
5.11	Outputs – General-Purpose I/O (Reduced Drive Strength) (P1.0 to P1.7, P2.0 to P2.7, P3.0 to P3.4, P4.0 to P4.7, P5.0 to P5.5, P6.0 to P6.7, P7.0 to P7.5, PJ.0 to PJ.3)	24	5.42	JTAG and Spy-Bi-Wire Interface	45
5.12	Output Frequency – General-Purpose I/O (P1.0 to P1.7, P2.0 to P2.7, P3.0 to P3.4, P4.0 to P4.7, P5.0 to P5.5, P6.0 to P6.7, P7.0 to P7.5, PJ.0 to PJ.3)	24	6	Detailed Description	46
5.13	Typical Characteristics – Outputs, Reduced Drive Strength (PxDS.y = 0)	25	6.1	CPU (Link to User's Guide)	46
5.14	Typical Characteristics – Outputs, Full Drive Strength (PxDS.y = 1)	26	6.2	Operating Modes	47
5.15	Crystal Oscillator, XT1, Low-Frequency Mode	27	6.3	Interrupt Vector Addresses	48
5.16	Crystal Oscillator, XT2	28	6.4	Memory Organization	49
5.17	Internal Very-Low-Power Low-Frequency Oscillator (VLO)	29	6.5	Bootloader (BSL)	50
5.18	Internal Reference, Low-Frequency Oscillator (REFO)	29	6.6	JTAG Operation	50
5.19	DCO Frequency	30	6.7	Flash Memory (Link to User's Guide)	51
			6.8	RAM (Link to User's Guide)	51
			6.9	Peripherals	51
			6.10	Input/Output Diagrams	72
			6.11	Device Descriptors	88
			7	器件和文档支持	94
			7.1	入门和后续步骤	94
			7.2	Device Nomenclature	94
			7.3	工具与软件	96
			7.4	文档支持	98
			7.5	相关链接	98
			7.6	社区资源	99
			7.7	商标	99
			7.8	静电放电警告	99
			7.9	Export Control Notice	99
			7.10	Glossary	99
			8	机械、封装和可订购信息	100

2 修订历史记录

注：之前版本的页码可能与当前版本有所不同。

Changes from November 26, 2015 to September 27, 2018	Page
• Added Section 3.1, Related Products	7
• Added typical conditions statements at the beginning of Section 5, Specifications	18
• Changed the MIN value of the $V_{(DVCC_BOR_hys)}$ parameter from 60 mV to 50 mV in Section 5.20, PMM, Brownout Reset (BOR)	31
• Updated notes (1) and (2) and added note (3) in Section 5.26, Wake-up Times From Low-Power Modes and Reset	34
• Removed ADC10DIV from the formula for the TYP value in the second row of the $t_{CONVERT}$ parameter in Section 5.36, 10-Bit ADC, Timing Parameters , because ADC10CLK is after division	41
• Added second row for t_{EN_CMP} with Test Conditions of "CBPWRMD = 10" and MAX value of 100 μ s in Section 5.40, Comparator_B	44
• Renamed FCTL4.MGR0 and MGR1 bits in the $f_{MCLK,MGR}$ parameter in Section 5.41, Flash Memory , to be consistent with header files	45
• Throughout document, changed all instances of "bootstrap loader" to "bootloader"	50
• 将先前的开发工具支持 部分替换成了 节 7.3, 工具与软件	96
• 更新了 节 7.4 文档支持 中的相关文档列表	98

3 Device Comparison

Table 3-1 summarizes the available family members.

Table 3-1. Device Comparison⁽¹⁾⁽²⁾

DEVICE	FLASH (KB)	SRAM (KB)	Timer_A ⁽³⁾	Timer_B ⁽⁴⁾	USCI		ADC10_A (Ch)	Comp_B (Ch)	I/Os	PACKAGE
					CHANNEL A: UART, IrDA, SPI	CHANNEL B: SPI, I ² C				
MSP430F5249	128	8	5, 3, 3	7	2	2	10 ext, 2 int	8	53	64 RGC 80 ZQE
MSP430F5247	64	8	5, 3, 3	7	2	2	10 ext, 2 int	8	53	64 RGC 80 ZQE
MSP430F5244	128	8	5, 3, 3	7	2	2	8 ext, 2 int	6	37	48 RGZ
MSP430F5242	64	8	5, 3, 3	7	2	2	8 ext, 2 int	6	37	48 RGZ
MSP430F5239	128	8	5, 3, 3	7	2	2	-	8	53	64 RGC 80 ZQE
MSP430F5237	64	8	5, 3, 3	7	2	2	-	8	53	64 RGC 80 ZQE
MSP430F5234	128	8	5, 3, 3	7	2	2	-	6	37	48 RGZ
MSP430F5232	64	8	5, 3, 3	7	2	2	-	6	37	48 RGZ

- (1) For the most current package and ordering information, see the *Package Option Addendum* in 节 8, or see the TI website at www.ti.com.
- (2) Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/packaging.
- (3) Each number in the sequence represents an instantiation of Timer_A with its associated number of capture compare registers and PWM output generators available. For example, a number sequence of 3, 5 would represent two instantiations of Timer_A, the first instantiation having 3 and the second instantiation having 5 capture compare registers and PWM output generators, respectively.
- (4) Each number in the sequence represents an instantiation of Timer_B with its associated number of capture compare registers and PWM output generators available. For example, a number sequence of 3, 5 would represent two instantiations of Timer_B, the first instantiation having 3 and the second instantiation having 5 capture compare registers and PWM output generators, respectively.

3.1 Related Products

For information about other devices in this family of products or related products, see the following links.

Products for TI Microcontrollers TI's low-power and high-performance MCUs, with wired and wireless connectivity options, are optimized for a broad range of applications.

Products for MSP430 Ultra-Low-Power Microcontrollers One platform. One ecosystem. Endless possibilities. Enabling the connected world with innovations in ultra-low-power microcontrollers with advanced peripherals for precise sensing and measurement.

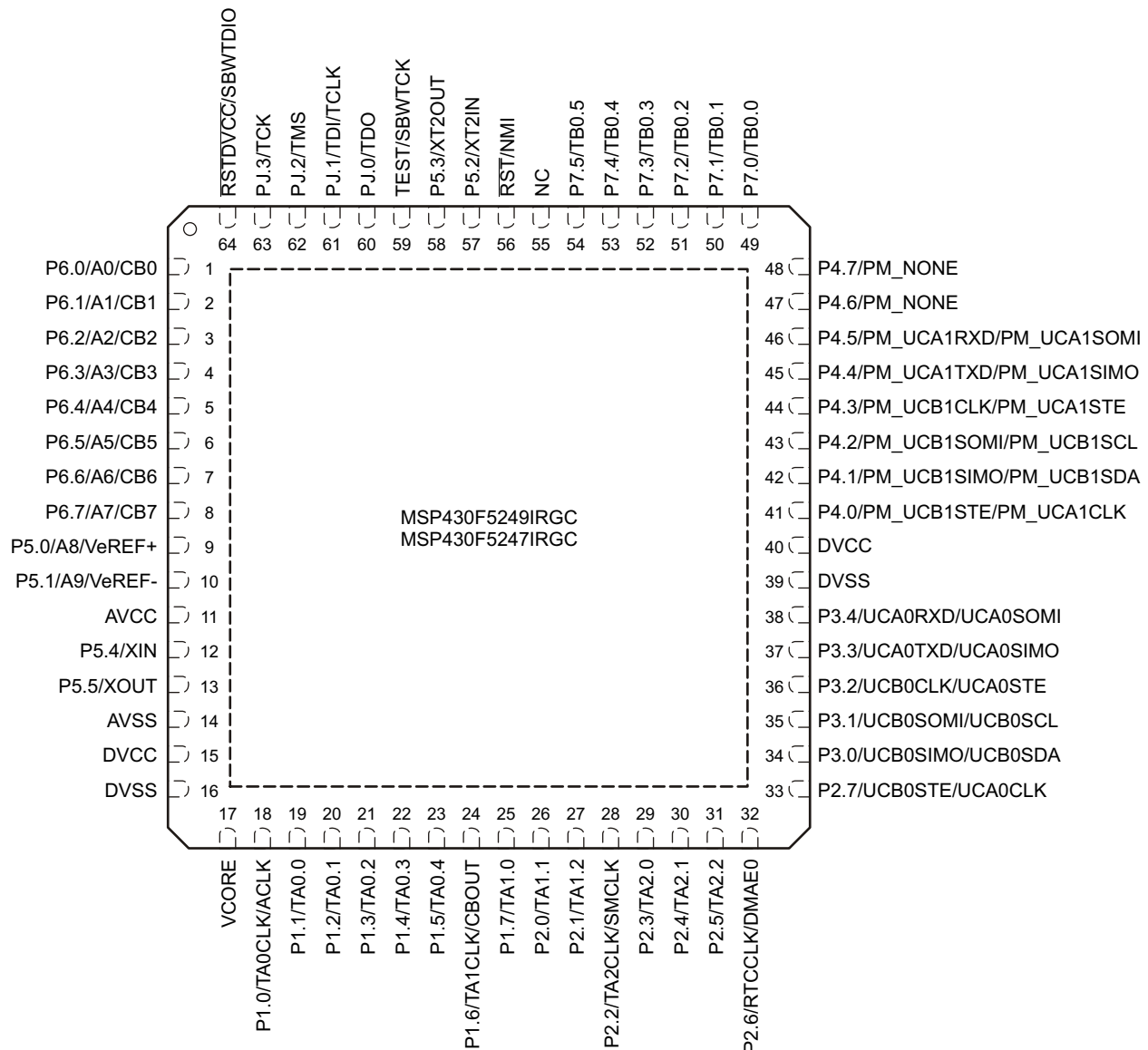
Companion Products for MSP430F5249 Review products that are frequently purchased or used in conjunction with this product.

TI Reference Designs Find reference designs that leverage the best in TI technology to solve your system-level challenges.

4 Terminal Configuration and Functions

4.1 Pin Diagrams

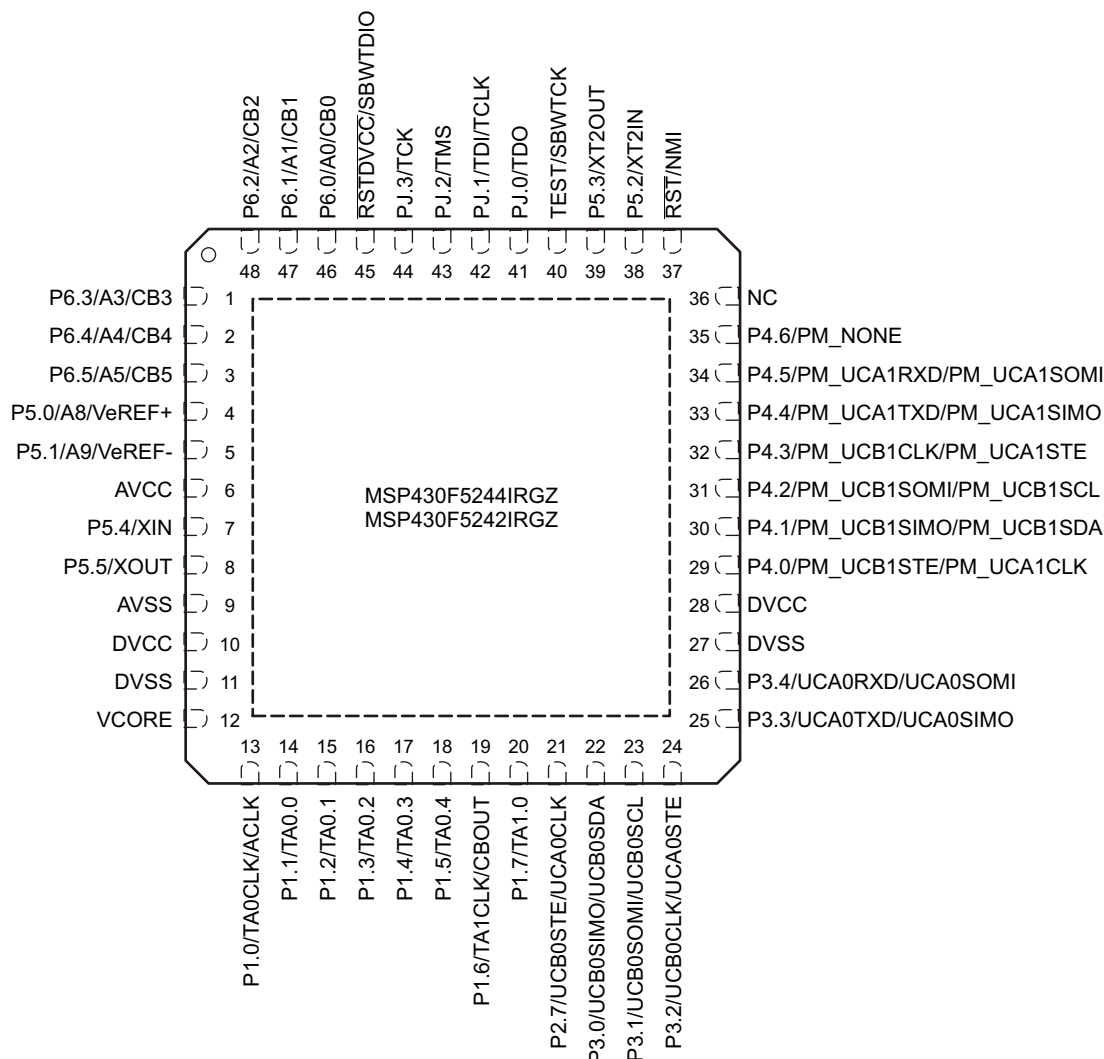
Figure 4-1 shows the pinout for the MSP430F5249 and MSP430F5247 devices in the 64-pin RGC package.



NOTE: TI recommends connecting the exposed thermal pad to V_{SS}.

Figure 4-1. 64-Pin RGC Package (Top View) – MSP430F5249, MSP430F5247

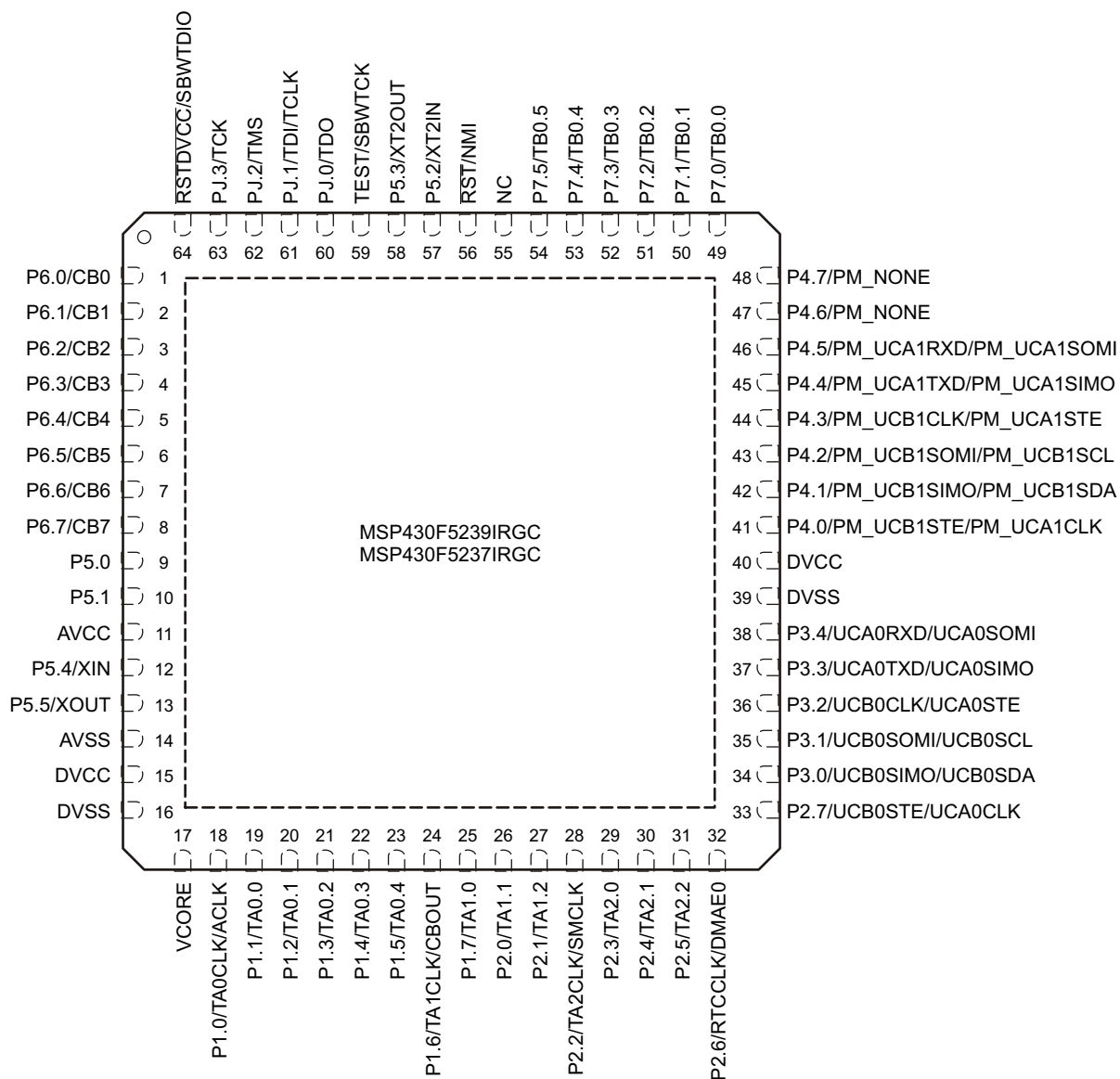
Figure 4-2 shows the pinout for the MSP430F5244 and MSP430F5242 devices in the 48-pin RGZ package.



NOTE: TI recommends connecting the exposed thermal pad to V_{SS}.

Figure 4-2. 48-Pin RGZ Package (Top View) – MSP430F5244, MSP430F5242

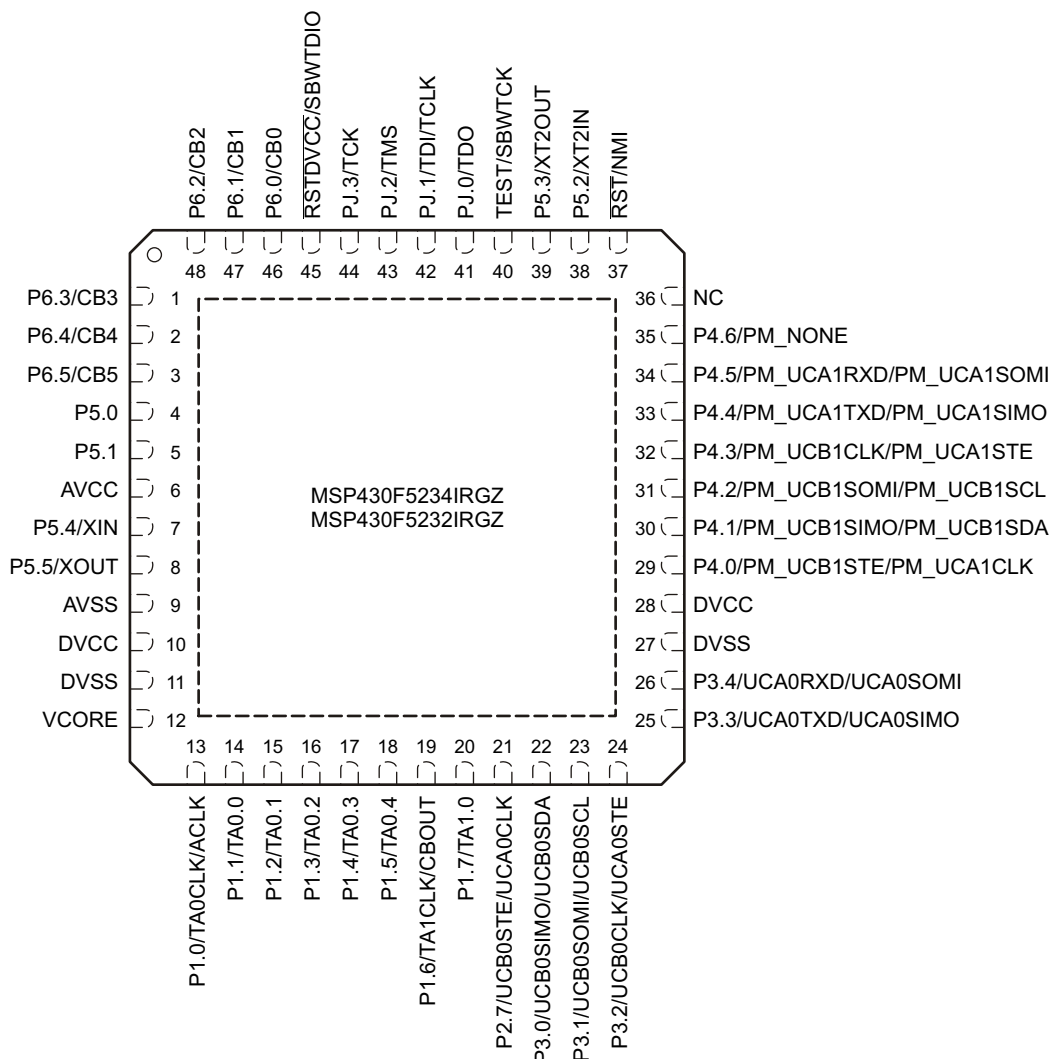
Figure 4-3 shows the pinout for the MSP430F5239 and MSP430F5237 devices in the 64-pin RGC package.



NOTE: TI recommends connecting the exposed thermal pad to V_{SS}.

Figure 4-3. 64-Pin RGC Package (Top View) – MSP430F5239, MSP430F5237

Figure 4-4 shows the pinout for the MSP430F5234 and MSP430F5232 devices in the 48-pin RGZ package.



NOTE: TI recommends connecting the exposed thermal pad to V_{SS}.

Figure 4-4. 48-Pin RGZ Package (Top View) – MSP430F5234, MSP430F5232

Figure 4-5 shows the pinout for the MSP430F5249, MSP430F5247, MSP430F5239, and MSP430F5237 devices in the 80-pin ZQE package.

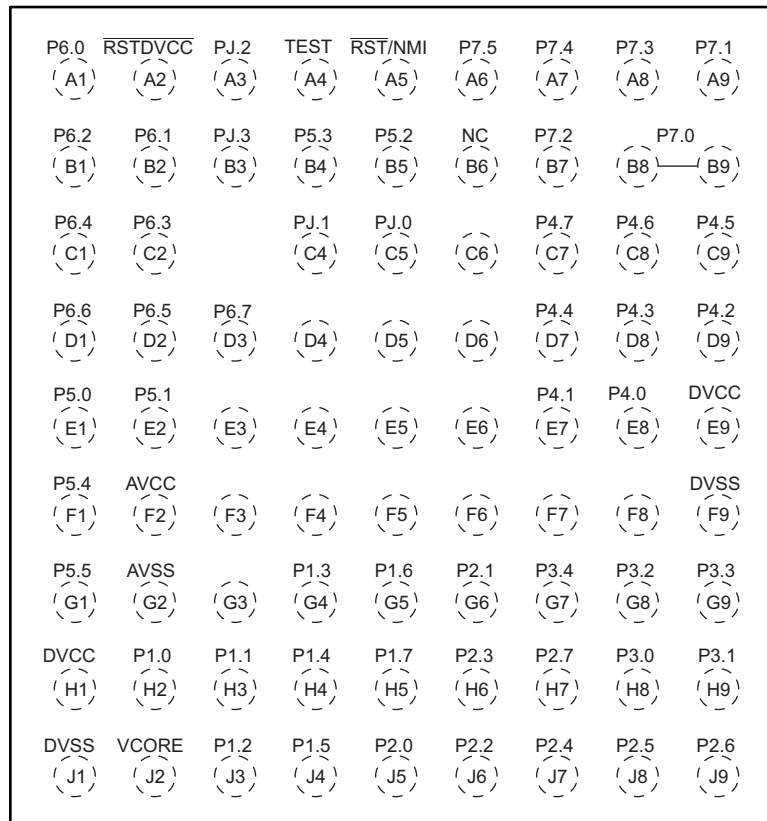


Figure 4-5. 80-Pin ZQE Package (Top View) – MSP430F5249, MSP430F5247, MSP430F5239, MSP430F5237

4.2 Signal Descriptions

Table 4-1 describes the signals for all device variants and package options.

Table 4-1. Signal Descriptions

TERMINAL				I/O ⁽¹⁾	DESCRIPTION
NAME	NO.				
	RGC	ZQE	RGZ		
P6.4/CB4/A4	5	C1	2	I/O	General-purpose digital I/O Comparator_B input CB4 Analog input A4 for the ADC (not available on all device types)
P6.5/CB5/A5	6	D2	3	I/O	General-purpose digital I/O Comparator_B input CB5 Analog input A5 for the ADC (not available on all device types)
P6.6/CB6/A6	7	D1	N/A	I/O	General-purpose digital I/O (not available on all device types) Comparator_B input CB6 (not available on all device types) Analog input A6 for the ADC (not available on all device types)
P6.7/CB7/A7	8	D3	N/A	I/O	General-purpose digital I/O (not available on all device types) Comparator_B input CB7 (not available on all device types) Analog input A7 for the ADC (not available on all device types)
P5.0/A8/VeREF+	9	E1	4	I/O	General-purpose digital I/O Analog input A8 for the ADC (not available on all device types) Input for an external reference voltage to the ADC (not available on all device types)
P5.1/A9/VeREF-	10	E2	5	I/O	General-purpose digital I/O Analog input A9 for the ADC (not available on all device types) Negative terminal for the ADC reference voltage for an external applied reference voltage (not available on all device types)
AVCC	11	F2	6		Analog power supply
P5.4/XIN	12	F1	7	I/O	General-purpose digital I/O Input terminal for crystal oscillator XT1
P5.5/XOUT	13	G1	8	I/O	General-purpose digital I/O Output terminal of crystal oscillator XT1
AVSS	14	G2	9		Analog ground supply
DVCC	15	H1	10		Digital power supply
DVSS	16	J1	11		Digital ground supply
VCORE ⁽²⁾	17	J2	12		Regulated core power supply output (internal use only, no external current loading)
P1.0/TA0CLK/ACLK	18	H2	13	I/O	General-purpose digital I/O with port interrupt TA0 clock signal TA0CLK input ACLK output (divided by 1, 2, 4, 8, 16, or 32)
P1.1/TA0.0	19	H3	14	I/O	General-purpose digital I/O with port interrupt TA0 CCR0 capture: CCI0A input, compare: Out0 output BSL transmit output
P1.2/TA0.1	20	J3	15	I/O	General-purpose digital I/O with port interrupt TA0 CCR1 capture: CCI1A input, compare: Out1 output BSL receive input
P1.3/TA0.2	21	G4	16	I/O	General-purpose digital I/O with port interrupt TA0 CCR2 capture: CCI2A input, compare: Out2 output

(1) I = input, O = output, N/A = not available

(2) VCore is for internal use only. No external current loading is possible. VCore should only be connected to the recommended capacitor value, C_{VCore}.

Table 4-1. Signal Descriptions (continued)

TERMINAL				I/O ⁽¹⁾	DESCRIPTION
NAME	NO.				
	RGC	ZQE	RGZ		
P1.4/TA0.3	22	H4	17	I/O	General-purpose digital I/O with port interrupt TA0 CCR3 capture: CCI3A input compare: Out3 output
P1.5/TA0.4	23	J4	18	I/O	General-purpose digital I/O with port interrupt TA0 CCR4 capture: CCI4A input, compare: Out4 output
P1.6/TA1CLK/CBOUT	24	G5	19	I/O	General-purpose digital I/O with port interrupt TA1 clock signal TA1CLK input Comparator_B output
P1.7/TA1.0	25	H5	20	I/O	General-purpose digital I/O with port interrupt TA1 CCR0 capture: CCI0A input, compare: Out0 output
P2.0/TA1.1	26	J5	N/A	I/O	General-purpose digital I/O with port interrupt (not available on all device types) TA1 CCR1 capture: CCI1A input, compare: Out1 output (not available on all device types)
P2.1/TA1.2	27	G6	N/A	I/O	General-purpose digital I/O with port interrupt (not available on all device types) TA1 CCR2 capture: CCI2A input, compare: Out2 output (not available on all device types)
P2.2/TA2CLK/SMCLK	28	J6	N/A	I/O	General-purpose digital I/O with port interrupt (not available on all device types) TA2 clock signal TA2CLK input SMCLK output (not available on all device types)
P2.3/TA2.0	29	H6	N/A	I/O	General-purpose digital I/O with port interrupt (not available on all device types) TA2 CCR0 capture: CCI0A input, compare: Out0 output (not available on all device types)
P2.4/TA2.1	30	J7	N/A	I/O	General-purpose digital I/O with port interrupt (not available on all device types) TA2 CCR1 capture: CCI1A input, compare: Out1 output (not available on all device types)
P2.5/TA2.2	31	J8	N/A	I/O	General-purpose digital I/O with port interrupt (not available on all device types) TA2 CCR2 capture: CCI2A input, compare: Out2 output (not available on all device types)
P2.6/RTCCLK/DMAE0	32	J9	N/A	I/O	General-purpose digital I/O with port interrupt (not available on all device types) RTC clock output for calibration (not available on all device types) DMA external trigger input (not available on all device types)
P2.7/UCB0STE/UCA0CLK	33	H7	21	I/O	General-purpose digital I/O Slave transmit enable for USCI_B0 SPI mode Clock signal input for USCI_A0 SPI slave mode Clock signal output for USCI_A0 SPI master mode
P3.0/UCB0SIMO/UCB0SDA	34	H8	22	I/O	General-purpose digital I/O Slave in, master out for USCI_B0 SPI mode I ² C data for USCI_B0 I ² C mode
P3.1/UCB0SOMI/UCB0SCL	35	H9	23	I/O	General-purpose digital I/O Slave out, master in for USCI_B0 SPI mode I ² C clock for USCI_B0 I ² C mode

Table 4-1. Signal Descriptions (continued)

TERMINAL				I/O ⁽¹⁾	DESCRIPTION
NAME	NO.				
	RGC	ZQE	RGZ		
P3.2/UCB0CLK/UCA0STE	36	G8	24	I/O	General-purpose digital I/O Clock signal input for USCI_B0 SPI slave mode Clock signal output for USCI_B0 SPI master mode Slave transmit enable for USCI_A0 SPI mode
P3.3/UCA0TXD/UCA0SIMO	37	G9	25	I/O	General-purpose digital I/O Transmit data for USCI_A0 UART mode Slave in, master out for USCI_A0 SPI mode
P3.4/UCA0RXD/UCA0SOMI	38	G7	26	I/O	General-purpose digital I/O Receive data for USCI_A0 UART mode Slave out, master in for USCI_A0 SPI mode
DVSS	39	F9	27		Digital ground supply
DVCC	40	E9	28		Digital power supply
P4.0/PM_UCB1STE/ PM_UCA1CLK	41	E8	29	I/O	General-purpose digital I/O with reconfigurable port mapping secondary function Default mapping: Slave transmit enable for USCI_B1 SPI mode Default mapping: Clock signal input for USCI_A1 SPI slave mode Default mapping: Clock signal output for USCI_A1 SPI master mode
P4.1/PM_UCB1SIMO/ PM_UCB1SDA	42	E7	30	I/O	General-purpose digital I/O with reconfigurable port mapping secondary function Default mapping: Slave in, master out for USCI_B1 SPI mode Default mapping: I ² C data for USCI_B1 I ² C mode
P4.2/PM_UCB1SOMI/ PM_UCB1SCL	43	D9	31	I/O	General-purpose digital I/O with reconfigurable port mapping secondary function Default mapping: Slave out, master in for USCI_B1 SPI mode Default mapping: I ² C clock for USCI_B1 I ² C mode
P4.3/PM_UCB1CLK/ PM_UCA1STE	44	D8	32	I/O	General-purpose digital I/O with reconfigurable port mapping secondary function Default mapping: Clock signal input for USCI_B1 SPI slave mode Default mapping: Clock signal output for USCI_B1 SPI master mode Default mapping: Slave transmit enable for USCI_A1 SPI mode
P4.4/PM_UCA1TXD/ PM_UCA1SIMO	45	D7	33	I/O	General-purpose digital I/O with reconfigurable port mapping secondary function Default mapping: Transmit data for USCI_A1 UART mode Default mapping: Slave in, master out for USCI_A1 SPI mode
P4.5/PM_UCA1RXD/ PM_UCA1SOMI	46	C9	34	I/O	General-purpose digital I/O with reconfigurable port mapping secondary function Default mapping: Receive data for USCI_A1 UART mode Default mapping: Slave out, master in for USCI_A1 SPI mode
P4.6/PM_NONE	47	C8	35	I/O	General-purpose digital I/O with reconfigurable port mapping secondary function Default mapping: no secondary function.
P4.7/PM_NONE	48	C7	N/A	I/O	General-purpose digital I/O with reconfigurable port mapping secondary function (not available on all device types) Default mapping: no secondary function. (not available on all device types)
P7.0/TB0.0	49	B8, B9	N/A	I/O	General-purpose digital I/O (not available on all device types) TB0 CCR0 capture: CCI0A input, compare: Out0 output (not available on all device types)

Table 4-1. Signal Descriptions (continued)

TERMINAL				I/O ⁽¹⁾	DESCRIPTION
NAME	NO.				
	RGC	ZQE	RGZ		
P7.1/TB0.1	50	A9	N/A	I/O	General-purpose digital I/O (not available on all device types) TB0 CCR1 capture: CCI1A input, compare: Out1 output (not available on all device types)
P7.2/TB0.2	51	B7	N/A	I/O	General-purpose digital I/O (not available on all device types) TB0 CCR2 capture: CCI2A input, compare: Out2 output (not available on all device types)
P7.3/TB0.3	52	A8	N/A	I/O	General-purpose digital I/O (not available on all device types) TB0 CCR3 capture: CCI3A input, compare: Out3 output (not available on all device types)
P7.4/TB0.4	53	A7	N/A	I/O	General-purpose digital I/O (not available on all device types) TB0 CCR4 capture: CCI4A input, compare: Out4 output (not available on all device types)
P7.5/TB0.5	54	A6	N/A	I/O	General-purpose digital I/O (not available on all device types) TB0 CCR5 capture: CCI5A input, compare: Out5 output (not available on all device types)
$\overline{\text{RST}}$ /NMI	56	A5	37	I	Reset input, active low (also see Section 4.2.1) ⁽³⁾ Nonmaskable interrupt input
P5.2/XT2IN	57	B5	38	I/O	General-purpose digital I/O Input terminal for crystal oscillator XT2
P5.3/XT2OUT	58	B4	39	I/O	General-purpose digital I/O \\\nOutput terminal of crystal oscillator XT2
TEST/SBWTCK ⁽⁴⁾	59	A4	40	I	Test mode pin – Selects four-wire JTAG operation Spy-Bi-Wire input clock when Spy-Bi-Wire operation activated
PJ.0/TDO ⁽⁵⁾	60	C5	41	I/O	General-purpose digital I/O JTAG test data output port
PJ.1/TDI/TCLK ⁽⁵⁾	61	C4	42	I/O	General-purpose digital I/O JTAG test data input or test clock input
PJ.2/TMS ⁽⁵⁾	62	A3	43	I/O	General-purpose digital I/O JTAG test mode select
PJ.3/TCK ⁽⁵⁾	63	B3	44	I/O	General-purpose digital I/O JTAG test clock
$\overline{\text{RSTDVCC}}$ /SBWTDIO ⁽⁵⁾	64	A2	45	I/O	Reset input active low (also see Section 4.2.1) ⁽⁶⁾ Spy-Bi-Wire data input/output when Spy-Bi-Wire operation activated
P6.0/CB0/A0	1	A1	46	I/O	General-purpose digital I/O Comparator_B input CB0 Analog input A0 for the ADC (not available on all device types)
P6.1/CB1/A1	2	B2	47	I/O	General-purpose digital I/O Comparator_B input CB1 Analog input A1 for the ADC (not available on all device types)
P6.2/CB2/A2	3	B1	48	I/O	General-purpose digital I/O Comparator_B input CB2 Analog input A2 for the ADC (not available on all device types)

(3) When this pin is configured as reset, the internal pullup resistor is enabled by default.

(4) See [§ 6.5](#) and [§ 6.6](#) for use with BSL and JTAG functions, respectively.

(5) See [§ 6.6](#) for use with JTAG function.

(6) This nonconfigurable reset has an internal pullup to DVCC.

Table 4-1. Signal Descriptions (continued)

TERMINAL				I/O ⁽¹⁾	DESCRIPTION
NAME	NO.				
	RGC	ZQE	RGZ		
P6.3/CB3/A3	4	C2	1	I/O	General-purpose digital I/O Comparator_B input CB3 Analog input A3 for the ADC (not available on all device types)
Reserved	55 ⁽⁷⁾	⁽⁸⁾	36 ⁽⁷⁾		Reserved
QFN Pad	Pad	N/A	Pad		QFN package pad. Connection to V _{SS} recommended.

(7) This pin is reserved and can be left unconnected or connected to ground.

(8) Pins C6, D4, D5, D6, E3, E4, E5, E6, F3, F4, F5, F6, F7, F8, G3 are reserved and should be connected to ground. Pin B6 is reserved and can be left unconnected or connected to ground.

4.2.1 $\overline{\text{RST}}$ /NMI and $\overline{\text{RSTDVCC}}$ /SBWTDIO Pins

The $\overline{\text{RST}}$ /NMI and $\overline{\text{RSTDVCC}}$ /SBWTDIO pins have overlapping function when configured as reset but they are differentiated as shown here:

- Both can be used for the reset function. When both are used as reset, they can be tied together.
- $\overline{\text{RST}}$ /NMI also includes the external NMI function and has a configurable pullup or pulldown when used as reset.
- $\overline{\text{RSTDVCC}}$ /SBWTDIO also includes the SBWTDIO function and has a nonconfigurable pullup when used as reset.

5 Specifications

All graphs in this section are for typical conditions, unless otherwise noted.

Typical (TYP) values are specified at $V_{CC} = 3.3\text{ V}$ and $T_A = 25^\circ\text{C}$, unless otherwise noted.

5.1 Absolute Maximum Ratings⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

	MIN	MAX	UNIT
Voltage applied at V_{CC} to V_{SS}	-0.3	4.1	V
Voltage applied to any pin (excluding V_{CORE}) ⁽²⁾	-0.3	$V_{CC} + 0.3$	V
Diode current at any device pin		±2	mA
Storage temperature, T_{stg} ⁽³⁾	-55	150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltages are referenced to V_{SS} . V_{CORE} is for internal device use only. No external DC loading or voltage should be applied.
- (3) Higher temperature may be applied during board soldering according to the current JEDEC J-STD-020 specification with peak reflow temperatures not higher than classified on the device label on the shipping boxes or reels.

5.2 ESD Ratings

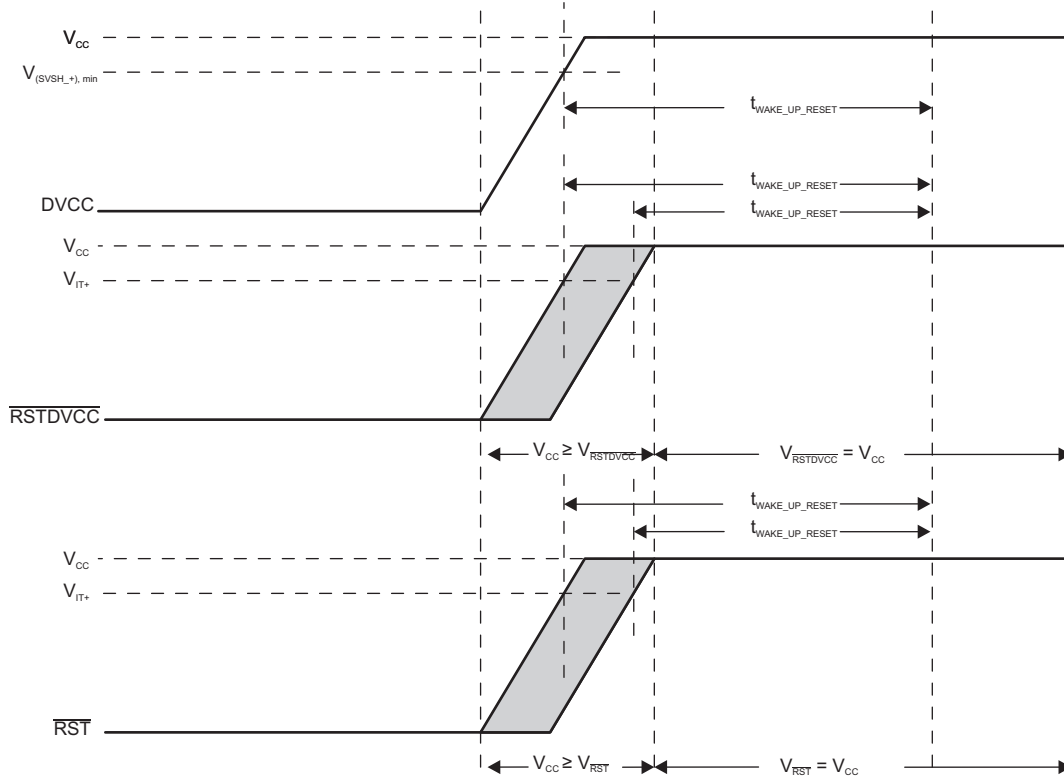
	VALUE	UNIT
$V_{(ESD)}$ Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±1000
	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±250

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process. Pins listed as ±1000 V may actually have higher performance.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process. Pins listed as ±250 V may actually have higher performance.

5.3 Recommended Operating Conditions

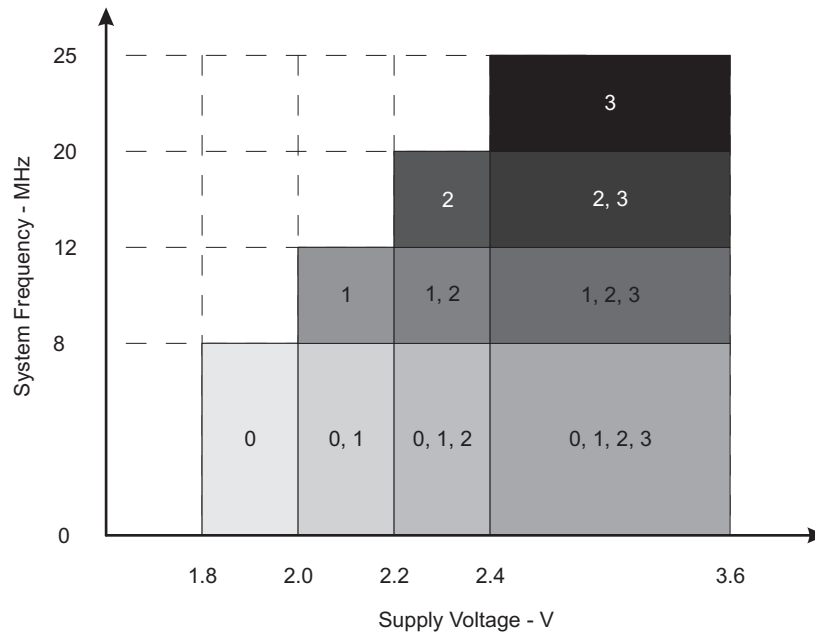
		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage during program execution and flash programming ($AV_{CC} = DV_{CC}$) ^{(1) (2)}	PMMCOREVx = 0	1.8	3.6	V
		PMMCOREVx = 0, 1	2.0	3.6	
		PMMCOREVx = 0, 1, 2	2.2	3.6	
		PMMCOREVx = 0, 1, 2, 3	2.4	3.6	
V_{SS}	Supply voltage ($AV_{SS} = DV_{SS}$)		0		V
T_A	Operating free-air temperature	-40		85	°C
T_J	Operating junction temperature	-40		85	°C
$C_{V_{CORE}}$	Recommended capacitor at V_{CORE} ⁽³⁾		470		nF
$C_{DV_{CC}}/C_{V_{CORE}}$	Capacitor ratio of DV_{CC} to V_{CORE}		10		
f_{SYSTEM}	Processor frequency (maximum MCLK frequency) ⁽⁴⁾ (see Figure 5-2)	PMMCOREVx = 0 (default condition), $1.8\text{ V} \leq V_{CC} \leq 3.6\text{ V}$	0	8.0	MHz
		PMMCOREVx = 1, $2.0\text{ V} \leq V_{CC} \leq 3.6\text{ V}$	0	12.0	
		PMMCOREVx = 2, $2.2\text{ V} \leq V_{CC} \leq 3.6\text{ V}$	0	20.0	
		PMMCOREVx = 3, $2.4\text{ V} \leq V_{CC} \leq 3.6\text{ V}$	0	25.0	

- (1) TI recommends powering AV_{CC} and DV_{CC} from the same source. A maximum difference of 0.3 V between AV_{CC} and DV_{CC} can be tolerated during power up and operation.
- (2) The minimum supply voltage is defined by the supervisor SVS levels when it is enabled. See the threshold parameters in [Section 5.22](#) for the exact values and further details.
- (3) A capacitor tolerance of ±20% or better is required.
- (4) Modules may have a different maximum input clock specification. See the specification of the respective module in this data sheet.



NOTE: The device remains in reset based on the conditions of the $\overline{RSTDVCC}/SBWTDIO$ and $\overline{RST}$ pins, along with the voltage present on $DVCC$ voltage supply. Holding $\overline{RSTDVCC}/SBWTDIO$ or $\overline{RST}$ at a logic low or holding $DVCC$ below the $SVSH_+$ minimum threshold causes the device to remain in its reset condition; that is, these conditions form a logical OR with respect to device reset.

Figure 5-1. Reset Timing



NOTE: The numbers within the fields denote the supported PMMCOREVx settings.

Figure 5-2. Maximum System Frequency

5.4 Active Mode Supply Current Into V_{CC} Excluding External Current

over recommended operating free-air temperature (unless otherwise noted)⁽¹⁾ ⁽²⁾ ⁽³⁾

PARAMETER	EXECUTION MEMORY	V _{CC}	PMMCOREVx	FREQUENCY (f _{DCO} = f _{MCLK} = f _{SMCLK})										UNIT
				1 MHz		8 MHz		12 MHz		20 MHz		25 MHz		
				TYP	MAX	TYP	MAX	TYP	MAX	TYP	MAX	TYP	MAX	
I _{AM, Flash}	Flash	3.0 V	0	0.36	0.47	2.32	2.60							mA
			1	0.40		2.65		4.0	4.4					
			2	0.44		2.90		4.3		7.1	7.7			
			3	0.46		3.10		4.6		7.6		10.1	11.0	
I _{AM, RAM}	RAM	3.0 V	0	0.20	0.29	1.20	1.30							mA
			1	0.22		1.35		2.0	2.2					
			2	0.24		1.50		2.2		3.7	4.2			
			3	0.26		1.60		2.4		3.9		5.3	6.2	

- (1) All inputs are tied to 0 V or to V_{CC} . Outputs do not source or sink any current.
- (2) The currents are characterized with a Micro Crystal MS1V-T1K crystal with a load capacitance of 12.5 pF. The internal and external load capacitance are chosen to closely match the required 12.5 pF.
- (3) Characterized with program executing typical data processing.
 $f_{ACLK} = 32786 \text{ Hz}$, $f_{DCO} = f_{MCLK} = f_{SMCLK}$ at specified frequency.
 $XTS = CPUOFF = SCG0 = SCG1 = OSCOFF = SMCLKOFF = 0$.

5.5 Low-Power Mode Supply Currents (Into V_{CC}) Excluding External Current

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)^{(1) (2)}

PARAMETER		V _{CC}	PMMCOREVx	TEMPERATURE (T _A)								UNIT	
				−40°C		25°C		60°C		85°C			
				TYP	MAX	TYP	MAX	TYP	MAX	TYP	MAX		
I _{LPM0,1MHz}	Low-power mode 0 ^{(3) (4)}	2.2 V	0	73		77	91	80		85	97	μA	
		3.0 V	3	79		83	99	88		95	107		
I _{LPM2}	Low-power mode 2 ^{(5) (4)}	2.2 V	0	6.5		6.5	12	10		11	17	μA	
		3.0 V	3	7.0		7.0	13	11		12	18		
I _{LPM3,XT1LF}	Low-power mode 3, crystal mode ^{(6) (4)}	2.2 V	0	1.60		1.90		2.8		6.0		μA	
			1	1.65		2.00		3.0		6.3			
			2	1.75		2.15		3.2		6.6			
		3.0 V	0	1.8		2.1	2.9	3.0		6.2	9.4		
			1	1.9		2.3		3.2		6.5			
			2	2.0		2.4		3.3		6.8			
			3	2.0		2.5	3.9	3.4		6.8	10.9		
I _{LPM3,VLO}	Low-power mode 3, VLO mode ^{(7) (4)}	3.0 V	0	1.1		1.4	2.7	2.0		6.1	9.7	μA	
			1	1.1		1.4		2.2		6.4			
			2	1.2		1.5		2.3		6.8			
			3	1.3		1.6	3.0	2.3		6.8	10.9		
I _{LPM4}	Low-power mode 4 ^{(8) (4)}	3.0 V	0	0.9		1.1	1.5	2.0		5.1	8.8	μA	
			1	1.1		1.2		2.1		5.3			
			2	1.2		1.2		2.2		5.5			
			3	1.3		1.3	1.6	2.2		5.5	9.8		
I _{LPM4.5}	Low-power mode 4.5 ⁽⁹⁾	3.0 V			0.15		0.18	0.35	0.26		0.5	1.0	μA

(1) All inputs are tied to 0 V or to V_{CC} . Outputs do not source or sink any current.

(2) The currents are characterized with a Micro Crystal MS1V-T1K crystal with a load capacitance of 12.5 pF. The internal and external load capacitance are chosen to closely match the required 12.5 pF.

(3) Current for watchdog timer clocked by SMCLK included. ACLK = low-frequency crystal operation (XTS = 0, XT1DRIVEx = 0).

CPUOFF = 1, SCG0 = 0, SCG1 = 0, OSCOFF = 0 (LPM0), f_{ACLK} = 32768 Hz, f_{MCLK} = 0 MHz, f_{SMCLK} = f_{DCO} = 1 MHz

(4) Current for brownout, high side supervisor (SVSH) normal mode included. Low-side supervisor (SVSL) and low-side monitor (SVM_L) disabled. High-side monitor (SVM_H) disabled. RAM retention enabled.

(5) Current for watchdog timer and RTC clocked by ACLK included. ACLK = low-frequency crystal operation (XTS = 0, XT1DRIVEx = 0).

CPUOFF = 1, SCG0 = 0, SCG1 = 1, OSCOFF = 0 (LPM2), f_{ACLK} = 32768 Hz, f_{MCLK} = 0 MHz, f_{SMCLK} = f_{DCO} = 0 MHz, DCO setting = 1 MHz operation, DCO bias generator enabled.)

(6) Current for watchdog timer and RTC clocked by ACLK included. ACLK = low-frequency crystal operation (XTS = 0, XT1DRIVEx = 0).

CPUOFF = 1, SCG0 = 1, SCG1 = 1, OSCOFF = 0 (LPM3), f_{ACLK} = 32768 Hz, f_{MCLK} = f_{SMCLK} = f_{DCO} = 0 MHz

(7) Current for watchdog timer and RTC clocked by ACLK included. ACLK = VLO.

CPUOFF = 1, SCG0 = 1, SCG1 = 1, OSCOFF = 0 (LPM3), f_{ACLK} = f_{VLO} , f_{MCLK} = f_{SMCLK} = f_{DCO} = 0 MHz

(8) CPUOFF = 1, SCG0 = 1, SCG1 = 1, OSCOFF = 1 (LPM4), f_{DCO} = f_{ACLK} = f_{MCLK} = f_{SMCLK} = 0 MHz

(9) Internal regulator disabled. No data retention.

CPUOFF = 1, SCG0 = 1, SCG1 = 1, OSCOFF = 1, PMMREGOFF = 1 (LPM4.5), f_{DCO} = f_{ACLK} = f_{MCLK} = f_{SMCLK} = 0 MHz

5.6 Thermal Resistance Characteristics

THERMAL METRIC ⁽¹⁾		VALUE	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance, still air	VQFN 48 (RGZ)	27.8
		VQFN 64 (RGC)	29.6
		BGA 80 (ZQE)	48.1
$R_{\theta JC(TOP)}$	Junction-to-case (top) thermal resistance	VQFN 48 (RGZ)	13.6
		VQFN 64 (RGC)	14.7
		BGA 80 (ZQE)	20.9
$R_{\theta JC(BOTTOM)}$	Junction-to-case (bottom) thermal resistance	VQFN 48 (RGZ)	0.9
		VQFN 64 (RGC)	1.4
		BGA 80 (ZQE)	N/A ⁽²⁾
$R_{\theta JB}$	Junction-to-board thermal resistance	VQFN 48 (RGZ)	4.7
		VQFN 64 (RGC)	8.5
		BGA 80 (ZQE)	25.7
Ψ_{JT}	Junction-to-package-top thermal characterization parameter	VQFN 48 (RGZ)	0.2
		VQFN 64 (RGC)	0.2
		BGA 80 (ZQE)	0.4
Ψ_{JB}	Junction-to-board thermal characterization parameter	VQFN 48 (RGZ)	4.6
		VQFN 64 (RGC)	8.4
		BGA 80 (ZQE)	25.7

(1) These values are based on a JEDEC-defined 2S2P system (with the exception of the Theta JC [$R_{\theta JC}$] value, which is based on a JEDEC-defined 1S0P system) and will change based on environment as well as application. For more information, see these EIA/JEDEC standards:

- JESD51-2, *Integrated Circuits Thermal Test Method Environmental Conditions - Natural Convection (Still Air)*
- JESD51-3, *Low Effective Thermal Conductivity Test Board for Leaded Surface Mount Packages*
- JESD51-7, *High Effective Thermal Conductivity Test Board for Leaded Surface Mount Packages*
- JESD51-9, *Test Boards for Area Array Surface Mount Package Thermal Measurements*

(2) N/A = not applicable

5.7 Schmitt-Trigger Inputs – General-Purpose I/O⁽¹⁾

(P1.0 to P1.7, P2.0 to P2.7, P3.0 to P3.4, P4.0 to P4.7, P5.0 to P5.5, P6.0 to P6.7, P7.0 to P7.5, PJ.0 to PJ.3, RSTDVCC/SBWTIO, RST/NMI)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
V _{IT+} Positive-going input threshold voltage		1.8 V	0.80		1.40	V
		3 V	1.50		2.10	
V _{IT-} Negative-going input threshold voltage		1.8 V	0.45		1.00	V
		3 V	0.75		1.65	
V _{hys} Input voltage hysteresis (V _{IT+} – V _{IT-})		1.8 V	0.3		0.8	V
		3 V	0.4		1.0	
R _{Pull} Pullup or pulldown resistor ⁽²⁾	For pullup: V _{IN} = V _{SS} For pulldown: V _{IN} = V _{CC}		20	35	50	kΩ
C _I Input capacitance	V _{IN} = V _{SS} or V _{CC}			5		pF

(1) Same parametrics apply to clock input pin when crystal bypass mode is used on XT1 (XIN) or XT2 (XT2IN).

(2) Also applies to RST pin when pullup or pulldown resistor is enabled.

5.8 Inputs – Interrupts

(P1.0 to P1.7, P2.0 to P2.7)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	MAX	UNIT
t _(int) External interrupt timing ⁽¹⁾	External trigger pulse duration to set interrupt flag	1.8 V, 3 V	20		ns

(1) An external signal sets the interrupt flag every time the minimum interrupt pulse width t_(int) is met. It may be set by trigger signals shorter than t_(int).

5.9 Leakage Current – General-Purpose I/O

(P1.0 to P1.7, P2.0 to P2.7, P3.0 to P3.4, P4.0 to P4.7, P5.0 to P5.5, P6.0 to P6.7, P7.0 to P7.5, PJ.0 to PJ.3)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	MAX	UNIT
I _{lkg} (P _{x.y}) High-impedance leakage current	(1) (2)	1.8 V, 3 V	–50	50	nA

(1) The leakage current is measured with V_{SS} or V_{CC} applied to the corresponding pins, unless otherwise noted.

(2) The leakage of the digital port pins is measured individually. The port pin is selected for input and the pullup or pulldown resistor is disabled.

5.10 Outputs – General-Purpose I/O (Full Drive Strength)

(P1.0 to P1.7, P2.0 to P2.7, P3.0 to P3.4, P4.0 to P4.7, P5.0 to P5.5, P6.0 to P6.7, P7.0 to P7.5, PJ.0 to PJ.3)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	MAX	UNIT
V _{OH} High-level output voltage	I _(OHmax) = –3 mA ⁽¹⁾	1.8 V	V _{CC} – 0.25	V _{CC}	V
	I _(OHmax) = –10 mA ⁽²⁾		V _{CC} – 0.60	V _{CC}	
	I _(OHmax) = –5 mA ⁽¹⁾	3 V	V _{CC} – 0.25	V _{CC}	
	I _(OHmax) = –15 mA ⁽²⁾		V _{CC} – 0.60	V _{CC}	
V _{OL} Low-level output voltage	I _(OLmax) = 3 mA ⁽¹⁾	1.8 V	V _{SS}	V _{SS} + 0.25	V
	I _(OLmax) = 10 mA ⁽²⁾		V _{SS}	V _{SS} + 0.60	
	I _(OLmax) = 5 mA ⁽¹⁾	3 V	V _{SS}	V _{SS} + 0.25	
	I _(OLmax) = 15 mA ⁽²⁾		V _{SS}	V _{SS} + 0.60	

(1) The maximum total current, I_(OHmax) and I_(OLmax), for all outputs combined should not exceed ±48 mA to hold the maximum voltage drop specified.

(2) The maximum total current, I_(OHmax) and I_(OLmax), for all outputs combined should not exceed ±100 mA to hold the maximum voltage drop specified.

5.11 Outputs – General-Purpose I/O (Reduced Drive Strength) (P1.0 to P1.7, P2.0 to P2.7, P3.0 to P3.4, P4.0 to P4.7, P5.0 to P5.5, P6.0 to P6.7, P7.0 to P7.5, PJ.0 to PJ.3)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)⁽¹⁾

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	MAX	UNIT
V _{OH} High-level output voltage	I _(OHmax) = –1 mA ⁽²⁾	1.8 V	V _{CC} – 0.25	V _{CC}	V
	I _(OHmax) = –3 mA ⁽³⁾		V _{CC} – 0.60	V _{CC}	
	I _(OHmax) = –2 mA ⁽²⁾	3.0 V	V _{CC} – 0.25	V _{CC}	
	I _(OHmax) = –6 mA ⁽³⁾		V _{CC} – 0.60	V _{CC}	
V _{OL} Low-level output voltage	I _(OLmax) = 1 mA ⁽²⁾	1.8 V	V _{SS}	V _{SS} + 0.25	V
	I _(OLmax) = 3 mA ⁽³⁾		V _{SS}	V _{SS} + 0.60	
	I _(OLmax) = 2 mA ⁽²⁾	3.0 V	V _{SS}	V _{SS} + 0.25	
	I _(OLmax) = 6 mA ⁽³⁾		V _{SS}	V _{SS} + 0.60	

- (1) Selecting reduced drive strength may reduce EMI.
- (2) The maximum total current, I_(OHmax) and I_(OLmax), for all outputs combined, should not exceed ±48 mA to hold the maximum voltage drop specified.
- (3) The maximum total current, I_(OHmax) and I_(OLmax), for all outputs combined, should not exceed ±100 mA to hold the maximum voltage drop specified.

5.12 Output Frequency – General-Purpose I/O (P1.0 to P1.7, P2.0 to P2.7, P3.0 to P3.4, P4.0 to P4.7, P5.0 to P5.5, P6.0 to P6.7, P7.0 to P7.5, PJ.0 to PJ.3)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
f _{Px,y} Port output frequency (with load)	See ⁽¹⁾⁽²⁾	V _{CC} = 1.8 V, PMMCOREVx = 0	16	MHz
		V _{CC} = 3 V, PMMCOREVx = 3	25	
f _{Port_CLK} Clock output frequency	ACLK, SMCLK, or MCLK, C _L = 20 pF ⁽²⁾	V _{CC} = 1.8 V, PMMCOREVx = 0	16	MHz
		V _{CC} = 3 V, PMMCOREVx = 3	25	

- (1) A resistive divider with 2 × R₁ between V_{CC} and V_{SS} is used as load. The output is connected to the center tap of the divider. For full drive strength, R₁ = 550 Ω. For reduced drive strength, R₁ = 1.6 kΩ. C_L = 20 pF is connected to the output to V_{SS}.
- (2) The output voltage reaches at least 10% and 90% V_{CC} at the specified toggle frequency.

5.13 Typical Characteristics – Outputs, Reduced Drive Strength (PxDS.y = 0)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

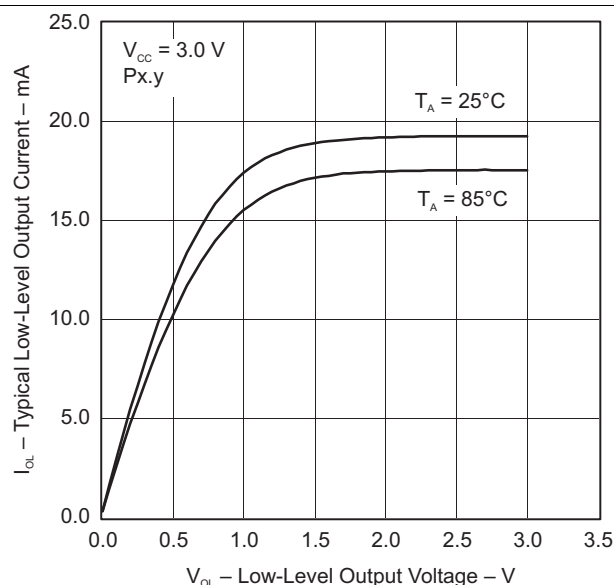


图 5-3. Typical Low-Level Output Current vs Low-Level Output Voltage

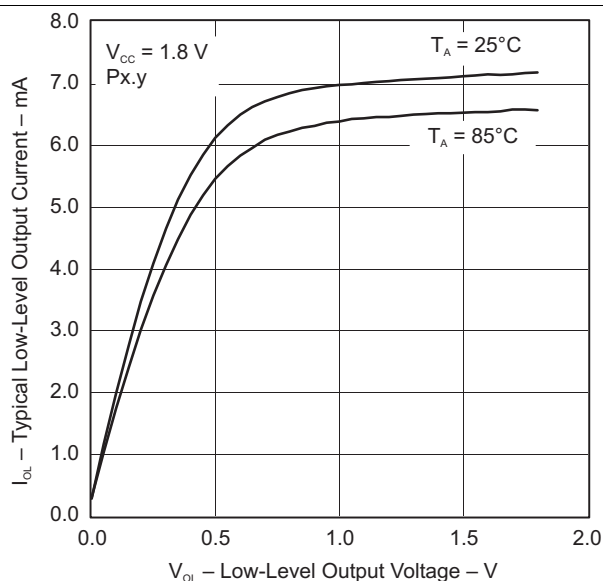


图 5-4. Typical Low-Level Output Current vs Low-Level Output Voltage

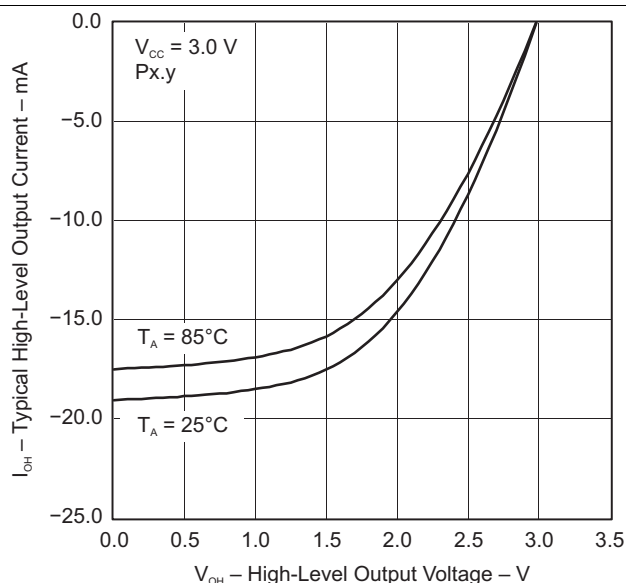


图 5-5. Typical High-Level Output Current vs High-Level Output Voltage

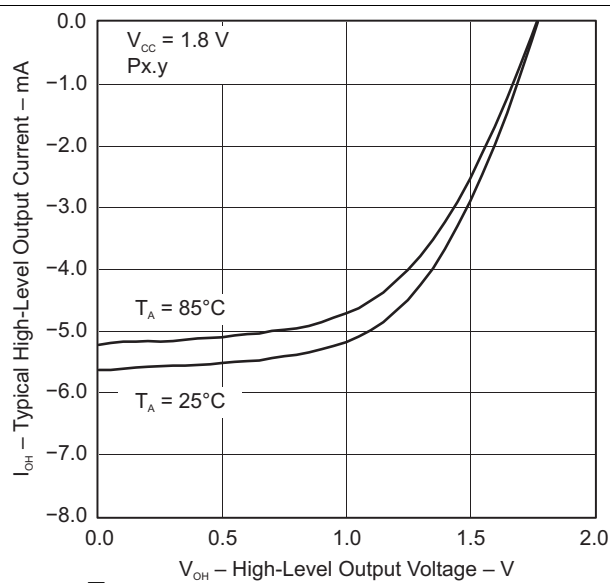


图 5-6. Typical High-Level Output Current vs High-Level Output Voltage

5.14 Typical Characteristics – Outputs, Full Drive Strength (PxDS.y = 1)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

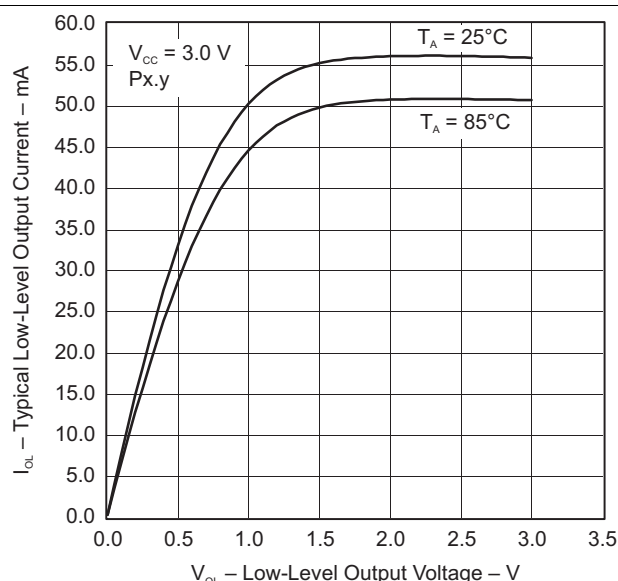


图 5-7. Typical Low-Level Output Current vs Low-Level Output Voltage

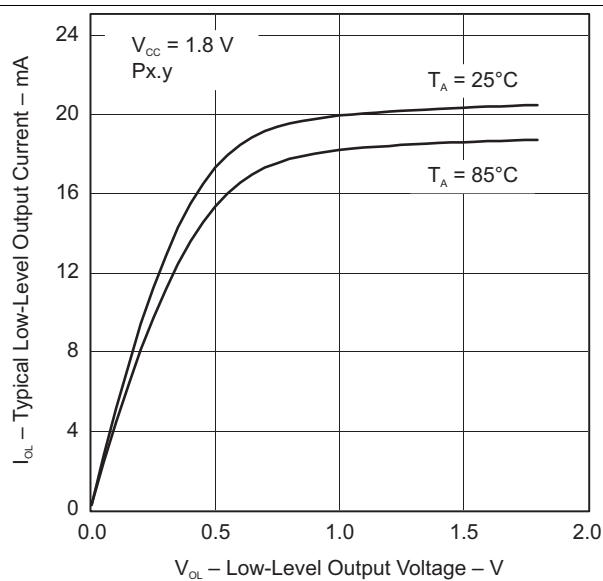


图 5-8. Typical Low-Level Output Current vs Low-Level Output Voltage

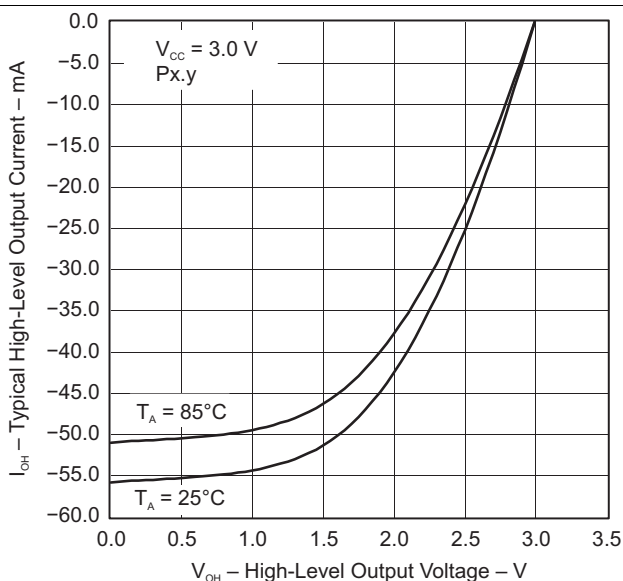


图 5-9. Typical High-Level Output Current vs High-Level Output Voltage

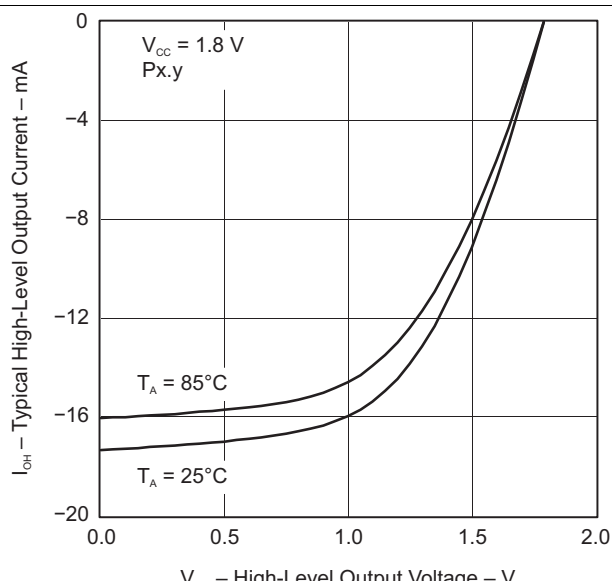


图 5-10. Typical High-Level Output Current vs High-Level Output Voltage

5.15 Crystal Oscillator, XT1, Low-Frequency Mode⁽¹⁾

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
ΔI _{DVCC,LF}	Differential XT1 oscillator crystal current consumption from lowest drive setting, LF mode	f _{OSC} = 32768 Hz, XTS = 0, XT1BYPASS = 0, XT1DRIVE _x = 1, T _A = 25°C	3.0 V	0.075		μA	
		f _{OSC} = 32768 Hz, XTS = 0, XT1BYPASS = 0, XT1DRIVE _x = 2, T _A = 25°C		0.170			
		f _{OSC} = 32768 Hz, XTS = 0, XT1BYPASS = 0, XT1DRIVE _x = 3, T _A = 25°C		0.290			
f _{XT1,LF0}	XT1 oscillator crystal frequency, LF mode	XTS = 0, XT1BYPASS = 0		32768		Hz	
f _{XT1,LF,SW}	XT1 oscillator logic-level square-wave input frequency, LF mode	XTS = 0, XT1BYPASS = 1 ⁽²⁾ ⁽³⁾		10	32.768	50	kHz
OA _{LF}	Oscillation allowance for LF crystals ⁽⁴⁾	XTS = 0, XT1BYPASS = 0, XT1DRIVE _x = 0, f _{XT1,LF} = 32768 Hz, C _{L,eff} = 6 pF		210		kΩ	
		XTS = 0, XT1BYPASS = 0, XT1DRIVE _x = 1, f _{XT1,LF} = 32768 Hz, C _{L,eff} = 12 pF	300				
C _{L,eff}	Integrated effective load capacitance, LF mode ⁽⁵⁾	XTS = 0, XCAP _x = 0 ⁽⁶⁾		1		pF	
		XTS = 0, XCAP _x = 1	5.5				
		XTS = 0, XCAP _x = 2	8.5				
		XTS = 0, XCAP _x = 3	12.0				
Duty cycle, LF mode		XTS = 0, Measured at ACLK, f _{XT1,LF} = 32768 Hz		30%	70%		
f _{Fault,LF}	Oscillator fault frequency, LF mode ⁽⁷⁾	XTS = 0 XT1BYPASS = 1 ⁽⁸⁾		10	10000		Hz
t _{START,LF}	Start-up time, LF mode	f _{OSC} = 32768 Hz, XTS = 0, XT1BYPASS = 0, XT1DRIVE _x = 0, T _A = 25°C, C _{L,eff} = 6 pF	3.0 V	1000		ms	
		f _{OSC} = 32768 Hz, XTS = 0, XT1BYPASS = 0, XT1DRIVE _x = 3, T _A = 25°C, C _{L,eff} = 12 pF		500			

- (1) To improve EMI on the XT1 oscillator, the following guidelines should be observed.
 - Keep the trace between the device and the crystal as short as possible.
 - Design a good ground plane around the oscillator pins.
 - Prevent crosstalk from other clock or data lines into oscillator pins XIN and XOUT.
 - Avoid running PCB traces underneath or adjacent to the XIN and XOUT pins.
 - Use assembly materials and processes that avoid any parasitic load on the oscillator XIN and XOUT pins.
 - If conformal coating is used, make sure that it does not induce capacitive or resistive leakage between the oscillator pins.
- (2) When XT1BYPASS is set, XT1 circuits are automatically powered down. Input signal is a digital square wave with parametrics defined in the Schmitt-trigger Inputs section of this datasheet. When in crystal bypass mode, XIN can be configured so that it can support an input digital waveform with swing levels from DVSS to DVCC.
- (3) Maximum frequency of operation of the entire device cannot be exceeded.
- (4) Oscillation allowance is based on a safety factor of 5 for recommended crystals. The oscillation allowance is a function of the XT1DRIVE_x settings and the effective load. In general, comparable oscillator allowance can be achieved based on the following guidelines, but should be evaluated based on the actual crystal selected for the application:
 - For XT1DRIVE_x = 0, C_{L,eff} ≤ 6 pF.
 - For XT1DRIVE_x = 1, 6 pF ≤ C_{L,eff} ≤ 9 pF.
 - For XT1DRIVE_x = 2, 6 pF ≤ C_{L,eff} ≤ 10 pF.
 - For XT1DRIVE_x = 3, C_{L,eff} ≥ 6 pF.
- (5) Includes parasitic bond and package capacitance (approximately 2 pF per pin). Because the PCB adds additional capacitance, verify the correct load by measuring the ACLK frequency. For a correct setup, the effective load capacitance should always match the specification of the used crystal.
- (6) Requires external capacitors at both terminals. Values are specified by crystal manufacturers.
- (7) Frequencies below the MIN specification set the fault flag. Frequencies above the MAX specification do not set the fault flag. Frequencies between the MIN and MAX specifications might set the flag.
- (8) Measured with logic-level input frequency but also applies to operation with crystals.

5.16 Crystal Oscillator, XT2

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)^{(1) (2)}

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
I _{DVCC,XT2} XT2 oscillator crystal current consumption	f _{OSC} = 4 MHz, XT2OFF = 0, T _A = 25°C, XT2BYPASS = 0, XT2DRIVE _x = 0	3.0 V		200		μA
	f _{OSC} = 12 MHz, XT2OFF = 0, T _A = 25°C, XT2BYPASS = 0, XT2DRIVE _x = 1			260		
	f _{OSC} = 20 MHz, XT2OFF = 0, T _A = 25°C, XT2BYPASS = 0, XT2DRIVE _x = 2			325		
	f _{OSC} = 32 MHz, XT2OFF = 0, T _A = 25°C, XT2BYPASS = 0, XT2DRIVE _x = 3			450		
f _{XT2,HF0} XT2 oscillator crystal frequency, mode 0	XT2DRIVE _x = 0, XT2BYPASS = 0 ⁽³⁾		4		8	MHz
f _{XT2,HF1} XT2 oscillator crystal frequency, mode 1	XT2DRIVE _x = 1, XT2BYPASS = 0 ⁽³⁾		8		16	MHz
f _{XT2,HF2} XT2 oscillator crystal frequency, mode 2	XT2DRIVE _x = 2, XT2BYPASS = 0 ⁽³⁾		16		24	MHz
f _{XT2,HF3} XT2 oscillator crystal frequency, mode 3	XT2DRIVE _x = 3, XT2BYPASS = 0 ⁽³⁾		24		32	MHz
f _{XT2,HF,SW} XT2 oscillator logic-level square-wave input frequency, bypass mode	XT2BYPASS = 1 ⁽³⁾⁽⁴⁾		0.7		32	MHz
O _{AHF} Oscillation allowance for HF crystals ⁽⁵⁾	XT2DRIVE _x = 0, XT2BYPASS = 0, f _{XT2,HF0} = 6 MHz, C _{L,eff} = 15 pF			450		Ω
	XT2DRIVE _x = 1, XT2BYPASS = 0, f _{XT2,HF1} = 12 MHz, C _{L,eff} = 15 pF			320		
	XT2DRIVE _x = 2, XT2BYPASS = 0, f _{XT2,HF2} = 20 MHz, C _{L,eff} = 15 pF			200		
	XT2DRIVE _x = 3, XT2BYPASS = 0, f _{XT2,HF3} = 32 MHz, C _{L,eff} = 15 pF			200		
t _{START,HF} Start-up time	f _{OSC} = 6 MHz, XT2BYPASS = 0, XT2DRIVE _x = 0, T _A = 25°C, C _{L,eff} = 15 pF	3.0 V		0.5		ms
	f _{OSC} = 20 MHz, XT2BYPASS = 0, XT2DRIVE _x = 2, T _A = 25°C, C _{L,eff} = 15 pF			0.3		
C _{L,eff} Integrated effective load capacitance, HF mode ⁽¹⁾⁽⁶⁾				1		pF
Duty cycle	Measured at ACLK, f _{XT2,HF2} = 20 MHz		40%	50%	60%	
f _{Fault,HF} Oscillator fault frequency ⁽⁷⁾	XT2BYPASS = 1 ⁽⁸⁾		30		300	kHz

(1) Requires external capacitors at both terminals. Values are specified by crystal manufacturers.

(2) To improve EMI on the XT2 oscillator the following guidelines should be observed.

- Keep the traces between the device and the crystal as short as possible.
- Design a good ground plane around the oscillator pins.
- Prevent crosstalk from other clock or data lines into oscillator pins XT2IN and XT2OUT.
- Avoid running PCB traces underneath or adjacent to the XT2IN and XT2OUT pins.
- Use assembly materials and processes that avoid any parasitic load on the oscillator XT2IN and XT2OUT pins.
- If conformal coating is used, make sure that it does not induce capacitive or resistive leakage between the oscillator pins.

(3) This represents the maximum frequency that can be input to the device externally. Maximum frequency achievable on the device operation is based on the frequencies present on ACLK, MCLK, and SMCLK cannot be exceed for a given range of operation.

(4) When XT2BYPASS is set, the XT2 circuit is automatically powered down. Input signal is a digital square wave with parametrics defined in the Schmitt-trigger Inputs section of this datasheet. When in crystal bypass mode, XT2IN can be configured so that it can support an input digital waveform with swing levels from DVSS to DVCC.

(5) Oscillation allowance is based on a safety factor of 5 for recommended crystals.

(6) Includes parasitic bond and package capacitance (approximately 2 pF per pin). Because the PCB adds additional capacitance, verify the correct load by measuring the ACLK frequency. For a correct setup, the effective load capacitance should always match the specification of the used crystal.

(7) Frequencies below the MIN specification set the fault flag. Frequencies above the MAX specification do not set the fault flag. Frequencies between the MIN and MAX specifications might set the flag.

(8) Measured with logic-level input frequency but also applies to operation with crystals. In general, an effective load capacitance of up to 18 pF can be supported.

5.17 Internal Very-Low-Power Low-Frequency Oscillator (VLO)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
f _{VLO} VLO frequency	Measured at ACLK	1.8 V to 3.6 V	6	9.4	14	kHz
df _{VLO} /dT VLO frequency temperature drift	Measured at ACLK ⁽¹⁾	1.8 V to 3.6 V		0.5		%/°C
df _{VLO} /dV _{CC} VLO frequency supply voltage drift	Measured at ACLK ⁽²⁾	1.8 V to 3.6 V		4		%/V
Duty cycle	Measured at ACLK	1.8 V to 3.6 V	40%	50%	60%	

(1) Calculated using the box method: (MAX(–40°C to 85°C) – MIN(–40°C to 85°C)) / MIN(–40°C to 85°C) / (85°C – (–40°C))

(2) Calculated using the box method: (MAX(1.8 V to 3.6 V) – MIN(1.8 V to 3.6 V)) / MIN(1.8 V to 3.6 V) / (3.6 V – 1.8 V)

5.18 Internal Reference, Low-Frequency Oscillator (REFO)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
I _{REFO} REFO oscillator current consumption	T _A = 25°C	1.8 V to 3.6 V		3		μA
f _{REFO}	REFO frequency calibrated	1.8 V to 3.6 V		32768		Hz
	REFO absolute tolerance calibrated	Full temperature range	1.8 V to 3.6 V	–3.5%	3.5%	
		T _A = 25°C	3 V	–1.5%	1.5%	
df _{REFO} /dT REFO frequency temperature drift	Measured at ACLK ⁽¹⁾	1.8 V to 3.6 V		0.01		%/°C
df _{REFO} /dV _{CC} REFO frequency supply voltage drift	Measured at ACLK ⁽²⁾	1.8 V to 3.6 V		1.0		%/V
Duty cycle	Measured at ACLK	1.8 V to 3.6 V	40%	50%	60%	
t _{START} REFO start-up time	40%/60% duty cycle	1.8 V to 3.6 V		25		μs

(1) Calculated using the box method: (MAX(–40°C to 85°C) – MIN(–40°C to 85°C)) / MIN(–40°C to 85°C) / (85°C – (–40°C))

(2) Calculated using the box method: (MAX(1.8 V to 3.6 V) – MIN(1.8 V to 3.6 V)) / MIN(1.8 V to 3.6 V) / (3.6 V – 1.8 V)

5.19 DCO Frequency

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{DCO}(0,0)}$ DCO frequency (0, 0) ⁽¹⁾	DCORSELx = 0, DCOx = 0, MODx = 0	0.07		0.20	MHz
$f_{\text{DCO}(0,31)}$ DCO frequency (0, 31) ⁽¹⁾	DCORSELx = 0, DCOx = 31, MODx = 0	0.70		1.70	MHz
$f_{\text{DCO}(1,0)}$ DCO frequency (1, 0) ⁽¹⁾	DCORSELx = 1, DCOx = 0, MODx = 0	0.15		0.36	MHz
$f_{\text{DCO}(1,31)}$ DCO frequency (1, 31) ⁽¹⁾	DCORSELx = 1, DCOx = 31, MODx = 0	1.47		3.45	MHz
$f_{\text{DCO}(2,0)}$ DCO frequency (2, 0) ⁽¹⁾	DCORSELx = 2, DCOx = 0, MODx = 0	0.32		0.75	MHz
$f_{\text{DCO}(2,31)}$ DCO frequency (2, 31) ⁽¹⁾	DCORSELx = 2, DCOx = 31, MODx = 0	3.17		7.38	MHz
$f_{\text{DCO}(3,0)}$ DCO frequency (3, 0) ⁽¹⁾	DCORSELx = 3, DCOx = 0, MODx = 0	0.64		1.51	MHz
$f_{\text{DCO}(3,31)}$ DCO frequency (3, 31) ⁽¹⁾	DCORSELx = 3, DCOx = 31, MODx = 0	6.07		14.0	MHz
$f_{\text{DCO}(4,0)}$ DCO frequency (4, 0) ⁽¹⁾	DCORSELx = 4, DCOx = 0, MODx = 0	1.3		3.2	MHz
$f_{\text{DCO}(4,31)}$ DCO frequency (4, 31) ⁽¹⁾	DCORSELx = 4, DCOx = 31, MODx = 0	12.3		28.2	MHz
$f_{\text{DCO}(5,0)}$ DCO frequency (5, 0) ⁽¹⁾	DCORSELx = 5, DCOx = 0, MODx = 0	2.5		6.0	MHz
$f_{\text{DCO}(5,31)}$ DCO frequency (5, 31) ⁽¹⁾	DCORSELx = 5, DCOx = 31, MODx = 0	23.7		54.1	MHz
$f_{\text{DCO}(6,0)}$ DCO frequency (6, 0) ⁽¹⁾	DCORSELx = 6, DCOx = 0, MODx = 0	4.6		10.7	MHz
$f_{\text{DCO}(6,31)}$ DCO frequency (6, 31) ⁽¹⁾	DCORSELx = 6, DCOx = 31, MODx = 0	39.0		88.0	MHz
$f_{\text{DCO}(7,0)}$ DCO frequency (7, 0) ⁽¹⁾	DCORSELx = 7, DCOx = 0, MODx = 0	8.5		19.6	MHz
$f_{\text{DCO}(7,31)}$ DCO frequency (7, 31) ⁽¹⁾	DCORSELx = 7, DCOx = 31, MODx = 0	60		135	MHz
S_{DCORSEL} Frequency step between range DCORSEL and DCORSEL + 1	$S_{\text{RSEL}} = f_{\text{DCO}(\text{DCORSEL}+1, \text{DCO})} / f_{\text{DCO}(\text{DCORSEL}, \text{DCO})}$	1.2		2.3	ratio
S_{DCO} Frequency step between tap DCO and DCO + 1	$S_{\text{DCO}} = f_{\text{DCO}(\text{DCORSEL}, \text{DCO}+1)} / f_{\text{DCO}(\text{DCORSEL}, \text{DCO})}$	1.02		1.12	ratio
Duty cycle	Measured at SMCLK	40%	50%	60%	
df_{DCO}/dT DCO frequency temperature drift ⁽²⁾	$f_{\text{DCO}} = 1 \text{ MHz}$		0.1		%/°C
$df_{\text{DCO}}/dV_{\text{CC}}$ DCO frequency voltage drift ⁽³⁾	$f_{\text{DCO}} = 1 \text{ MHz}$		1.9		%/V

- (1) When selecting the proper DCO frequency range (DCORSELx), the target DCO frequency, f_{DCO} , should be set to reside within the range of $f_{\text{DCO}(n, 0), \text{MAX}} \leq f_{\text{DCO}} \leq f_{\text{DCO}(n, 31), \text{MIN}}$, where $f_{\text{DCO}(n, 0), \text{MAX}}$ represents the maximum frequency specified for the DCO frequency, range n, tap 0 (DCOx = 0) and $f_{\text{DCO}(n, 31), \text{MIN}}$ represents the minimum frequency specified for the DCO frequency, range n, tap 31 (DCOx = 31). This ensures that the target DCO frequency resides within the range selected. It should also be noted that if the actual f_{DCO} frequency for the selected range causes the FLL or the application to select tap 0 or 31, the DCO fault flag is set to report that the selected range is at its minimum or maximum tap setting.
- (2) Calculated using the box method: $(\text{MAX}(-40^\circ\text{C to } 85^\circ\text{C}) - \text{MIN}(-40^\circ\text{C to } 85^\circ\text{C})) / \text{MIN}(-40^\circ\text{C to } 85^\circ\text{C}) / (85^\circ\text{C} - (-40^\circ\text{C}))$
- (3) Calculated using the box method: $(\text{MAX}(1.8 \text{ V to } 3.6 \text{ V}) - \text{MIN}(1.8 \text{ V to } 3.6 \text{ V})) / \text{MIN}(1.8 \text{ V to } 3.6 \text{ V}) / (3.6 \text{ V} - 1.8 \text{ V})$

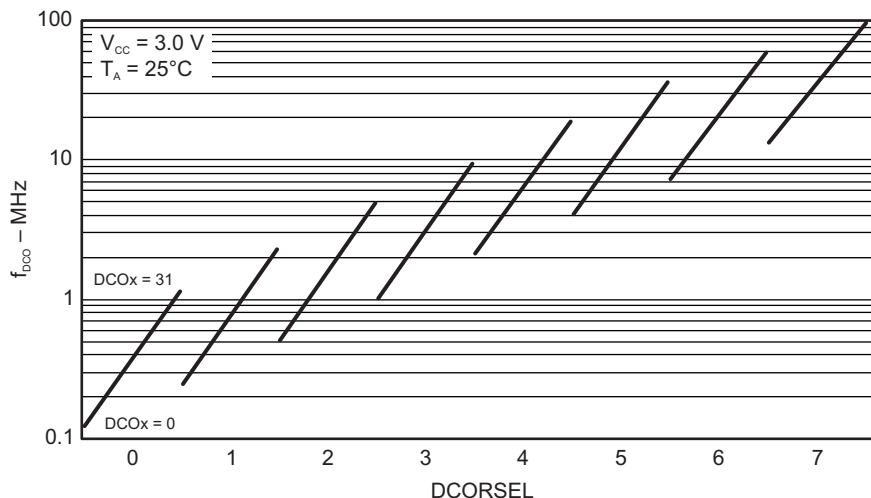


Figure 5-11. Typical DCO Frequency

5.20 PMM, Brownout Reset (BOR)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{(DVCC_BOR_IT-)}$	BOR _H on voltage, DV _{CC} falling level	$ dDV_{CC}/dt < 3 \text{ V/s}$			1.45	V
$V_{(DVCC_BOR_IT+)}$	BOR _H off voltage, DV _{CC} rising level	$ dDV_{CC}/dt < 3 \text{ V/s}$	0.80	1.30	1.50	V
$V_{(DVCC_BOR_hys)}$	BOR _H hysteresis		50		250	mV
t_{RESET}	Pulse duration required at RST/NMI pin to accept a reset		2			μs

5.21 PMM, Core Voltage

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{\text{CORE3(AM)}}$	Core voltage, active mode, PMMCOREV = 3	$2.4 \text{ V} \leq DV_{CC} \leq 3.6 \text{ V}$		1.90		V
$V_{\text{CORE2(AM)}}$	Core voltage, active mode, PMMCOREV = 2	$2.2 \text{ V} \leq DV_{CC} \leq 3.6 \text{ V}$		1.80		V
$V_{\text{CORE1(AM)}}$	Core voltage, active mode, PMMCOREV = 1	$2.0 \text{ V} \leq DV_{CC} \leq 3.6 \text{ V}$		1.60		V
$V_{\text{CORE0(AM)}}$	Core voltage, active mode, PMMCOREV = 0	$1.8 \text{ V} \leq DV_{CC} \leq 3.6 \text{ V}$		1.40		V
$V_{\text{CORE3(LPM)}}$	Core voltage, low-current mode, PMMCOREV = 3	$2.4 \text{ V} \leq DV_{CC} \leq 3.6 \text{ V}$		1.94		V
$V_{\text{CORE2(LPM)}}$	Core voltage, low-current mode, PMMCOREV = 2	$2.2 \text{ V} \leq DV_{CC} \leq 3.6 \text{ V}$		1.84		V
$V_{\text{CORE1(LPM)}}$	Core voltage, low-current mode, PMMCOREV = 1	$2.0 \text{ V} \leq DV_{CC} \leq 3.6 \text{ V}$		1.64		V
$V_{\text{CORE0(LPM)}}$	Core voltage, low-current mode, PMMCOREV = 0	$1.8 \text{ V} \leq DV_{CC} \leq 3.6 \text{ V}$		1.44		V

5.22 PMM, SVS High Side

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$I_{(SVSH)}$ SVS current consumption	SVSHE = 0, DV _{CC} = 3.6 V		0		nA
	SVSHE = 1, DV _{CC} = 3.6 V, SVSHFP = 0		200		
	SVSHE = 1, DV _{CC} = 3.6 V, SVSHFP = 1		1.5		μA
$V_{(SVSH_IT-)}$ SVS _H on voltage level ⁽¹⁾	SVSHE = 1, SVSHRVL = 0	1.57	1.68	1.78	V
	SVSHE = 1, SVSHRVL = 1	1.79	1.88	1.98	
	SVSHE = 1, SVSHRVL = 2	1.98	2.08	2.21	
	SVSHE = 1, SVSHRVL = 3	2.10	2.18	2.31	
$V_{(SVSH_IT+)}$ SVS _H off voltage level ⁽¹⁾	SVSHE = 1, SVSMHRRRL = 0	1.62	1.74	1.85	V
	SVSHE = 1, SVSMHRRRL = 1	1.88	1.94	2.07	
	SVSHE = 1, SVSMHRRRL = 2	2.07	2.14	2.28	
	SVSHE = 1, SVSMHRRRL = 3	2.20	2.30	2.42	
	SVSHE = 1, SVSMHRRRL = 4	2.32	2.40	2.55	
	SVSHE = 1, SVSMHRRRL = 5	2.52	2.70	2.88	
	SVSHE = 1, SVSMHRRRL = 6	2.90	3.10	3.23	
	SVSHE = 1, SVSMHRRRL = 7	2.90	3.10	3.23	
$t_{pd(SVSH)}$ SVS _H propagation delay	SVSHE = 1, dV _{DVCC} /dt = 10 mV/μs, SVSHFP = 1		2.5		μs
	SVSHE = 1, dV _{DVCC} /dt = 1 mV/μs, SVSHFP = 0		20		
$t_{(SVSH)}$ SVS _H on or off delay time	SVSHE = 0 → 1, dV _{DVCC} /dt = 10 mV/μs, SVSHFP = 1		12.5		μs
	SVSHE = 0 → 1, dV _{DVCC} /dt = 1 mV/μs, SVSHFP = 0		100		
dV _{DVCC} /dt DV _{CC} rise time		0		1000	V/s

(1) The SVS_H settings available depend on the VCore (PMMCOREVx) setting. See the *Power Management Module and Supply Voltage Supervisor* chapter in the [MSP430x5xx and MSP430x6xx Family User's Guide](#) on recommended settings and use.

5.23 PMM, SVM High Side

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$I_{(SVMH)}$ SVM _H current consumption	SVMHE = 0, DV _{CC} = 3.6 V		0		nA
	SVMHE = 1, DV _{CC} = 3.6 V, SVMHFP = 0		200		
	SVMHE = 1, DV _{CC} = 3.6 V, SVMHFP = 1		1.5		μA
$V_{(SVMH)}$ SVM _H on or off voltage level ⁽¹⁾	SVMHE = 1, SVSMHRRRL = 0	1.62	1.74	1.85	V
	SVMHE = 1, SVSMHRRRL = 1	1.88	1.94	2.07	
	SVMHE = 1, SVSMHRRRL = 2	2.07	2.14	2.28	
	SVMHE = 1, SVSMHRRRL = 3	2.20	2.30	2.42	
	SVMHE = 1, SVSMHRRRL = 4	2.32	2.40	2.55	
	SVMHE = 1, SVSMHRRRL = 5	2.52	2.70	2.88	
	SVMHE = 1, SVSMHRRRL = 6	2.90	3.10	3.23	
	SVMHE = 1, SVSMHRRRL = 7	2.90	3.10	3.23	
$t_{pd(SVMH)}$ SVM _H propagation delay	SVMHE = 1, dV _{DVCC} /dt = 10 mV/μs, SVMHFP = 1		2.5		μs
	SVMHE = 1, dV _{DVCC} /dt = 1 mV/μs, SVMHFP = 0		20		
$t_{(SVMH)}$ SVM _H on or off delay time	SVMHE = 0 → 1, dV _{DVCC} /dt = 10 mV/μs, SVMHFP = 1		12.5		μs
	SVMHE = 0 → 1, dV _{DVCC} /dt = 1 mV/μs, SVMHFP = 0		100		

(1) The SVM_H settings available depend on the V_{CORE} (PMMCOREVx) setting. See the *Power Management Module and Supply Voltage Supervisor* chapter in the [MSP430x5xx and MSP430x6xx Family User's Guide](#) on recommended settings and use.

5.24 PMM, SVS Low Side

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$I_{(SVSL)}$ SVS _L current consumption	SVSLE = 0, PMMCOREV = 2		0		nA
	SVSLE = 1, PMMCOREV = 2, SVSLFP = 0		200		
	SVSLE = 1, PMMCOREV = 2, SVSLFP = 1		1.5		μA
$t_{pd(SVSL)}$ SVS _L propagation delay	SVSLE = 1, dV _{CORE} /dt = 10 mV/μs, SVSLFP = 1		2.5		μs
	SVSLE = 1, dV _{CORE} /dt = 1 mV/μs, SVSLFP = 0		20		
$t_{(SVSL)}$ SVS _L on or off delay time	SVSLE = 0 → 1, dV _{CORE} /dt = 10 mV/μs, SVSLFP = 1		12.5		μs
	SVSLE = 0 → 1, dV _{CORE} /dt = 1 mV/μs, SVSLFP = 0		100		

5.25 PMM, SVM Low Side

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$I_{(SVML)}$ SVM _L current consumption	SVMLE = 0, PMMCOREV = 2		0		nA
	SVMLE = 1, PMMCOREV = 2, SVMLFP = 0		200		
	SVMLE = 1, PMMCOREV = 2, SVMLFP = 1		1.5		μA
$t_{pd(SVML)}$ SVM _L propagation delay	SVMLE = 1, $dV_{CORE}/dt = 10 \text{ mV}/\mu\text{s}$, SVMLFP = 1		2.5		μs
	SVMLE = 1, $dV_{CORE}/dt = 1 \text{ mV}/\mu\text{s}$, SVMLFP = 0		20		
$t_{(SVML)}$ SVM _L on or off delay time	SVMLE = 0 → 1, $dV_{CORE}/dt = 10 \text{ mV}/\mu\text{s}$, SVMLFP = 1		12.5		μs
	SVMLE = 0 → 1, $dV_{CORE}/dt = 1 \text{ mV}/\mu\text{s}$, SVMLFP = 0		100		

5.26 Wake-up Times From Low-Power Modes and Reset

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{\text{WAKE-UP-FAST}}$ Wake-up time from LPM2, LPM3, or LPM4 to active mode ⁽¹⁾	PMMCOREV = SVSMLRRL = n (where n = 0, 1, 2, or 3), SVSLFP = 1, $f_{\text{MCLK}} \geq 4 \text{ MHz}$		3.5	7.5	μs
	$1 \text{ MHz} < f_{\text{MCLK}} < 4 \text{ MHz}$		4.5	9	
$t_{\text{WAKE-UP-SLOW}}$ Wake-up time from LPM2, LPM3 or LPM4 to active mode ⁽²⁾⁽³⁾	PMMCOREV = SVSMLRRL = n (where n = 0, 1, 2, or 3), SVSLFP = 0		150	175	μs
$t_{\text{WAKE-UP-LPM5}}$ Wake-up time from LPM4.5 to active mode ⁽⁴⁾			2	3	ms
$t_{\text{WAKE-UP-RESET}}$ Wake-up time from $\overline{\text{RST}}$ or BOR event to active mode ⁽⁴⁾			2	3	ms

- (1) This value represents the time from the wake-up event to the first active edge of MCLK. The wake-up time depends on the performance mode of the low-side supervisor (SVS_L) and low-side monitor (SVM_L). $t_{\text{WAKE-UP-FAST}}$ is possible with SVS_L and SVM_L in full performance mode or disabled. For specific register settings, see the *Low-Side SVS and SVM Control and Performance Mode Selection* section in the *Power Management Module and Supply Voltage Supervisor* chapter of the [MSP430x5xx and MSP430x6xx Family User's Guide](#).
- (2) This value represents the time from the wake-up event to the first active edge of MCLK. The wake-up time depends on the performance mode of the low-side supervisor (SVS_L) and low-side monitor (SVM_L). $t_{\text{WAKE-UP-SLOW}}$ is set with SVS_L and SVM_L in normal mode (low current mode). For specific register settings, see the *Low-Side SVS and SVM Control and Performance Mode Selection* section in the *Power Management Module and Supply Voltage Supervisor* chapter of the [MSP430x5xx and MSP430x6xx Family User's Guide](#).
- (3) The wake-up times from LPM0 and LPM1 to AM are not specified. They are proportional to MCLK cycle time but are not affected by the performance mode settings as for LPM2, LPM3, and LPM4.
- (4) This value represents the time from the wake-up event to the reset vector execution.

5.27 Timer_A

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	MAX	UNIT
f _{TA} Timer_A input clock frequency	Internal: SMCLK or ACLK, External: TACLK, Duty cycle = 50% ±10%	1.8 V		25	MHz
		3.0 V		25	
t _{TA,cap} Timer_A capture timing ⁽¹⁾	All capture inputs, minimum pulse duration required for capture	1.8 V	20		ns
		3.0 V	20		

- (1) The external signal sets the interrupt flag every time the minimum parameters are met. It may be set even with trigger signals shorter than t_{TA,cap}.

5.28 Timer_B

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	MAX	UNIT
f _{TB} Timer_B input clock frequency	Internal: SMCLK or ACLK, External: TBCLK, Duty cycle = 50% ±10%	1.8 V		25	MHz
		3.0 V		25	
t _{TB,cap} Timer_B capture timing ⁽¹⁾	All capture inputs, minimum pulse duration required for capture	1.8 V	20		ns
		3.0 V	20		

- (1) The external signal sets the interrupt flag every time the minimum parameters are met. It may be set even with trigger signals shorter than t_{TB,cap}.

5.29 USCI (UART Mode) Clock Frequency

PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
f _{USCI} USCI input clock frequency	Internal: SMCLK or ACLK, External: UCLK, Duty cycle = 50% ±10%		f _{SYSTEM}	MHz
f _{BITCLK} BITCLK clock frequency (equals baud rate in MBaud)			1	MHz

5.30 USCI (UART Mode)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	V _{CC}	MIN	MAX	UNIT
t _r UART receive deglitch time ⁽¹⁾	1.8 V	50	600	ns
	3.0 V	50	600	

- (1) Pulses on the UART receive input (UCxRX) shorter than the UART receive deglitch time are suppressed. To make sure that pulses are correctly recognized, their duration should exceed the maximum specification of the deglitch time.

5.31 USCI (SPI Master Mode) Clock Frequency

PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
f_{USCI} USCI input clock frequency	Internal: SMCLK or ACLK, Duty cycle = 50% $\pm$ 10%		f_{SYSTEM}	MHz

5.32 USCI (SPI Master Mode)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)⁽¹⁾
(see [Figure 5-12](#) and [Figure 5-13](#))

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	MAX	UNIT
f_{USCI} USCI input clock frequency	SMCLK, ACLK, Duty cycle = 50% $\pm$ 10%			f_{SYSTEM}	MHz
$t_{SU,MI}$ SOMI input data setup time	PMMCOREV = 0	1.8 V	55		ns
		3.0 V	38		
	PMMCOREV = 3	2.4 V	30		
		3.0 V	25		
$t_{HD,MI}$ SOMI input data hold time	PMMCOREV = 0	1.8 V	0		ns
		3.0 V	0		
	PMMCOREV = 3	2.4 V	0		
		3.0 V	0		
$t_{VALID,MO}$ SIMO output data valid time ⁽²⁾	UCLK edge to SIMO valid, C _L = 20 pF, PMMCOREV = 0	1.8 V		20	ns
		3.0 V		18	
	UCLK edge to SIMO valid, C _L = 20 pF, PMMCOREV = 3	2.4 V		16	
		3.0 V		15	
$t_{HD,MO}$ SIMO output data hold time ⁽³⁾	C _L = 20 pF, PMMCOREV = 0	1.8 V	–10		ns
		3.0 V	–8		
	C _L = 20 pF, PMMCOREV = 3	2.4 V	–10		
		3.0 V	–8		

(1) $f_{UCXCLK} = 1/2t_{LO/HI}$ with $t_{LO/HI} \geq \max(t_{VALID,MO}(USCI) + t_{SU,SI}(Slave), t_{SU,MI}(USCI) + t_{VALID,SO}(Slave))$

For the slave parameters $t_{SU,SI}(Slave)$ and $t_{VALID,SO}(Slave)$, see the SPI parameters of the attached slave.

(2) Specifies the time to drive the next valid data to the SIMO output after the output changing UCLK clock edge. Refer to the timing diagrams in [Figure 5-12](#) and [Figure 5-13](#).

(3) Specifies how long data on the SIMO output is valid after the output changing UCLK clock edge. Negative values indicate that the data on the SIMO output can become invalid before the output changing clock edge observed on UCLK. Refer to the timing diagrams in [Figure 5-12](#) and [Figure 5-13](#).

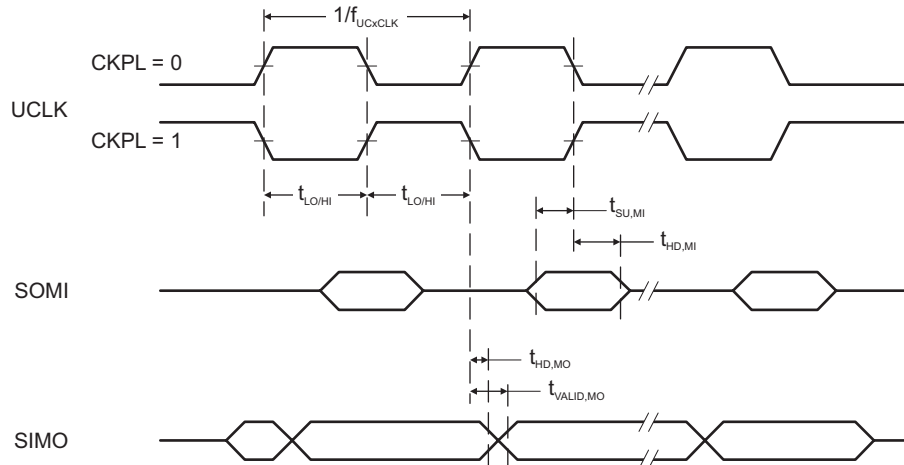


Figure 5-12. SPI Master Mode, CKPH = 0

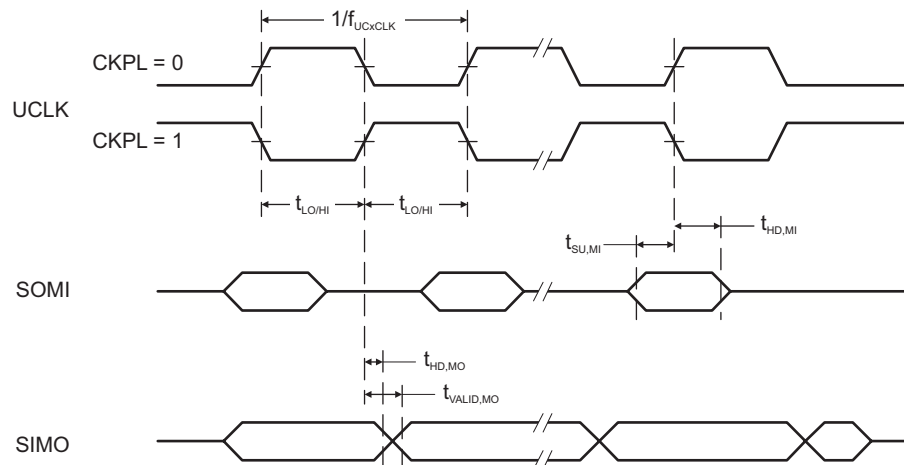


Figure 5-13. SPI Master Mode, CKPH = 1

5.33 USCI (SPI Slave Mode)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)⁽¹⁾
(see [Figure 5-14](#) and [Figure 5-15](#))

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	MAX	UNIT
$t_{STE,LEAD}$ STE lead time, STE low to clock	PMMCOREV = 0	1.8 V	11		ns
		3.0 V	8		
	PMMCOREV = 3	2.4 V	7		
		3.0 V	6		
$t_{STE,LAG}$ STE lag time, Last clock to STE high	PMMCOREV = 0	1.8 V	3		ns
		3.0 V	3		
	PMMCOREV = 3	2.4 V	3		
		3.0 V	3		
$t_{STE,ACC}$ STE access time, STE low to SOMI data out	PMMCOREV = 0	1.8 V		66	ns
		3.0 V		50	
	PMMCOREV = 3	2.4 V		36	
		3.0 V		30	
$t_{STE,DIS}$ STE disable time, STE high to SOMI high impedance	PMMCOREV = 0	1.8 V		30	ns
		3.0 V		23	
	PMMCOREV = 3	2.4 V		16	
		3.0 V		13	
$t_{SU,SI}$ SIMO input data setup time	PMMCOREV = 0	1.8 V	5		ns
		3.0 V	5		
	PMMCOREV = 3	2.4 V	2		
		3.0 V	2		
$t_{HD,SI}$ SIMO input data hold time	PMMCOREV = 0	1.8 V	5		ns
		3.0 V	5		
	PMMCOREV = 3	2.4 V	5		
		3.0 V	5		
$t_{VALID,SO}$ SOMI output data valid time ⁽²⁾	UCLK edge to SOMI valid, C _L = 20 pF, PMMCOREV = 0	1.8 V		76	ns
		3.0 V		60	
	UCLK edge to SOMI valid, C _L = 20 pF, PMMCOREV = 3	2.4 V		44	
		3.0 V		40	
$t_{HD,SO}$ SOMI output data hold time ⁽³⁾	C _L = 20 pF, PMMCOREV = 0	1.8 V	18		ns
		3.0 V	12		
	C _L = 20 pF, PMMCOREV = 3	2.4 V	10		
		3.0 V	8		

- $f_{UCXCLK} = 1/2(t_{LO/Hi} \text{ with } t_{LO/Hi} \geq \max(t_{VALID,MO(Master)} + t_{SU,SI(USCI)}, t_{SU,MI(Master)} + t_{VALID,SO(USCI)})$
For the master parameters $t_{SU,MI(Master)}$ and $t_{VALID,MO(Master)}$, see the SPI parameters of the attached master.
- Specifies the time to drive the next valid data to the SOMI output after the output changing UCLK clock edge. Refer to the timing diagrams in [Figure 5-12](#) and [Figure 5-13](#).
- Specifies how long data on the SOMI output is valid after the output changing UCLK clock edge. Refer to the timing diagrams in [Figure 5-12](#) and [Figure 5-13](#).

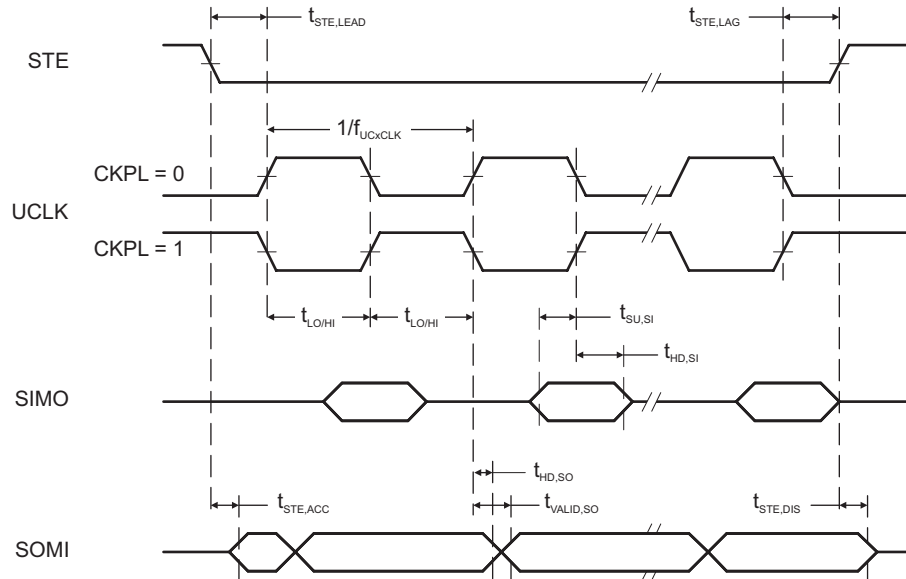


Figure 5-14. SPI Slave Mode, CKPH = 0

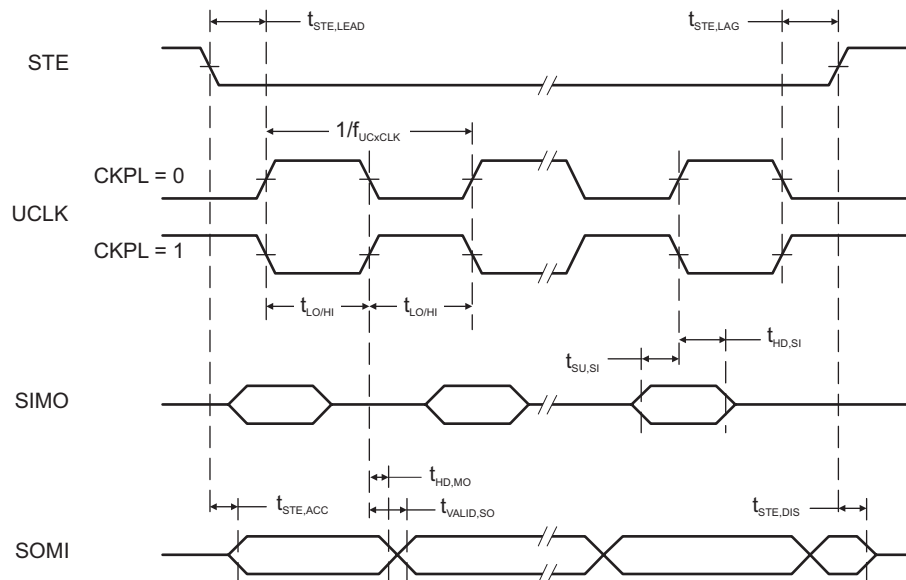


Figure 5-15. SPI Slave Mode, CKPH = 1

5.34 USCI (I²C Mode)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see [Figure 5-16](#))

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	MAX	UNIT
f _{USCI} USCI input clock frequency	Internal: SMCLK or ACLK, External: UCLK Duty cycle = 50% ±10%		f _{SYSTEM}		MHz
f _{SCL} SCL clock frequency		2.2 V, 3 V	0	400	kHz
t _{HD,STA} Hold time (repeated) START	f _{SCL} ≤ 100 kHz	2.2 V, 3 V	4.0		μs
	f _{SCL} > 100 kHz		0.6		
t _{SU,STA} Setup time for a repeated START	f _{SCL} ≤ 100 kHz	2.2 V, 3 V	4.7		μs
	f _{SCL} > 100 kHz		0.6		
t _{HD,DAT} Data hold time		2.2 V, 3 V	0		ns
t _{SU,DAT} Data setup time		2.2 V, 3 V	250		ns
t _{SU,STO} Setup time for STOP	f _{SCL} ≤ 100 kHz	2.2 V, 3 V	4.0		μs
	f _{SCL} > 100 kHz		0.6		
t _{SP} Pulse duration of spikes suppressed by input filter		2.2 V, 3 V	50	600	ns

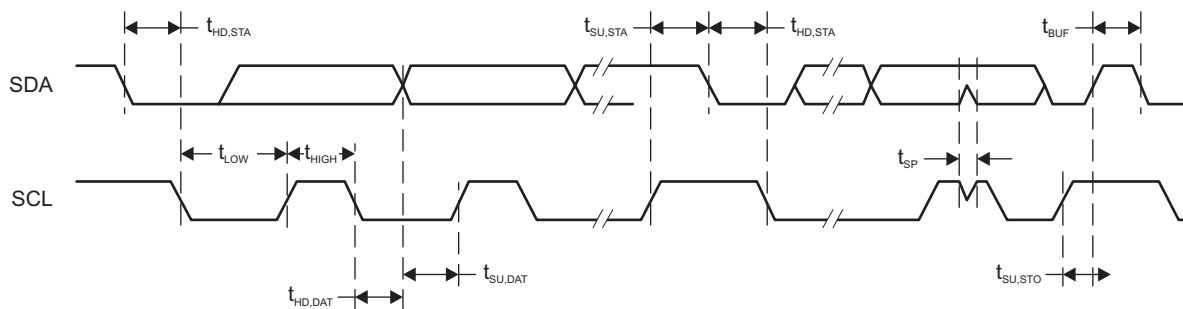


Figure 5-16. I²C Mode Timing

5.35 10-Bit ADC, Power Supply and Input Range Conditions

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)⁽¹⁾

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
AV _{CC}	Analog supply voltage	AV _{CC} and DV _{CC} are connected together, AV _{SS} and DV _{SS} are connected together, V _(AVSS) = V _(DVSS) = 0 V		1.8		3.6	V
V _(Ax)	Analog input voltage range ⁽²⁾	All ADC10_A pins: P1.0 to P1.5, P3.6, and P3.7 terminals		0		AV _{CC}	V
I _{ADC10_A}	Operating supply current into AVCC terminal, REF module and reference buffer off	f _{ADC10CLK} = 5.0 MHz, ADC10ON = 1, REFON = 0, SHT0 = 0, SHT1 = 0, ADC10DIV = 0, ADC10SREF = 00	2.2 V		60	100	μA
			3 V		75	110	
	Operating supply current into AVCC terminal, REF module on, reference buffer on	f _{ADC10CLK} = 5.0 MHz, ADC10ON = 1, REFON = 1, SHT0 = 0, SHT1 = 0, ADC10DIV = 0, ADC10SREF = 01	3 V		113	150	
	Operating supply current into AVCC terminal, REF module off, reference buffer on	f _{ADC10CLK} = 5.0 MHz, ADC10ON = 1, REFON = 0, SHT0 = 0, SHT1 = 0, ADC10DIV = 0, ADC10SREF = 10, VREF = 2.5 V	3 V		105	140	
	Operating supply current into AVCC terminal, REF module off, reference buffer off	f _{ADC10CLK} = 5.0 MHz, ADC10ON = 1, REFON = 0, SHT0 = 0, SHT1 = 0, ADC10DIV = 0, ADC10SREF = 11, VREF = 2.5 V	3 V		70	110	
C _I	Input capacitance	Only one terminal Ax can be selected at one time from the pad to the ADC10_A capacitor array including wiring and pad	2.2 V		3.5		pF
R _I	Input MUX ON resistance	AV _{CC} > 2.0 V, 0 V ≤ V _{Ax} ≤ AV _{CC}				36	kΩ
		1.8 V < AV _{CC} < 2 V, 0 V ≤ V _{Ax} ≤ AV _{CC}				96	

(1) The leakage current is defined in the leakage current table with P6.x/Ax parameter.

(2) The analog input voltage range must be within the selected reference voltage range V_{R+} to V_{R-} for valid conversion results. The external reference voltage requires decoupling capacitors. Two decoupling capacitors, 10 μF and 100 nF, should be connected to VREF to decouple the dynamic current required for an external reference source if it is used for the ADC10_A. See also the [MSP430x5xx and MSP430x6xx Family User's Guide](#).

5.36 10-Bit ADC, Timing Parameters

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
f _{ADC10CLK}		For specified performance of ADC10_A linearity parameters	2.2 V, 3 V	0.45	5	5.5	MHz
f _{ADC10OSC}	Internal ADC10_A oscillator ⁽¹⁾	ADC10DIV = 0, f _{ADC10CLK} = f _{ADC10OSC}	2.2 V, 3 V	4.2	4.8	5.4	MHz
t _{CONVERT}	Conversion time	REFON = 0, Internal oscillator, 12 ADC10CLK cycles, 10-bit mode, f _{ADC10OSC} = 4 MHz to 5 MHz	2.2 V, 3 V	2.4		3.0	μs
		External f _{ADC10CLK} from ACLK, MCLK or SMCLK, ADC10SSEL ≠ 0			12 × 1 / f _{ADC10CLK}		
t _{ADC10ON}	Turnon settling time of the ADC	See ⁽²⁾				100	ns
t _{Sample}	Sampling time	R _S = 1000 Ω, R _I = 96 k Ω, C _I = 3.5 pF ⁽³⁾	1.8 V	3			μs
			3.0 V	1			

(1) The ADC10OSC is sourced directly from MODOSC inside the UCS.

(2) The condition is that the error in a conversion started after t_{ADC10ON} is less than ±0.5 LSB. The reference and input signal are already settled.

(3) Approximately 8 Tau (τ) are needed to get an error of less than ±0.5 LSB

5.37 10-Bit ADC, Linearity Parameters

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
E _I	Integral linearity error	$1.4\text{ V} \leq (V_{\text{eREF}+} - V_{\text{eREF}-}) \leq 1.6\text{ V}$, $C_{\text{VeREF}+} = 20\text{ pF}$	2.2 V, 3 V			±1.0	LSB
		$1.6\text{ V} < (V_{\text{eREF}+} - V_{\text{eREF}-}) \leq V_{\text{AVCC}}$, $C_{\text{VeREF}+} = 20\text{ pF}$				±1.0	
E _D	Differential linearity error	$1.4\text{ V} \leq (V_{\text{eREF}+} - V_{\text{eREF}-})$, $C_{\text{VeREF}+} = 20\text{ pF}$	2.2 V, 3 V			±1.0	LSB
E _O	Offset error	$1.4\text{ V} \leq (V_{\text{eREF}+} - V_{\text{eREF}-})$, $C_{\text{VeREF}+} = 20\text{ pF}$, Internal impedance of source $R_S < 100\ \Omega$	2.2 V, 3 V			±1.0	LSB
E _G	Gain error	$1.4\text{ V} \leq (V_{\text{eREF}+} - V_{\text{eREF}-})$, $C_{\text{VeREF}+} = 20\text{ pF}$, ADC10SREFX = 11b	2.2 V, 3 V			±1.0	LSB
E _T	Total unadjusted error	$1.4\text{ V} \leq (V_{\text{eREF}+} - V_{\text{eREF}-})$, $C_{\text{VeREF}+} = 20\text{ pF}$, ADC10SREFX = 11b	2.2 V, 3 V		±1.0	±2.0	LSB

5.38 REF, External Reference

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)⁽¹⁾

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
V _{eREF+}	Positive external reference voltage input	$V_{\text{eREF}+} > V_{\text{eREF}-}$ ⁽²⁾		1.4		AV _{CC}	V
V _{eREF-}	Negative external reference voltage input	$V_{\text{eREF}+} > V_{\text{eREF}-}$ ⁽³⁾		0		1.2	V
(V _{eREF+} – V _{eREF-})	Differential external reference voltage input	$V_{\text{eREF}+} > V_{\text{eREF}-}$ ⁽⁴⁾		1.4		AV _{CC}	V
I _{VeREF+} I _{VeREF-}	Static input current	$1.4\text{ V} \leq V_{\text{eREF}+} \leq V_{\text{AVCC}}$, $V_{\text{eREF}-} = 0\text{ V}$, $f_{\text{ADC10CLK}} = 5\text{ MHz}$, ADC10SHTX = 0x0001, Conversion rate 200 kpsps	2.2 V, 3 V	–26		26	μA
		$1.4\text{ V} \leq V_{\text{eREF}+} \leq V_{\text{AVCC}}$, $V_{\text{eREF}-} = 0\text{ V}$, $f_{\text{ADC10CLK}} = 5\text{ MHz}$, ADC10SHTX = 0x1000, Conversion rate 20 kpsps	2.2 V, 3 V	–1		1	
C _{VeREF+/-}	Capacitance at VeREF+ or VeREF- terminal	See ⁽⁵⁾		10			μF

- (1) The external reference is used during ADC conversion to charge and discharge the capacitance array. The input capacitance, C_I, is also the dynamic load for an external reference during conversion. The dynamic impedance of the reference supply should follow the recommendations on analog-source impedance to allow the charge to settle for 10-bit accuracy.
- (2) The accuracy limits the minimum positive external reference voltage. Lower reference voltage levels may be applied with reduced accuracy requirements.
- (3) The accuracy limits the maximum negative external reference voltage. Higher reference voltage levels may be applied with reduced accuracy requirements.
- (4) The accuracy limits minimum external differential reference voltage. Lower differential reference voltage levels may be applied with reduced accuracy requirements.
- (5) Two decoupling capacitors, 10 μF and 100 nF, should be connected to VREF to decouple the dynamic current required for an external reference source if it is used for the ADC10_A. See also the [MSP430x5xx and MSP430x6xx Family User's Guide](#).

5.39 REF, Built-In Reference

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)⁽¹⁾

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
V _{REF+}	REFVSEL = {2} for 2.5 V, REFON = 1	3 V	2.472	2.51	2.548	V
	REFVSEL = {1} for 2.0 V, REFON = 1	3 V	1.96	1.99	2.02	
	REFVSEL = {0} for 1.5 V, REFON = 1	2.2 V, 3 V	1.472	1.495	1.518	
AV _{CC(min)}	REFVSEL = {0} for 1.5 V		1.8			V
	REFVSEL = {1} for 2.0 V		2.2			
	REFVSEL = {2} for 2.5 V		2.7			
I _{REF+}	f _{ADC10CLK} = 5.0 MHz, REFON = 1, REFBURST = 0, REFVSEL = {2} for 2.5 V	3 V		18	24	μA
	f _{ADC10CLK} = 5.0 MHz, REFON = 1, REFBURST = 0, REFVSEL = {1} for 2.0 V	3 V		15.5	21	μA
	f _{ADC10CLK} = 5.0 MHz, REFON = 1, REFBURST = 0, REFVSEL = {0} for 1.5 V	3 V		13.5	21	μA
TC _{REF+}	I _{VREF+} = 0 A, REFVSEL = {0, 1, 2}, REFON = 1			30	50	ppm/ °C
I _{SENSOR}	REFON = 0, INCH = 0Ah, ADC10ON = N/A, T _A = 30°C	2.2 V		20	22	μA
		3 V		20	22	
V _{SENSOR}	ADC10ON = 1, INCH = 0Ah, T _A = 30°C	2.2 V		770		mV
		3 V		770		
V _{MID}	ADC10ON = 1, INCH = 0Bh, V _{MID} ≈ 0.5 × V _{AVCC}	2.2 V	1.06	1.1	1.14	V
		3 V	1.46	1.5	1.54	
t _{SENSOR(sample)}	ADC10ON = 1, INCH = 0Ah, Error of conversion result ≤ 1 LSB			30		μs
t _{VMID(sample)}	ADC10ON = 1, INCH = 0Bh, Error of conversion result ≤ 1 LSB			1		μs
PSRR _{DC}	AV _{CC} = AV _{CC(min)} to AV _{CC(max)} , T _A = 25 °C, REFVSEL = {0, 1, 2}, REFON = 1			120		μV/V
PSRR _{AC}	AV _{CC} = AV _{CC(min)} to AV _{CC(max)} , T _A = 25°C, f = 1 kHz, ΔV _{pp} = 100 mV, REFVSEL = {0, 1, 2}, REFON = 1			6.4		mV/V
t _{SETTLE}	AV _{CC} = AV _{CC(min)} to AV _{CC(max)} , REFVSEL = {0, 1, 2}, REFON = 0 → 1			75		μs

- (1) The leakage current is defined in the leakage current table with P6.x/Ax parameter.
- (2) The internal reference current is supplied through the AVCC terminal. Consumption is independent of the ADC10ON control bit, unless a conversion is active. The REFON bit enables to settle the built-in reference before starting an A/D conversion.
- (3) Calculated using the box method: (MAX(−40°C to 85°C) – MIN(−40°C to 85°C)) / MIN(−40°C to 85°C)/(85°C – (−40°C)).
- (4) The sensor current I_{SENSOR} is consumed if (ADC10ON = 1 and REFON = 1) or (ADC10ON = 1 and INCH = 0Ah and sample signal is high). When REFON = 1, I_{SENSOR} is already included in I_{REF+}.
- (5) The temperature sensor offset can be significant. TI recommends a single-point calibration to minimize the offset error of the built-in temperature sensor.
- (6) The typical equivalent impedance of the sensor is 51 kΩ. The sample time required includes the sensor-on time t_{SENSOR(on)}.
- (7) The on-time t_{VMID(on)} is included in the sampling time t_{VMID(sample)}; no additional on time is needed.
- (8) The condition is that the error in a conversion started after t_{REFON} is less than ±0.5 LSB.

5.40 Comparator_B

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
V _{CC}	Supply voltage		1.8		3.6	V
I _{AVCC_COMP}	Comparator operating supply current into AVCC, excludes reference resistor ladder	1.8 V			38	μA
		2.2 V		31	38	
		3 V		32	39	
		2.2 V, 3 V		10	17	
	CBPWRMD = 00, CBON = 1, CBRsX = 00					
	CBPWRMD = 01, CBON = 1, CBRsX = 00					
	CBPWRMD = 10, CBON = 1, CBRsX = 00			0.2	0.85	
V _{REF}	Reference voltage level	≥ 1.8 V		1.44	±2.5%	V
		≥ 2.2 V		1.92	±2.5%	
		≥ 3.0 V		2.39	±2.5%	
I _{AVCC_REF}	Quiescent current of resistor ladder into AVCC, includes REF module current	2.2 V, 3 V		17	22	μA
		2.2 V, 3 V		33	40	
	CBREFLX = 01, CBREFACC = 0					
	CBREFLX = 10, CBREFACC = 0					
	CBREFLX = 11, CBREFACC = 0					
V _{IC}	Common mode input range		0		V _{CC} – 1	V
V _{OFFSET}	Input offset voltage	CBPWRMD = 00	–20		20	mV
		CBPWRMD = 01 or 10	–10		10	
C _{IN}	Input capacitance			5		pF
R _{SIN}	Series input resistance	On (switch closed)		3	4	kΩ
		Off (switch open)	50			MΩ
t _{PD}	Propagation delay, response time	CBPWRMD = 00, CBF = 0			450	ns
		CBPWRMD = 01, CBF = 0			600	
		CBPWRMD = 10, CBF = 0			50	
t _{PD,filter}	Propagation delay with filter active	CBPWRMD = 00, CBON = 1, CBF = 1, CBF _{DLY} = 00	0.35	0.6	1.5	μs
		CBPWRMD = 00, CBON = 1, CBF = 1, CBF _{DLY} = 01	0.6	1.0	1.8	
		CBPWRMD = 00, CBON = 1, CBF = 1, CBF _{DLY} = 10	1.0	1.8	3.4	
		CBPWRMD = 00, CBON = 1, CBF = 1, CBF _{DLY} = 11	1.8	3.4	6.5	
t _{EN_CMP}	Comparator enable time	CBON = 0 to CBON = 1, CBPWRMD = 00 or 01		1	2	μs
		CBON = 0 to CBON = 1, CBPWRMD = 10			100	
t _{EN_REF}	Resistor reference enable time	CBON = 0 to CBON = 1		1.0	1.5	μs
TC _{CB_REF}	Temperature coefficient of V _{CB_REF}				50	ppm/°C
V _{CB_REF}	Reference voltage for a given tap	V _{IN} = reference into resistor ladder, n = 0 to 31		V _{IN} × (n + 0.5) / 32	V _{IN} × (n + 1) / 32	V

5.41 Flash Memory

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		T _J	MIN	TYP	MAX	UNIT
DV _{CC(PGM/ERASE)}	Program and erase supply voltage		1.8		3.6	V
I _{PGM}	Average supply current from DVCC during program			3	5	mA
I _{ERASE}	Average supply current from DVCC during erase			6	11	mA
I _{MERASE} , I _{BANK}	Average supply current from DVCC during mass erase or bank erase			6	11	mA
t _{CPT}	Cumulative program time ⁽¹⁾				16	ms
	Program and erase endurance		10 ⁴	10 ⁵		cycles
t _{Retention}	Data retention duration	25°C	100			years
t _{Word}	Word or byte program time ⁽²⁾		64		85	μs
t _{Block, 0}	Block program time for first byte or word ⁽²⁾		49		65	μs
t _{Block, 1–(N–1)}	Block program time for each additional byte or word, except for last byte or word ⁽²⁾		37		49	μs
t _{Block, N}	Block program time for last byte or word ⁽²⁾		55		73	μs
t _{Erase}	Erase time for segment, mass erase, and bank erase when available ⁽²⁾		23		32	ms
f _{MCLK,MGR}	MCLK frequency in marginal read mode (FCTL4.MGR0 = 1 or FCTL4.MGR1 = 1)		0		1	MHz

(1) The cumulative program time must not be exceeded when writing to a 128-byte flash block. This parameter applies to all programming methods: individual word write, individual byte write, and block write modes.

(2) These values are hardwired into the state machine of the flash controller.

5.42 JTAG and Spy-Bi-Wire Interface

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		V _{CC}	MIN	TYP	MAX	UNIT
f _{SBW}	Spy-Bi-Wire input frequency	2.2 V, 3 V	0		20	MHz
t _{SBW,Low}	Spy-Bi-Wire low clock pulse length	2.2 V, 3 V	0.025		15	μs
t _{SBW,En}	Spy-Bi-Wire enable time (TEST high to acceptance of first clock edge) ⁽¹⁾	2.2 V, 3 V			1	μs
t _{SBW,Rst}	Spy-Bi-Wire return to normal operation time		15		100	μs
f _{TCK}	TCK input frequency - 4-wire JTAG ⁽²⁾	2.2 V	0		5	MHz
		3 V	0		10	MHz
R _{Internal}	Internal pulldown resistance on TEST	2.2 V, 3 V	45	60	80	kΩ

(1) Tools that access the Spy-Bi-Wire interface must wait for the t_{SBW,En} time after pulling the TEST/SBW_{TCK} pin high before applying the first SBW_{TCK} clock edge.

(2) f_{TCK} may be restricted to meet the timing requirements of the module selected.

6 Detailed Description

6.1 CPU ([Link to User's Guide](#))

The MSP430 CPU has a 16-bit RISC architecture that is highly transparent to the application. All operations, other than program-flow instructions, are performed as register operations in conjunction with seven addressing modes for source operand and four addressing modes for destination operand.

The CPU is integrated with 16 registers that provide reduced instruction execution time. The register-to-register operation execution time is one cycle of the CPU clock. Four of the registers, R0 to R3, are dedicated as program counter, stack pointer, status register, and constant generator, respectively. The remaining registers are general-purpose registers (see [图 6-1](#)).

Peripherals are connected to the CPU using data, address, and control buses. Peripherals can be managed with all instructions.

The instruction set consists of the original 51 instructions with three formats and seven address modes and additional instructions for the expanded address range. Each instruction can operate on word and byte data.

Program Counter	PC/R0
Stack Pointer	SP/R1
Status Register	SR/CG1/R2
Constant Generator	CG2/R3
General-Purpose Register	R4
General-Purpose Register	R5
General-Purpose Register	R6
General-Purpose Register	R7
General-Purpose Register	R8
General-Purpose Register	R9
General-Purpose Register	R10
General-Purpose Register	R11
General-Purpose Register	R12
General-Purpose Register	R13
General-Purpose Register	R14
General-Purpose Register	R15

图 6-1. CPU Registers

6.2 Operating Modes

The microcontrollers has one active mode and six software selectable low-power modes of operation. An interrupt event can wake up the device from any of the low-power modes, service the request, and restore back to the low-power mode on return from the interrupt program.

Software can configure the following operating modes:

- Active mode (AM)
 - All clocks are active
- Low-power mode 0 (LPM0)
 - CPU is disabled
 - ACLK and SMCLK remain active, MCLK is disabled
 - FLL loop control remains active
- Low-power mode 1 (LPM1)
 - CPU is disabled
 - FLL loop control is disabled
 - ACLK and SMCLK remain active, MCLK is disabled
- Low-power mode 2 (LPM2)
 - CPU is disabled
 - MCLK and FLL loop control and DCOCLK are disabled
 - DC generator of the DCO remains enabled
 - ACLK remains active
- Low-power mode 3 (LPM3)
 - CPU is disabled
 - MCLK, FLL loop control, and DCOCLK are disabled
 - DC generator of the DCO is disabled
 - ACLK remains active
- Low-power mode 4 (LPM4)
 - CPU is disabled
 - ACLK is disabled
 - MCLK, FLL loop control, and DCOCLK are disabled
 - DC generator of the DCO is disabled
 - Crystal oscillator is stopped
 - Complete data retention
- Low-power mode 4.5 (LPM4.5)
 - Internal regulator disabled
 - No data retention
 - Wake-up input from $\overline{\text{RST}}$ /NMI, P1, and P2

6.3 Interrupt Vector Addresses

The interrupt vectors and the power-up start address are in the address range 0FFFFh to 0FF80h (see [表 6-1](#)). The vector contains the 16-bit address of the interrupt-handler instruction sequence.

表 6-1. Interrupt Sources, Flags, and Vectors

INTERRUPT SOURCE	INTERRUPT FLAG	SYSTEM INTERRUPT	WORD ADDRESS	PRIORITY
System Reset Power up External reset Watchdog time-out, password violation Flash memory password violation PMM password violation	WDTIFG, KEYV (SYSRSTIV) ^{(1) (2)}	Reset	0FFFEh	63, highest
System NMI PMM Vacant memory access JTAG mailbox	SVMLIFG, SVMHIFG, DLYLIFG, DLYHIFG, VLRIFG, VLRHIFG, VMAIFG, JMBNIFG, JMBOUTIFG (SYSSNIV) ⁽¹⁾	(Non)maskable	0FFFCh	62
User NMI NMI Oscillator fault Flash memory access violation	NMIIFG, OFIFG, ACCVIFG, BUSIFG (SYSUNIV) ^{(1) (2)}	(Non)maskable	0FFFAh	61
COMP_B	Comparator B interrupt flags (CBIV) ^{(1) (3)}	Maskable	0FFF8h	60
TB0	TB0CCR0 CCIFG0 ⁽³⁾	Maskable	0FFF6h	59
TB0	TB0CCR1 CCIFG1 to TB0CCR6 CCIFG6, TB0IFG (TB0IV) ^{(1) (3)}	Maskable	0FFF4h	58
WDT_A interval timer mode	WDTIFG	Maskable	0FFF2h	57
USCI_A0 receive or transmit	UCA0RXIFG, UCA0TXIFG (UCA0IV) ^{(1) (3)}	Maskable	0FFF0h	56
USCI_B0 receive or transmit	UCB0RXIFG, UCB0TXIFG (UCB0IV) ^{(1) (3)}	Maskable	0FFEEh	55
ADC10_A	ADC10IFG0 ^{(1) (3) (4)}	Maskable	0FFECCh	54
TA0	TA0CCR0 CCIFG0 ⁽³⁾	Maskable	0FFEAh	53
TA0	TA0CCR1 CCIFG1 to TA0CCR4 CCIFG4, TA0IFG (TA0IV) ^{(1) (3)}	Maskable	0FFE8h	52
Reserved	Reserved	Maskable	0FFE6h	51
DMA	DMA0IFG, DMA1IFG, DMA2IFG (DMAIV) ^{(1) (3)}	Maskable	0FFE4h	50
TA1	TA1CCR0 CCIFG0 ⁽³⁾	Maskable	0FFE2h	49
TA1	TA1CCR1 CCIFG1 to TA1CCR2 CCIFG2, TA1IFG (TA1IV) ^{(1) (3)}	Maskable	0FFE0h	48
I/O port P1	P1IFG.0 to P1IFG.7 (P1IV) ^{(1) (3)}	Maskable	0FFDEh	47
USCI_A1 receive or transmit	UCA1RXIFG, UCA1TXIFG (UCA1IV) ^{(1) (3)}	Maskable	0FFDCh	46
USCI_B1 receive or transmit	UCB1RXIFG, UCB1TXIFG (UCB1IV) ^{(1) (3)}	Maskable	0FFDAh	45
TA2	TA2CCR0 CCIFG0 ⁽³⁾	Maskable	0FFD8h	44
TA2	TA2CCR1 CCIFG1 to TA2CCR2 CCIFG2, TA2IFG (TA2IV) ^{(1) (3)}	Maskable	0FFD6h	43
I/O port P2	P2IFG.0 to P2IFG.7 (P2IV) ^{(1) (3)}	Maskable	0FFD4h	42
RTC_A	RTCRDYIFG, RTCTEVIFG, RTCAIFG, RT0PSIFG, RT1PSIFG (RTCIV) ^{(1) (3)}	Maskable	0FFD2h	41
Reserved	Reserved ⁽⁵⁾		0FFD0h	40
			⋮	⋮
			0FF80h	0, lowest

(1) Multiple source flags

(2) A reset is generated if the CPU tries to fetch instructions from within peripheral space or vacant memory space.

(Non)maskable: the individual interrupt enable bit can disable an interrupt event, but the general interrupt enable bit cannot disable it.

(3) Interrupt flags are in the module.

(4) Only on devices with ADC, otherwise reserved.

(5) Reserved interrupt vectors at addresses are not used in this device and can be used for regular program code if necessary. To maintain compatibility with other devices, TI recommends reserving these locations.

6.4 Memory Organization

表 6-2 summarizes the memory map of all device variants.

表 6-2. Memory Organization⁽¹⁾

		MSP430F5247, MSP430F5242, MSP430F5237, MSP430F5232	MSP430F5249, MSP430F5244, MSP430F5239, MSP430F5234
Memory (flash) Main: interrupt vector	Total Size	64KB 00FFFFh to 00FF80h	128KB 00FFFFh to 00FF80h
Main: code memory	Bank D	N/A	32KB 0243FFh to 01C400h
	Bank C	N/A	32KB 01C3FFh to 014400h
	Bank B	32KB 0143FFh to 00C400h	32KB 0143FFh to 00C400h
	Bank A	32KB 00C3FFh to 004400h	32KB 00C3FFh to 004400h
RAM	Sector 3	2KB 0043FFh to 003C00h	2KB 0043FFh to 003C00h
	Sector 2	2KB 003BFFh to 003400h	2KB 003BFFh to 003400h
	Sector 1	2KB 0033FFh to 002C00h	2KB 0033FFh to 002C00h
	Sector 0	2KB 002BFFh to 002400h	2KB 002BFFh to 002400h
TI factory memory (ROM)	A	128 B 001BFFh to 001B80h	128 B 001BFFh to 001B80h
	B	128 B 001B7Fh to 001B00h	128 B 001B7Fh to 001B00h
	C	128 B 001AFFh to 001A80h	128 B 001AFFh to 001A80h
	D	128 B 001A7Fh to 001A00h	128 B 001A7Fh to 001A00h
Information memory (flash)	Info A	128 B 0019FFh to 001980h	128 B 0019FFh to 001980h
	Info B	128 B 00197Fh to 001900h	128 B 00197Fh to 001900h
	Info C	128 B 0018FFh to 001880h	128 B 0018FFh to 001880h
	Info D	128 B 00187Fh to 001800h	128 B 00187Fh to 001800h
Bootloader (BSL) memory (flash)	BSL 3	512 B 0017FFh to 001600h	512 B 0017FFh to 001600h
	BSL 2	512 B 0015FFh to 001400h	512 B 0015FFh to 001400h
	BSL 1	512 B 0013FFh to 001200h	512 B 0013FFh to 001200h
	BSL 0	512 B 0011FFh to 001000h	512 B 0011FFh to 001000h
Peripherals	Size	4KB 000FFFh to 0h	4KB 000FFFh to 0h

(1) N/A = Not available

6.5 Bootloader (BSL)

The BSL enables users to program the flash memory or RAM using a UART serial interface. Access to the device memory by the BSL is protected by a user-defined password. The BSL requires a specific entry sequence on the $\overline{\text{RSTDVCC}}$ /SBWTDIO and TEST/SBWTK pins. 表 6-3 lists the required pins and their functions. For details on interfacing to development tools and device programmers, see the [MSP430 Hardware Tools User's Guide](#). For a complete description of the features of the BSL and its implementation, see the [MSP430 Flash Device Bootloader \(BSL\) User's Guide](#).

注

Devices from TI come factory programmed with the timer based UART BSL only. If the USCI based BSL is preferred, it is also available, but must be programmed by the user.

表 6-3. BSL Pin Requirements and Functions

DEVICE SIGNAL	BSL FUNCTION
$\overline{\text{RSTDVCC}}$ /SBWTDIO	External reset
TEST/SBWTK	Enable BSL
P1.1	Data transmit
P1.2	Data receive
DVCC, AVCC	Device power supply
DVSS	Ground supply

6.6 JTAG Operation

6.6.1 JTAG Standard Interface

The MSP430 family supports the standard JTAG interface which requires four signals for sending and receiving data. The JTAG signals are shared with general-purpose I/O. The TEST/SBWTK pin is used to enable the JTAG signals. In addition to these signals, the SBWTDIO is required to interface with MSP430 development tools and device programmers. 表 6-4 lists the JTAG pin requirements. For details on interfacing to development tools and device programmers, see the [MSP430 Hardware Tools User's Guide](#). For a complete description of the features of the JTAG interface and its implementation, see [MSP430 Programming With the JTAG Interface](#).

表 6-4. JTAG Pin Requirements and Functions

DEVICE SIGNAL	DIRECTION	FUNCTION
PJ.3/TCK	IN	JTAG clock input
PJ.2/TMS	IN	JTAG state control
PJ.1/TDI/TCLK	IN	JTAG data input, TCLK input
PJ.0/TDO	OUT	JTAG data output
TEST/SBWTK	IN	Enable JTAG pins
$\overline{\text{RSTDVCC}}$ /SBWTDIO	IN	External reset
DVCC, AVCC		Device power supply
DVSS		Ground supply

6.6.2 Spy-Bi-Wire Interface

In addition to the standard JTAG interface, the MSP430 family supports the two-wire Spy-Bi-Wire interface. Spy-Bi-Wire can be used to interface with MSP430 development tools and device programmers. 表 6-5 lists the Spy-Bi-Wire interface pin requirements. For details on interfacing to development tools and device programmers, see the [MSP430 Hardware Tools User's Guide](#). For a complete description of the features of the JTAG interface and its implementation, see [MSP430 Programming With the JTAG Interface](#).

表 6-5. Spy-Bi-Wire Pin Requirements and Functions

DEVICE SIGNAL	DIRECTION	FUNCTION
TEST/SBWTCK	IN	Spy-Bi-Wire clock input
SBWTDIO	IN, OUT	Spy-Bi-Wire data input/output
DVCC, AVCC		Device power supply
DVSS		Ground supply

6.7 Flash Memory ([Link to User's Guide](#))

The flash memory can be programmed using the JTAG port, Spy-Bi-Wire (SBW), the BSL, or in-system by the CPU. The CPU can perform single-byte, single-word, and long-word writes to the flash memory. Features of the flash memory include:

- Flash memory has n segments of main memory and four segments of information memory (A to D) of 128 bytes each. Each segment in main memory is 512 bytes in size.
- Segments 0 to n may be erased in one step, or each segment may be individually erased.
- Segments A to D can be erased individually. Segments A to D are also called *information memory*.
- Segment A can be locked separately.

6.8 RAM ([Link to User's Guide](#))

The RAM is made up of n sectors. Each sector can be completely powered down to save leakage; however, all data is lost. Features of the RAM include:

- RAM memory has n sectors. The size of a sector can be found in [节 6.4](#).
- Each sector 0 to n can be complete disabled; however, data retention is lost.
- Each sector 0 to n automatically enters low-power retention mode when possible.

6.9 Peripherals

Peripherals are connected to the CPU through data, address, and control buses. Peripherals can be managed using all instructions. For complete module descriptions, see the [MSP430F5xx and MSP430F6xx Family User's Guide](#).

6.9.1 Digital I/O ([Link to User's Guide](#))

- All individual I/O bits are independently programmable.
- Any combination of input, output, and interrupt conditions is possible.
- Pullup or pulldown on all ports is programmable.
- Drive strength on all ports is programmable.
- All bits of ports P1 and P2 support edge-selectable interrupt and LPM4.5 wake-up input.
- All instructions support read and write access to port-control registers.
- Ports can be accessed byte-wise or word-wise in pairs.

6.9.2 Port Mapping Controller ([Link to User's Guide](#))

The port mapping controller allows the flexible and reconfigurable mapping of digital functions to port P4 (see [表 6-6](#)).

表 6-6. Port Mapping Mnemonics and Functions

VALUE	PxMAPy MNEMONIC	INPUT PIN FUNCTION	OUTPUT PIN FUNCTION
0	PM_NONE	None	DVSS
1	PM_CBOUT0	–	COMP_B output
	PM_TB0CLK	TB0 clock input	–
2	PM_ADC10CLK	–	ADC10CLK
	PM_DMAE0	DMAE0 input	–
3	PM_SVMOUT	–	SVM output
	PM_TB0OUTH	TB0 high impedance input TB0OUTH	–
4	PM_TB0CCR0A	TB0 CCR0 capture input CCI0A	TB0 CCR0 compare output Out0
5	PM_TB0CCR1A	TB0 CCR1 capture input CCI1A	TB0 CCR1 compare output Out1
6	PM_TB0CCR2A	TB0 CCR2 capture input CCI2A	TB0 CCR2 compare output Out2
7	PM_TB0CCR3A	TB0 CCR3 capture input CCI3A	TB0 CCR3 compare output Out3
8	PM_TB0CCR4A	TB0 CCR4 capture input CCI4A	TB0 CCR4 compare output Out4
9	PM_TB0CCR5A	TB0 CCR5 capture input CCI5A	TB0 CCR5 compare output Out5
10	PM_TB0CCR6A	TB0 CCR6 capture input CCI6A	TB0 CCR6 compare output Out6
11	PM_UCA1RXD	USCI_A1 UART RXD (Direction controlled by USCI – input)	
	PM_UCA1SOMI	USCI_A1 SPI slave out master in (direction controlled by USCI)	
12	PM_UCA1TXD	USCI_A1 UART TXD (Direction controlled by USCI – output)	
	PM_UCA1SIMO	USCI_A1 SPI slave in master out (direction controlled by USCI)	
13	PM_UCA1CLK	USCI_A1 clock input/output (direction controlled by USCI)	
	PM_UCB1STE	USCI_B1 SPI slave transmit enable (direction controlled by USCI)	
14	PM_UCB1SOMI	USCI_B1 SPI slave out master in (direction controlled by USCI)	
	PM_UCB1SCL	USCI_B1 I ² C clock (open drain and direction controlled by USCI)	
15	PM_UCB1SIMO	USCI_B1 SPI slave in master out (direction controlled by USCI)	
	PM_UCB1SDA	USCI_B1 I ² C data (open drain and direction controlled by USCI)	
16	PM_UCB1CLK	USCI_B1 clock input/output (direction controlled by USCI)	
	PM_UCA1STE	USCI_A1 SPI slave transmit enable (direction controlled by USCI)	
17	PM_CBOUT1	None	COMP_B output
18	PM_MCLK	None	MCLK
19	PM_RTCCLK	None	RTCCLK output
20	PM_UCA0RXD	USCI_A0 UART RXD (Direction controlled by USCI – input)	
	PM_UCA0SOMI	USCI_A0 SPI slave out master in (direction controlled by USCI)	
21	PM_UCA0TXD	USCI_A0 UART TXD (Direction controlled by USCI – output)	
	PM_UCA0SIMO	USCI_A0 SPI slave in master out (direction controlled by USCI)	
22	PM_UCA0CLK	USCI_A0 clock input/output (direction controlled by USCI)	
	PM_UCB0STE	USCI_B0 SPI slave transmit enable (direction controlled by USCI)	
23	PM_UCB0SOMI	USCI_B0 SPI slave out master in (direction controlled by USCI)	
	PM_UCB0SCL	USCI_B0 I ² C clock (open drain and direction controlled by USCI)	
24	PM_UCB0SIMO	USCI_B0 SPI slave in master out (direction controlled by USCI)	
	PM_UCB0SDA	USCI_B0 I ² C data (open drain and direction controlled by USCI)	
25	PM_UCB0CLK	USCI_B0 clock input/output (direction controlled by USCI)	
	PM_UCA0STE	USCI_A0 SPI slave transmit enable (direction controlled by USCI)	
26–30	Reserved	None	DVSS

表 6-6. Port Mapping Mnemonics and Functions (continued)

VALUE	PxMAPy MNEMONIC	INPUT PIN FUNCTION	OUTPUT PIN FUNCTION
31 (0FFh) ⁽¹⁾	PM_ANALOG	Disables the output driver and the input Schmitt-trigger to prevent parasitic cross currents when applying analog signals.	

(1) The value of the PM_ANALOG mnemonic is set to 0FFh. The port mapping registers are only 5 bits wide, and the upper bits are ignored, which results in a read value of 31.

表 6-7 lists the default settings for all pins that support port mapping.

表 6-7. Default Mapping

PIN	PxMAPy MNEMONIC	INPUT PIN FUNCTION	OUTPUT PIN FUNCTION
P4.0/P4MAP0	PM_UCB1STE/PM_UCA1CLK	USCI_B1 SPI slave transmit enable (direction controlled by USCI) USCI_A1 clock input/output (direction controlled by USCI)	
P4.1/P4MAP1	PM_UCB1SIMO/PM_UCB1SDA	USCI_B1 SPI slave in master out (direction controlled by USCI) USCI_B1 I ² C data (open drain and direction controlled by USCI)	
P4.2/P4MAP2	PM_UCB1SOMI/PM_UCB1SCL	USCI_B1 SPI slave out master in (direction controlled by USCI) USCI_B1 I ² C clock (open drain and direction controlled by USCI)	
P4.3/P4MAP3	PM_UCB1CLK/PM_UCA1STE	USCI_A1 SPI slave transmit enable (direction controlled by USCI) USCI_B1 clock input/output (direction controlled by USCI)	
P4.4/P4MAP4	PM_UCA1TXD/PM_UCA1SIMO	USCI_A1 UART TXD (Direction controlled by USCI – output) USCI_A1 SPI slave in master out (direction controlled by USCI)	
P4.5/P4MAP5	PM_UCA1RXD/PM_UCA1SOMI	USCI_A1 UART RXD (Direction controlled by USCI – input) USCI_A1 SPI slave out master in (direction controlled by USCI)	
P4.6/P4MAP6	PM_NONE	None	DVSS
P4.7/P4MAP7 ⁽¹⁾	PM_NONE	None	DVSS

(1) Not available on all devices

6.9.3 Oscillator and System Clock ([Link to User's Guide](#))

The clock system in the MSP430F524x and MSP430F523x family of devices is supported by the Unified Clock System (UCS) module that includes support for a 32-kHz watch crystal oscillator (XT1 LF mode only; XT1 HF mode is not supported), an internal very low-power low-frequency oscillator (VLO), an internal trimmed low-frequency oscillator (REFO), an integrated internal digitally controlled oscillator (DCO), and a high-frequency crystal oscillator (XT2). The UCS module is designed to meet the requirements of both low system cost and low power consumption. The UCS module features digital frequency-locked loop (FLL) hardware that, in conjunction with a digital modulator, stabilizes the DCO frequency to a programmable multiple of the selected FLL reference frequency. The internal DCO provides a fast turnon clock source and stabilizes in 3.5 μ s (typical). The UCS module provides the following clock signals:

- Auxiliary clock (ACLK), sourced from a 32-kHz watch crystal (XT1), a high-frequency crystal (XT2), the internal low-frequency oscillator (VLO), the trimmed low-frequency oscillator (REFO), or the internal DCO.
- Main clock (MCLK), the system clock used by the CPU. MCLK can be sourced by same sources made available to ACLK.
- Sub-Main clock (SMCLK), the subsystem clock used by the peripheral modules. SMCLK can be sourced by same sources made available to ACLK.
- ACLK/n, the buffered output of ACLK, ACLK/2, ACLK/4, ACLK/8, ACLK/16, ACLK/32.

6.9.4 Power-Management Module (PMM) ([Link to User's Guide](#))

The PMM includes an integrated voltage regulator that supplies the core voltage to the device and contains programmable output levels to provide for power optimization. The PMM also includes supply voltage supervisor (SVS) and supply voltage monitoring (SVM) circuitry, as well as brownout protection. The brownout circuit is implemented to provide the proper internal reset signal to the device during power-on and power-off. The SVS and SVM circuitry detects if the supply voltage drops below a user-selectable level and supports both supply voltage supervision (the device is automatically reset) and supply voltage monitoring (SVM) (the device is not automatically reset). SVS and SVM circuitry is available on the primary supply and core supply.

6.9.5 Hardware Multiplier (MPY) ([Link to User's Guide](#))

The multiplication operation is supported by a dedicated peripheral module. The module performs operations with 32-, 24-, 16-, and 8-bit operands. The module supports signed and unsigned multiplication as well as signed and unsigned multiply-and-accumulate operations.

6.9.6 Real-Time Clock (RTC_A) ([Link to User's Guide](#))

The RTC_A module can be used as a general-purpose 32-bit counter (counter mode) or as an integrated real-time clock (RTC) (calendar mode). In counter mode, the RTC_A also includes two independent 8-bit timers that can be cascaded to form a 16-bit timer/counter. Both timers can be read and written by software. Calendar mode integrates an internal calendar which compensates for months with less than 31 days and includes leap year correction. The RTC_A also supports flexible alarm functions and offset-calibration hardware.

6.9.7 Watchdog Timer (WDT_A) ([Link to User's Guide](#))

The primary function of the WDT_A module is to perform a controlled system restart after a software problem occurs. If the selected time interval expires, a system reset is generated. If the watchdog function is not needed in an application, the module can be configured as an interval timer and can generate interrupts at selected time intervals.

6.9.8 System (SYS) Module [\(Link to User's Guide\)](#)

The SYS module handles many of the system functions within the device. These include power-on reset (POR) and power-up clear (PUC) handling, NMI source selection and management, reset interrupt vector generators, bootloader entry mechanisms, and configuration management (device descriptors). It also includes a data exchange mechanism through JTAG called a JTAG mailbox that can be used in the application. 表 6-8 lists the SYS module interrupt vector registers.

表 6-8. System Module Interrupt Vector Registers

INTERRUPT VECTOR REGISTER	ADDRESS	INTERRUPT EVENT	VALUE	PRIORITY
SYSRSTIV, System Reset	019Eh	No interrupt pending	00h	
		Brownout (BOR)	02h	Highest
		$\overline{\text{RST}}$ /NMI (BOR)	04h	
		PMMSWBOR (BOR)	06h	
		Wakeup from LPMx.5	08h	
		Security violation (BOR)	0Ah	
		SVSL (POR)	0Ch	
		SVSH (POR)	0Eh	
		SVML_OVP (POR)	10h	
		SVMH_OVP (POR)	12h	
		PMMSWPOR (POR)	14h	
		WDT time-out (PUC)	16h	
		WDT password violation (PUC)	18h	
		KEYV flash password violation (PUC)	1Ah	
		Reserved	1Ch	
		Peripheral area fetch (PUC)	1Eh	
		PMM password violation (PUC)	20h	
		Reserved	22h to 3Eh	Lowest
SYSSNIV, System NMI	019Ch	No interrupt pending	00h	
		SVMLIFG	02h	Highest
		SVMHIFG	04h	
		SVSMLDLYIFG	06h	
		SVSMHDLYIFG	08h	
		VMAIFG	0Ah	
		JMBINIFG	0Ch	
		JMBOUTIFG	0Eh	
		SVMLVLRIFG	10h	
		SVMHVLRIFG	12h	
		Reserved	14h to 1Eh	Lowest
		Reserved	14h to 1Eh	Lowest
SYSUNIV, User NMI	019Ah	No interrupt pending	00h	
		NMIIFG	02h	Highest
		OFIFG	04h	
		ACCVIFG	06h	
		Reserved	08h	
		Reserved	0Ah to 1Eh	Lowest

6.9.9 DMA Controller ([Link to User's Guide](#))

The DMA controller allows movement of data from one memory address to another without CPU intervention. For example, the DMA controller can move data from the ADC10_A conversion memory to RAM. Using the DMA controller can increase the throughput of peripheral modules. The DMA controller reduces system power consumption by allowing the CPU to remain in sleep mode, without having to awaken to move data to or from a peripheral. 表 6-9 lists the sources that can trigger the DMA.

表 6-9. DMA Trigger Assignments⁽¹⁾

TRIGGER	CHANNEL		
	0	1	2
0	DMAREQ	DMAREQ	DMAREQ
1	TA0CCR0 CCIFG	TA0CCR0 CCIFG	TA0CCR0 CCIFG
2	TA0CCR2 CCIFG	TA0CCR2 CCIFG	TA0CCR2 CCIFG
3	TA1CCR0 CCIFG	TA1CCR0 CCIFG	TA1CCR0 CCIFG
4	TA1CCR2 CCIFG	TA1CCR2 CCIFG	TA1CCR2 CCIFG
5	TA2CCR0 CCIFG	TA2CCR0 CCIFG	TA2CCR0 CCIFG
6	TA2CCR2 CCIFG	TA2CCR2 CCIFG	TA2CCR2 CCIFG
7	TB0CCR0 CCIFG	TB0CCR0 CCIFG	TB0CCR0 CCIFG
8	TB0CCR2 CCIFG	TB0CCR2 CCIFG	TB0CCR2 CCIFG
9	Reserved	Reserved	Reserved
10	Reserved	Reserved	Reserved
11	Reserved	Reserved	Reserved
12	Reserved	Reserved	Reserved
13	Reserved	Reserved	Reserved
14	Reserved	Reserved	Reserved
15	Reserved	Reserved	Reserved
16	UCA0RXIFG	UCA0RXIFG	UCA0RXIFG
17	UCA0TXIFG	UCA0TXIFG	UCA0TXIFG
18	UCB0RXIFG	UCB0RXIFG	UCB0RXIFG
19	UCB0TXIFG	UCB0TXIFG	UCB0TXIFG
20	UCA1RXIFG	UCA1RXIFG	UCA1RXIFG
21	UCA1TXIFG	UCA1TXIFG	UCA1TXIFG
22	UCB1RXIFG	UCB1RXIFG	UCB1RXIFG
23	UCB1TXIFG	UCB1TXIFG	UCB1TXIFG
24	ADC10IFG0 ⁽²⁾	ADC10IFG0 ⁽²⁾	ADC10IFG0 ⁽²⁾
25	Reserved	Reserved	Reserved
26	Reserved	Reserved	Reserved
27	Reserved	Reserved	Reserved
28	Reserved	Reserved	Reserved
29	MPY ready	MPY ready	MPY ready
30	DMA2IFG	DMA0IFG	DMA1IFG
31	DMAE0	DMAE0	DMAE0

(1) If a reserved trigger source is selected, no trigger is generated.

(2) Only on devices with ADC. Reserved on devices without ADC.

6.9.10 Universal Serial Communication Interface (USCI) (Links to User's Guide: [UART Mode](#), [SPI Mode](#), [I²C Mode](#))

The USCI modules are used for serial data communication. The USCI module supports synchronous communication protocols such as SPI (3- or 4-pin) and I²C, and asynchronous communication protocols such as UART, enhanced UART with automatic baud-rate detection, and IrDA. Each USCI module contains two portions, A and B.

The USCI_An module provides support for SPI (3- or 4-pin), UART, enhanced UART, or IrDA.

The USCI_Bn module provides support for SPI (3- or 4-pin) or I²C.

The MSP430F524x and MSP430F523x series include two complete USCI modules (n = 0, 1).

6.9.11 TA0 (Link to User's Guide)

TA0 is a 16-bit timer/counter (Timer_A type) with five capture/compare registers. TA0 can support multiple captures and compares, PWM outputs, and interval timing (see [表 6-10](#)). TA0 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

表 6-10. TA0 Signal Connections

INPUT PIN NUMBER		DEVICE INPUT SIGNAL	MODULE INPUT SIGNAL	MODULE BLOCK	MODULE OUTPUT SIGNAL	DEVICE OUTPUT SIGNAL	OUTPUT PIN NUMBER	
RGC, ZQE	RGZ						RGC, ZQE	RGZ
18, H2-P1.0	13-P1.0	TA0CLK	TACLK	Timer	NA	NA		
		ACLK (internal)	ACLK					
		SMCLK (internal)	SMCLK					
18, H2-P1.0	13-P1.0	TA0CLK	$\overline{\text{TACLK}}$	CCR0	TA0	TA0.0	19, H3-P1.1	14-P1.1
19, H3-P1.1	14-P1.1	TA0.0	CCI0A					
		DV _{SS}	CCI0B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}	CCR1	TA1	TA0.1	20, J3-P1.2	15-P1.2
20, J3-P1.2	15-P1.2	TA0.1	CCI1A					
		CBOUT (internal)	CCI1B				ADC10 (internal) ADC10SHSx = {1}	ADC10 (internal) ADC10SHSx = {1}
		DV _{SS}	GND					
		DV _{CC}	V _{CC}	CCR2	TA2	TA0.2	21, G4-P1.3	16-P1.3
21, G4-P1.3	16-P1.3	TA0.2	CCI2A					
		ACLK (internal)	CCI2B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}	CCR3	TA3	TA0.3	22, H4-P1.4	17-P1.4
22, H4-P1.4	17-P1.4	TA0.3	CCI3A					
		DV _{SS}	CCI3B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}	CCR4	TA4	TA0.4	23, J4-P1.5	18-P1.5
23, J4-P1.5	18-P1.5	TA0.4	CCI4A					
		DV _{SS}	CCI4B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}					

6.9.12 TA1 [\(Link to User's Guide\)](#)

TA1 is a 16-bit timer/counter (Timer_A type) with three capture/compare registers. TA1 can support multiple captures and compares, PWM outputs, and interval timing (see [表 6-11](#)). TA1 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

表 6-11. TA1 Signal Connections

INPUT PIN NUMBER		DEVICE INPUT SIGNAL	MODULE INPUT SIGNAL	MODULE BLOCK	MODULE OUTPUT SIGNAL	DEVICE OUTPUT SIGNAL	OUTPUT PIN NUMBER	
RGC, ZQE	RGZ						RGC, ZQE	RGZ
24, G5-P1.6	19-P1.6	TA1CLK	TACLK	Timer	NA	NA		
		ACLK (internal)	ACLK					
		SMCLK (internal)	SMCLK					
24, G5-P1.6	19-P1.6	TA1CLK	$\overline{\text{TACLK}}$	CCR0	TA0	TA1.0	25, H5-P1.7	20-P1.7
25, H5-P1.7	20-P1.7	TA1.0	CCI0A					
		DV _{SS}	CCI0B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}	CCR1	TA1	TA1.1	26, J5-P2.0	
26, J5-P2.0		TA1.1	CCI1A					
		CBOUT (internal)	CCI1B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}	CCR2	TA2	TA1.2	27, G6-P2.1	
27, G6-P2.1		TA1.2	CCI2A					
		ACLK (internal)	CCI2B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}					

6.9.13 TA2 (Link to User's Guide)

TA2 is a 16-bit timer/counter (Timer_A type) with three capture/compare registers. TA2 can support multiple captures and compares, PWM outputs, and interval timing (see 表 6-12). TA2 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

表 6-12. TA2 Signal Connections

INPUT PIN NUMBER		DEVICE INPUT SIGNAL	MODULE INPUT SIGNAL	MODULE BLOCK	MODULE OUTPUT SIGNAL	DEVICE OUTPUT SIGNAL	OUTPUT PIN NUMBER	
RGC, ZQE	RGZ						RGC, ZQE	RGZ
28, J6-P2.2		TA2CLK	TACLK	Timer	NA	NA		
		ACLK (internal)	ACLK					
		SMCLK (internal)	SMCLK					
28, J6-P2.2		TA2CLK	$\overline{\text{TACLK}}$	CCR0	TA0	TA2.0	29, H6-P2.3	
29, H6-P2.3		TA2.0	CCI0A					
		DV _{SS}	CCI0B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}					
30, J7-P2.4		TA2.1	CCI1A	CCR1	TA1	TA2.1	30, J7-P2.4	
		CBOUT (internal)	CCI1B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}					
31, J8-P2.5		TA2.2	CCI2A	CCR2	TA2	TA2.2	31, J8-P2.5	
		ACLK (internal)	CCI2B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}					

6.9.14 TB0 (Link to User's Guide)

TB0 is a 16-bit timer/counter (Timer_B type) with seven capture/compare registers. TB0 can support multiple captures and compares, PWM outputs, and interval timing (see 表 6-13). TB0 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

表 6-13. TB0 Signal Connections

INPUT PIN NUMBER		DEVICE INPUT SIGNAL	MODULE INPUT SIGNAL	MODULE BLOCK	MODULE OUTPUT SIGNAL	DEVICE OUTPUT SIGNAL	OUTPUT PIN NUMBER	
RGC, ZQE	RGZ						RGC, ZQE	RGZ
(1)	(1)	TB0CLK	TBCLK	Timer	NA	NA		
		ACLK (internal)	ACLK					
		SMCLK (internal)	SMCLK					
(1)	(1)	TB0CLK	$\overline{\text{TBCLK}}$	CCR0	TB0	TB0.0		
49, B8(9)- P7.0 ⁽¹⁾	(1)	TB0.0	CCI0A				49, B8(9)-P7.0 ⁽¹⁾	(1)
49, B8(9)- P7.0 ⁽¹⁾	(1)	TB0.0	CCI0B				ADC10 (internal) ADC10SHSx = {2}	ADC10 (internal) ADC10SHSx = {2}
		DV _{SS}	GND					
		DV _{CC}	V _{CC}	CCR1	TB1	TB0.1		
50, A9- P7.1 ⁽¹⁾	(1)	TB0.1	CCI1A				50, A9-P7.1 ⁽¹⁾	(1)
		CBOUT (internal)	CCI1B				ADC10 (internal) ADC10SHSx = {3}	ADC10 (internal) ADC10SHSx = {3}
		DV _{SS}	GND					
		DV _{CC}	V _{CC}	CCR2	TB2	TB0.2		
51, B7- P7.2 ⁽¹⁾	(1)	TB0.2	CCI2A				51, B7-P7.2 ⁽¹⁾	(1)
51, B7- P7.2 ⁽¹⁾	(1)	TB0.2	CCI2B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}	CCR3	TB3	TB0.3		
52, A8- P7.3 ⁽¹⁾	(1)	TB0.3	CCI3A				52, A8-P7.3 ⁽¹⁾	(1)
52, A8- P7.3 ⁽¹⁾	(1)	TB0.3	CCI3B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}	CCR4	TB4	TB0.4		
53, A7- P7.4 ⁽¹⁾	(1)	TB0.4	CCI4A				53, A7-P7.4 ⁽¹⁾	(1)
53, A7- P7.4 ⁽¹⁾	(1)	TB0.4	CCI4B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}	CCR5	TB5	TB0.5		
54, A6- P7.5 ⁽¹⁾	(1)	TB0.5	CCI5A				54, A6-P7.5 ⁽¹⁾	(1)
54, A6- P7.5 ⁽¹⁾	(1)	TB0.5	CCI5B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}					

(1) Timer functions are available through the port mapping controller.

表 6-13. TB0 Signal Connections (continued)

INPUT PIN NUMBER		DEVICE INPUT SIGNAL	MODULE INPUT SIGNAL	MODULE BLOCK	MODULE OUTPUT SIGNAL	DEVICE OUTPUT SIGNAL	OUTPUT PIN NUMBER	
RGC, ZQE	RGZ						RGC, ZQE	RGZ
(1)	(1)	TB0.6	CCI6A	CCR6	TB6	TB0.6	(1)	(1)
		ACLK (internal)	CCI6B					
		DV _{SS}	GND					
		DV _{CC}	V _{CC}					

6.9.15 Comparator_B ([Link to User's Guide](#))

The primary function of the Comparator_B module is to support precision slope analog-to-digital conversions, battery voltage supervision, and monitoring of external analog signals.

6.9.16 ADC10_A ([Link to User's Guide](#))

The ADC10_A module supports fast 10-bit analog-to-digital conversions. The module implements a 10-bit SAR core, sample select control, reference generator, and a conversion result buffer. A window comparator with lower and upper limits allows CPU-independent result monitoring with three window comparator interrupt flags.

6.9.17 CRC16 ([Link to User's Guide](#))

The CRC16 module produces a signature based on a sequence of entered data values and can be used for data checking purposes. The CRC16 module signature is based on the CRC-CCITT standard.

6.9.18 Reference (REF) Module Voltage Reference ([Link to User's Guide](#))

The REF generates all of the critical reference voltages that can be used by the various analog peripherals in the device.

6.9.19 Embedded Emulation Module (EEM) (S Version) ([Link to User's Guide](#))

The EEM supports real-time in-system debugging. The S version of the EEM has the following features:

- Three hardware triggers or breakpoints on memory access
- One hardware trigger or breakpoint on CPU register write access
- Up to four hardware triggers can be combined to form complex triggers or breakpoints
- One cycle counter
- Clock control on module level

6.9.20 Peripheral File Map

表 6-14 lists the register base address and offset range for all peripherals.

表 6-14. Peripherals

MODULE NAME	BASE ADDRESS	OFFSET ADDRESS RANGE
Special Functions (see 表 6-15)	0100h	000h to 01Fh
PMM (see 表 6-16)	0120h	000h to 010h
Flash Control (see 表 6-17)	0140h	000h to 00Fh
CRC16 (see 表 6-18)	0150h	000h to 007h
RAM Control (see 表 6-19)	0158h	000h to 001h
Watchdog (see 表 6-20)	015Ch	000h to 001h
UCS (see 表 6-21)	0160h	000h to 01Fh
SYS (see 表 6-22)	0180h	000h to 01Fh
Shared Reference (see 表 6-23)	01B0h	000h to 001h
Port Mapping Control (see 表 6-24)	01C0h	000h to 002h
Port Mapping Port P4 (see 表 6-24)	01E0h	000h to 007h
Port P1, P2 (see 表 6-25)	0200h	000h to 01Fh
Port P3, P4 (see 表 6-26)	0220h	000h to 00Bh
Port P5, P6 (see 表 6-27)	0240h	000h to 00Bh
Port P7 (see 表 6-28)	0260h	000h to 00Bh
Port PJ (see 表 6-29)	0320h	000h to 01Fh
TA0 (see 表 6-30)	0340h	000h to 02Eh
TA1 (see 表 6-31)	0380h	000h to 02Eh
TB0 (see 表 6-32)	03C0h	000h to 02Eh
TA2 (see 表 6-33)	0400h	000h to 02Eh
Real-Time Clock (RTC_A) (see 表 6-34)	04A0h	000h to 01Bh
32-Bit Hardware Multiplier (see 表 6-35)	04C0h	000h to 02Fh
DMA General Control (see 表 6-36)	0500h	000h to 00Fh
DMA Channel 0 (see 表 6-36)	0510h	000h to 00Ah
DMA Channel 1 (see 表 6-36)	0520h	000h to 00Ah
DMA Channel 2 (see 表 6-36)	0530h	000h to 00Ah
USCI_A0 (see 表 6-37)	05C0h	000h to 01Fh
USCI_B0 (see 表 6-38)	05E0h	000h to 01Fh
USCI_A1 (see 表 6-39)	0600h	000h to 01Fh
USCI_B1 (see 表 6-40)	0620h	000h to 01Fh
ADC10_A (see 表 6-41)	0740h	000h to 01Fh
Comparator_B (see 表 6-42)	08C0h	000h to 00Fh

表 6-15. Special Function Registers (Base Address: 0100h)

REGISTER DESCRIPTION	REGISTER	OFFSET
SFR interrupt enable	SFRIE1	00h
SFR interrupt flag	SFRIFG1	02h
SFR reset pin control	SFRRPCR	04h

表 6-16. PMM Registers (Base Address: 0120h)

REGISTER DESCRIPTION	REGISTER	OFFSET
PMM control 0	PMMCTL0	00h
PMM control 1	PMMCTL1	02h
SVS high side control	SVSMHCTL	04h
SVS low side control	SVSMLCTL	06h
PMM interrupt flags	PMMIFG	0Ch
PMM interrupt enable	PMMIE	0Eh
PMM power mode 5 control	PM5CTL0	10h

表 6-17. Flash Control Registers (Base Address: 0140h)

REGISTER DESCRIPTION	REGISTER	OFFSET
Flash control 1	FCTL1	00h
Flash control 3	FCTL3	04h
Flash control 4	FCTL4	06h

表 6-18. CRC16 Registers (Base Address: 0150h)

REGISTER DESCRIPTION	REGISTER	OFFSET
CRC data input	CRC16DI	00h
CRC data input reverse byte	CRCDIRB	02h
CRC initialization and result	CRCINIRES	04h
CRC result reverse byte	CRCRESR	06h

表 6-19. RAM Control Registers (Base Address: 0158h)

REGISTER DESCRIPTION	REGISTER	OFFSET
RAM control 0	RCCTL0	00h

表 6-20. Watchdog Registers (Base Address: 015Ch)

REGISTER DESCRIPTION	REGISTER	OFFSET
Watchdog timer control	WDTCTL	00h

表 6-21. UCS Registers (Base Address: 0160h)

REGISTER DESCRIPTION	REGISTER	OFFSET
UCS control 0	UCSCTL0	00h
UCS control 1	UCSCTL1	02h
UCS control 2	UCSCTL2	04h
UCS control 3	UCSCTL3	06h
UCS control 4	UCSCTL4	08h
UCS control 5	UCSCTL5	0Ah
UCS control 6	UCSCTL6	0Ch
UCS control 7	UCSCTL7	0Eh
UCS control 8	UCSCTL8	10h
UCS control 9	UCSCTL9	12h

表 6-22. SYS Registers (Base Address: 0180h)

REGISTER DESCRIPTION	REGISTER	OFFSET
System control	SYSCTL	00h
Bootloader configuration area	SYSBSLC	02h
JTAG mailbox control	SYSJMBC	06h
JTAG mailbox input 0	SYSJMBI0	08h
JTAG mailbox input 1	SYSJMBI1	0Ah
JTAG mailbox output 0	SYSJMBO0	0Ch
JTAG mailbox output 1	SYSJMBO1	0Eh
User NMI vector generator	SYSUNIV	1Ah
System NMI vector generator	SYSSNIV	1Ch
Reset vector generator	SYSRSTIV	1Eh

表 6-23. Shared Reference Registers (Base Address: 01B0h)

REGISTER DESCRIPTION	REGISTER	OFFSET
Shared reference control	REFCTL	00h

**表 6-24. Port Mapping Registers
(Base Address of Port Mapping Control: 01C0h, Port P4: 01E0h)**

REGISTER DESCRIPTION	REGISTER	OFFSET
Port mapping key/ID	PMAPKEYID	00h
Port mapping control	PMAPCTL	02h
Port P4.0 mapping	P4MAP0	00h
Port P4.1 mapping	P4MAP1	01h
Port P4.2 mapping	P4MAP2	02h
Port P4.3 mapping	P4MAP3	03h
Port P4.4 mapping	P4MAP4	04h
Port P4.5 mapping	P4MAP5	05h
Port P4.6 mapping	P4MAP6	06h
Port P4.7 mapping	P4MAP7	07h

表 6-25. Port P1, P2 Registers (Base Address: 0200h)

REGISTER DESCRIPTION	REGISTER	OFFSET
Port P1 input	P1IN	00h
Port P1 output	P1OUT	02h
Port P1 direction	P1DIR	04h
Port P1 resistor enable	P1REN	06h
Port P1 drive strength	P1DS	08h
Port P1 selection	P1SEL	0Ah
Port P1 interrupt vector word	P1IV	0Eh
Port P1 interrupt edge select	P1IES	18h
Port P1 interrupt enable	P1IE	1Ah
Port P1 interrupt flag	P1IFG	1Ch
Port P2 input	P2IN	01h
Port P2 output	P2OUT	03h
Port P2 direction	P2DIR	05h
Port P2 resistor enable	P2REN	07h
Port P2 drive strength	P2DS	09h
Port P2 selection	P2SEL	0Bh
Port P2 interrupt vector word	P2IV	1Eh
Port P2 interrupt edge select	P2IES	19h
Port P2 interrupt enable	P2IE	1Bh
Port P2 interrupt flag	P2IFG	1Dh

表 6-26. Port P3, P4 Registers (Base Address: 0220h)

REGISTER DESCRIPTION	REGISTER	OFFSET
Port P3 input	P3IN	00h
Port P3 output	P3OUT	02h
Port P3 direction	P3DIR	04h
Port P3 resistor enable	P3REN	06h
Port P3 drive strength	P3DS	08h
Port P3 selection	P3SEL	0Ah
Port P4 input	P4IN	01h
Port P4 output	P4OUT	03h
Port P4 direction	P4DIR	05h
Port P4 resistor enable	P4REN	07h
Port P4 drive strength	P4DS	09h
Port P4 selection	P4SEL	0Bh

表 6-27. Port P5, P6 Registers (Base Address: 0240h)

REGISTER DESCRIPTION	REGISTER	OFFSET
Port P5 input	P5IN	00h
Port P5 output	P5OUT	02h
Port P5 direction	P5DIR	04h
Port P5 resistor enable	P5REN	06h
Port P5 drive strength	P5DS	08h
Port P5 selection	P5SEL	0Ah
Port P6 input	P6IN	01h
Port P6 output	P6OUT	03h
Port P6 direction	P6DIR	05h
Port P6 resistor enable	P6REN	07h
Port P6 drive strength	P6DS	09h
Port P6 selection	P6SEL	0Bh

表 6-28. Port P7 Registers (Base Address: 0260h)

REGISTER DESCRIPTION	REGISTER	OFFSET
Port P7 input	P7IN	00h
Port P7 output	P7OUT	02h
Port P7 direction	P7DIR	04h
Port P7 resistor enable	P7REN	06h
Port P7 drive strength	P7DS	08h
Port P7 selection	P7SEL	0Ah

表 6-29. Port J Registers (Base Address: 0320h)

REGISTER DESCRIPTION	REGISTER	OFFSET
Port PJ input	PJIN	00h
Port PJ output	PJOUT	02h
Port PJ direction	PJDIR	04h
Port PJ resistor enable	PJREN	06h
Port PJ drive strength	PJDS	08h

表 6-30. TA0 Registers (Base Address: 0340h)

REGISTER DESCRIPTION	REGISTER	OFFSET
TA0 control	TA0CTL	00h
Capture/compare control 0	TA0CCTL0	02h
Capture/compare control 1	TA0CCTL1	04h
Capture/compare control 2	TA0CCTL2	06h
Capture/compare control 3	TA0CCTL3	08h
Capture/compare control 4	TA0CCTL4	0Ah
TA0 counter	TA0R	10h
Capture/compare 0	TA0CCR0	12h
Capture/compare 1	TA0CCR1	14h
Capture/compare 2	TA0CCR2	16h
Capture/compare 3	TA0CCR3	18h
Capture/compare 4	TA0CCR4	1Ah
TA0 expansion 0	TA0EX0	20h
TA0 interrupt vector	TA0IV	2Eh

表 6-31. TA1 Registers (Base Address: 0380h)

REGISTER DESCRIPTION	REGISTER	OFFSET
TA1 control	TA1CTL	00h
Capture/compare control 0	TA1CCTL0	02h
Capture/compare control 1	TA1CCTL1	04h
Capture/compare control 2	TA1CCTL2	06h
TA1 counter	TA1R	10h
Capture/compare 0	TA1CCR0	12h
Capture/compare 1	TA1CCR1	14h
Capture/compare 2	TA1CCR2	16h
TA1 expansion 0	TA1EX0	20h
TA1 interrupt vector	TA1IV	2Eh

表 6-32. TB0 Registers (Base Address: 03C0h)

REGISTER DESCRIPTION	REGISTER	OFFSET
TB0 control	TB0CTL	00h
Capture/compare control 0	TB0CCTL0	02h
Capture/compare control 1	TB0CCTL1	04h
Capture/compare control 2	TB0CCTL2	06h
Capture/compare control 3	TB0CCTL3	08h
Capture/compare control 4	TB0CCTL4	0Ah
Capture/compare control 5	TB0CCTL5	0Ch
Capture/compare control 6	TB0CCTL6	0Eh
TB0 counter	TB0R	10h
Capture/compare 0	TB0CCR0	12h
Capture/compare 1	TB0CCR1	14h
Capture/compare 2	TB0CCR2	16h
Capture/compare 3	TB0CCR3	18h
Capture/compare 4	TB0CCR4	1Ah
Capture/compare 5	TB0CCR5	1Ch
Capture/compare 6	TB0CCR6	1Eh
TB0 expansion 0	TB0EX0	20h
TB0 interrupt vector	TB0IV	2Eh

表 6-33. TA2 Registers (Base Address: 0400h)

REGISTER DESCRIPTION	REGISTER	OFFSET
TA2 control	TA2CTL	00h
Capture/compare control 0	TA2CCTL0	02h
Capture/compare control 1	TA2CCTL1	04h
Capture/compare control 2	TA2CCTL2	06h
TA2 counter	TA2R	10h
Capture/compare 0	TA2CCR0	12h
Capture/compare 1	TA2CCR1	14h
Capture/compare 2	TA2CCR2	16h
TA2 expansion 0	TA2EX0	20h
TA2 interrupt vector	TA2IV	2Eh

表 6-34. Real-Time Clock Registers (Base Address: 04A0h)

REGISTER DESCRIPTION	REGISTER	OFFSET
RTC control 0	RTCCTL0	00h
RTC control 1	RTCCTL1	01h
RTC control 2	RTCCTL2	02h
RTC control 3	RTCCTL3	03h
RTC prescaler 0 control	RTCPS0CTL	08h
RTC prescaler 1 control	RTCPS1CTL	0Ah
RTC prescaler 0	RTCPS0	0Ch
RTC prescaler 1	RTCPS1	0Dh
RTC interrupt vector word	RTCIV	0Eh
RTC seconds/counter 1	RTCSEC/RTCNT1	10h
RTC minutes/counter 2	RTCMIN/RTCNT2	11h
RTC hours/counter 3	RTCHOUR/RTCNT3	12h
RTC day of week/counter 4	RTCDOW/RTCNT4	13h
RTC days	RTCDAY	14h
RTC month	RTCMON	15h
RTC year low	RTCYEARL	16h
RTC year high	RTCYEARH	17h
RTC alarm minutes	RTCAMIN	18h
RTC alarm hours	RTCAHOUR	19h
RTC alarm day of week	RTCADOW	1Ah
RTC alarm days	RTCADAY	1Bh

表 6-35. 32-Bit Hardware Multiplier Registers (Base Address: 04C0h)

REGISTER DESCRIPTION	REGISTER	OFFSET
16-bit operand 1 – multiply	MPY	00h
16-bit operand 1 – signed multiply	MPYS	02h
16-bit operand 1 – multiply accumulate	MAC	04h
16-bit operand 1 – signed multiply accumulate	MACS	06h
16-bit operand 2	OP2	08h
16 × 16 result low word	RESLO	0Ah
16 × 16 result high word	RESHI	0Ch
16 × 16 sum extension	SUMEXT	0Eh
32-bit operand 1 – multiply low word	MPY32L	10h
32-bit operand 1 – multiply high word	MPY32H	12h
32-bit operand 1 – signed multiply low word	MPYS32L	14h
32-bit operand 1 – signed multiply high word	MPYS32H	16h
32-bit operand 1 – multiply accumulate low word	MAC32L	18h
32-bit operand 1 – multiply accumulate high word	MAC32H	1Ah
32-bit operand 1 – signed multiply accumulate low word	MACS32L	1Ch
32-bit operand 1 – signed multiply accumulate high word	MACS32H	1Eh
32-bit operand 2 – low word	OP2L	20h
32-bit operand 2 – high word	OP2H	22h
32 × 32 result 0 – least significant word	RES0	24h
32 × 32 result 1	RES1	26h
32 × 32 result 2	RES2	28h
32 × 32 result 3 – most significant word	RES3	2Ah
MPY32 control 0	MPY32CTL0	2Ch

**表 6-36. DMA Registers (Base Address DMA General Control: 0500h,
DMA Channel 0: 0510h, DMA Channel 1: 0520h, DMA Channel 2: 0530h)**

REGISTER DESCRIPTION	REGISTER	OFFSET
DMA channel 0 control	DMA0CTL	00h
DMA channel 0 source address low	DMA0SAL	02h
DMA channel 0 source address high	DMA0SAH	04h
DMA channel 0 destination address low	DMA0DAL	06h
DMA channel 0 destination address high	DMA0DAH	08h
DMA channel 0 transfer size	DMA0SZ	0Ah
DMA channel 1 control	DMA1CTL	00h
DMA channel 1 source address low	DMA1SAL	02h
DMA channel 1 source address high	DMA1SAH	04h
DMA channel 1 destination address low	DMA1DAL	06h
DMA channel 1 destination address high	DMA1DAH	08h
DMA channel 1 transfer size	DMA1SZ	0Ah
DMA channel 2 control	DMA2CTL	00h
DMA channel 2 source address low	DMA2SAL	02h
DMA channel 2 source address high	DMA2SAH	04h
DMA channel 2 destination address low	DMA2DAL	06h
DMA channel 2 destination address high	DMA2DAH	08h
DMA channel 2 transfer size	DMA2SZ	0Ah
DMA module control 0	DMACTL0	00h
DMA module control 1	DMACTL1	02h
DMA module control 2	DMACTL2	04h
DMA module control 3	DMACTL3	06h
DMA module control 4	DMACTL4	08h
DMA interrupt vector	DMAIV	0Eh

表 6-37. USCI_A0 Registers (Base Address: 05C0h)

REGISTER DESCRIPTION	REGISTER	OFFSET
USCI control 1	UCA0CTL1	00h
USCI control 0	UCA0CTL0	01h
USCI baud rate 0	UCA0BR0	06h
USCI baud rate 1	UCA0BR1	07h
USCI modulation control	UCA0MCTL	08h
USCI status	UCA0STAT	0Ah
USCI receive buffer	UCA0RXBUF	0Ch
USCI transmit buffer	UCA0TXBUF	0Eh
USCI LIN control	UCA0ABCTL	10h
USCI IrDA transmit control	UCA0IRTCTL	12h
USCI IrDA receive control	UCA0IRRCTL	13h
USCI interrupt enable	UCA0IE	1Ch
USCI interrupt flags	UCA0IFG	1Dh
USCI interrupt vector word	UCA0IV	1Eh

表 6-38. USCI_B0 Registers (Base Address: 05E0h)

REGISTER DESCRIPTION	REGISTER	OFFSET
USCI synchronous control 1	UCB0CTL1	00h
USCI synchronous control 0	UCB0CTL0	01h
USCI synchronous bit rate 0	UCB0BR0	06h
USCI synchronous bit rate 1	UCB0BR1	07h
USCI synchronous status	UCB0STAT	0Ah
USCI synchronous receive buffer	UCB0RXBUF	0Ch
USCI synchronous transmit buffer	UCB0TXBUF	0Eh
USCI I2C own address	UCB0I2COA	10h
USCI I2C slave address	UCB0I2CSA	12h
USCI interrupt enable	UCB0IE	1Ch
USCI interrupt flags	UCB0IFG	1Dh
USCI interrupt vector word	UCB0IV	1Eh

表 6-39. USCI_A1 Registers (Base Address: 0600h)

REGISTER DESCRIPTION	REGISTER	OFFSET
USCI control 1	UCA1CTL1	00h
USCI control 0	UCA1CTL0	01h
USCI baud rate 0	UCA1BR0	06h
USCI baud rate 1	UCA1BR1	07h
USCI modulation control	UCA1MCTL	08h
USCI status	UCA1STAT	0Ah
USCI receive buffer	UCA1RXBUF	0Ch
USCI transmit buffer	UCA1TXBUF	0Eh
USCI LIN control	UCA1ABCTL	10h
USCI IrDA transmit control	UCA1IRTCTL	12h
USCI IrDA receive control	UCA1IRRCTL	13h
USCI interrupt enable	UCA1IE	1Ch
USCI interrupt flags	UCA1IFG	1Dh
USCI interrupt vector word	UCA1IV	1Eh

表 6-40. USCI_B1 Registers (Base Address: 0620h)

REGISTER DESCRIPTION	REGISTER	OFFSET
USCI synchronous control 1	UCB1CTL1	00h
USCI synchronous control 0	UCB1CTL0	01h
USCI synchronous bit rate 0	UCB1BR0	06h
USCI synchronous bit rate 1	UCB1BR1	07h
USCI synchronous status	UCB1STAT	0Ah
USCI synchronous receive buffer	UCB1RXBUF	0Ch
USCI synchronous transmit buffer	UCB1TXBUF	0Eh
USCI I2C own address	UCB1I2COA	10h
USCI I2C slave address	UCB1I2CSA	12h
USCI interrupt enable	UCB1IE	1Ch
USCI interrupt flags	UCB1IFG	1Dh
USCI interrupt vector word	UCB1IV	1Eh

表 6-41. ADC10_A Registers (Base Address: 0740h)

REGISTER DESCRIPTION	REGISTER	OFFSET
ADC10_A control 0	ADC10CTL0	00h
ADC10_A control 1	ADC10CTL1	02h
ADC10_A control 2	ADC10CTL2	04h
ADC10_A window comparator low threshold	ADC10LO	06h
ADC10_A window comparator high threshold	ADC10HI	08h
ADC10_A memory control 0	ADC10MCTL0	0Ah
ADC10_A conversion memory	ADC10MEM0	12h
ADC10_A interrupt enable	ADC10IE	1Ah
ADC10_A interrupt flags	ADC10IGH	1Ch
ADC10_A interrupt vector word	ADC10IV	1Eh

表 6-42. Comparator_B Registers (Base Address: 08C0h)

REGISTER DESCRIPTION	REGISTER	OFFSET
Comp_B control 0	CBCTL0	00h
Comp_B control 1	CBCTL1	02h
Comp_B control 2	CBCTL2	04h
Comp_B control 3	CBCTL3	06h
Comp_B interrupt	CBINT	0Ch
Comp_B interrupt vector word	CBIV	0Eh

6.10 Input/Output Diagrams

6.10.1 Port P1 (P1.0 to P1.7) Input/Output With Schmitt Trigger

图 6-2 shows the port diagram. 表 6-43 summarizes the selection of the pin function.

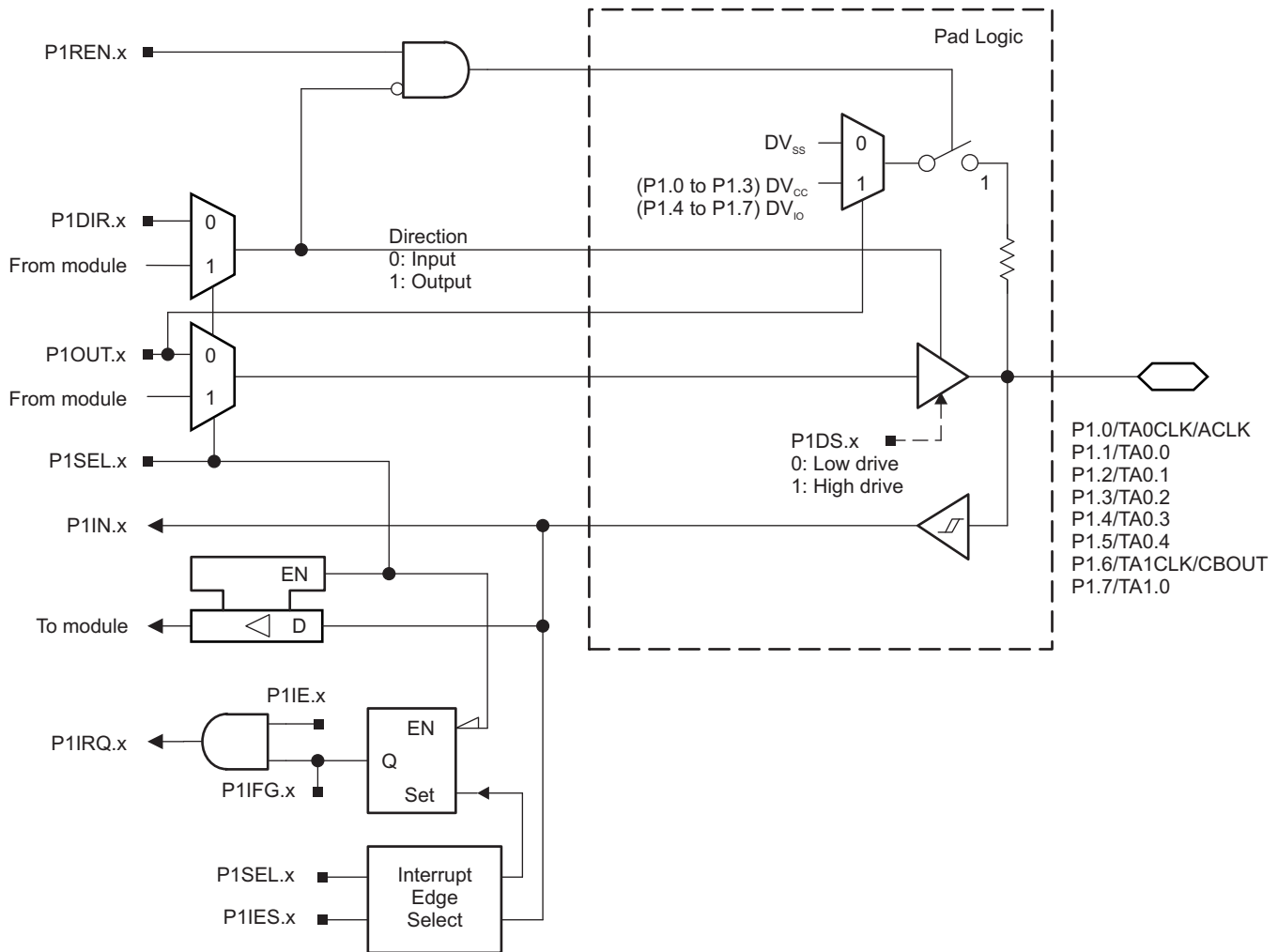


图 6-2. Port P1 (P1.0 to P1.7) Diagram

表 6-43. Port P1 (P1.0 to P1.7) Pin Functions

PIN NAME (P1.x)	x	FUNCTION	CONTROL BITS OR SIGNALS	
			P1DIR.x	P1SEL.x
P1.0/TA0CLK/ACLK	0	P1.0 (I/O)	I: 0; O: 1	0
		TA0CLK	0	1
		ACLK	1	1
P1.1/TA0.0	1	P1.1 (I/O)	I: 0; O: 1	0
		TA0.CCI0A	0	1
		TA0.0	1	1
P1.2/TA0.1	2	P1.2 (I/O)	I: 0; O: 1	0
		TA0.CCI1A	0	1
		TA0.1	1	1
P1.3/TA0.2	3	P1.3 (I/O)	I: 0; O: 1	0
		TA0.CCI2A	0	1
		TA0.2	1	1
P1.4/TA0.3	4	P1.4 (I/O)	I: 0; O: 1	0
		TA0.CCI3A	0	1
		TA0.3	1	1
P1.5/TA0.4	5	P1.5 (I/O)	I: 0; O: 1	0
		TA0.CCI4A	0	1
		TA0.4	1	1
P1.6/TA1CLK/CBOUT	6	P1.6 (I/O)	I: 0; O: 1	0
		TA1CLK	0	1
		CBOUT comparator B	1	1
P1.7/TA1.0	7	P1.7 (I/O)	I: 0; O: 1	0
		TA1.CCI0A	0	1
		TA1.0	1	1

6.10.2 Port P2 (P2.0 to P2.7) Input/Output With Schmitt Trigger

图 6-3 shows the port diagram. 表 6-44 summarizes the selection of the pin function.

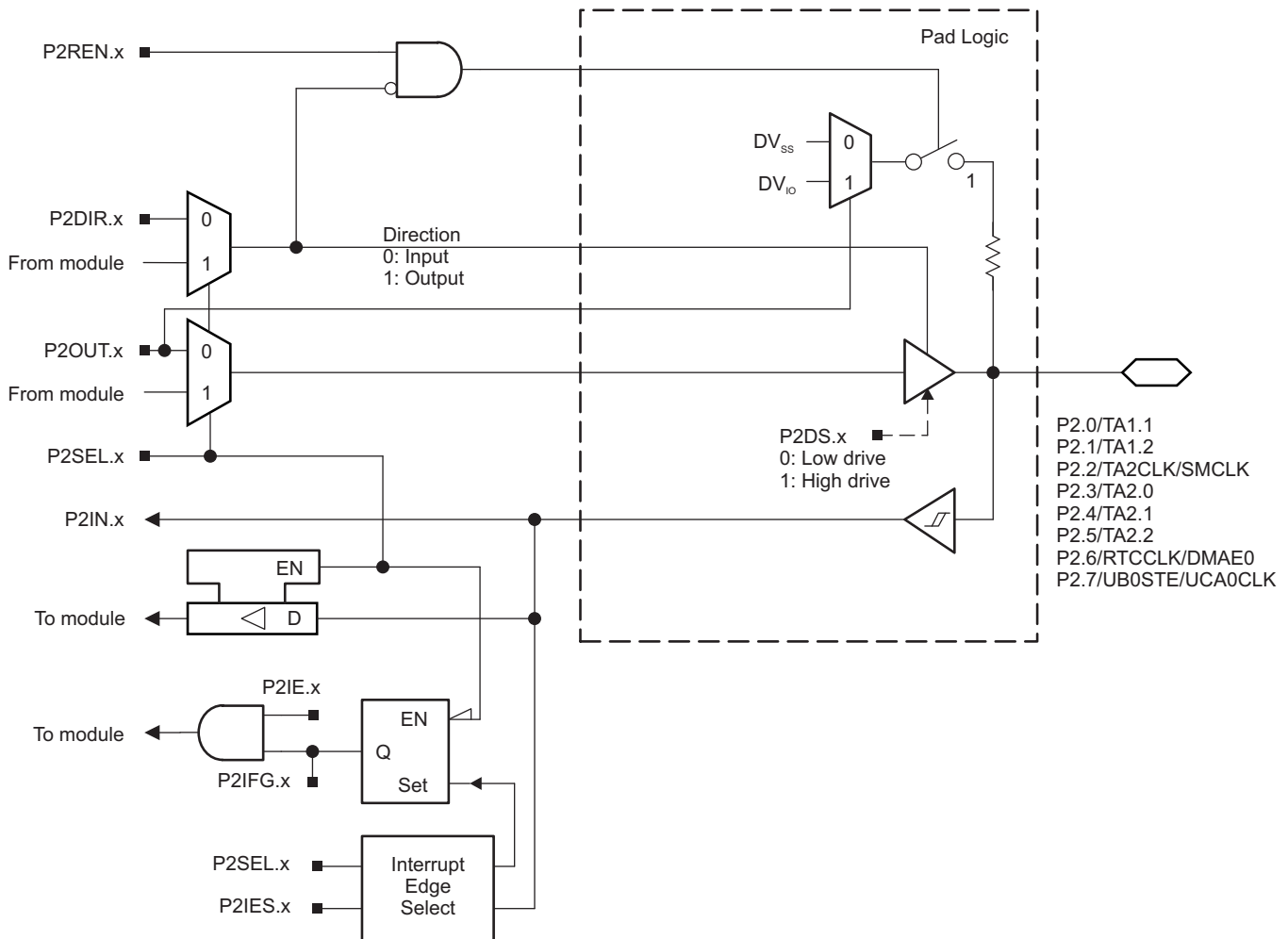


图 6-3. Port P2 (P2.0 to P2.7) Diagram

表 6-44. Port P2 (P2.0 to P2.7) Pin Functions

PIN NAME (P2.x)	x	FUNCTION	CONTROL BITS OR SIGNALS ⁽¹⁾	
			P2DIR.x	P2SEL.x
P2.0/TA1.1 ⁽²⁾	0	P2.0 (I/O)	I: 0; O: 1	0
		TA1.CCI1A	0	1
		TA1.1	1	1
P2.1/TA1.2 ⁽²⁾	1	P2.1 (I/O)	I: 0; O: 1	0
		TA1.CCI2A	0	1
		TA1.2	1	1
P2.2/TA2CLK/SMCLK ⁽²⁾	2	P2.2 (I/O)	I: 0; O: 1	0
		TA2CLK	0	1
		SMCLK	1	1
P2.3/TA2.0 ⁽²⁾	3	P2.3 (I/O)	I: 0; O: 1	0
		TA2.CCI0A	0	1
		TA2.0	1	1
P2.4/TA2.1 ⁽²⁾	4	P2.4 (I/O)	I: 0; O: 1	0
		TA2.CCI1A	0	1
		TA2.1	1	1
P2.5/TA2.2 ⁽²⁾	5	P2.5 (I/O)	I: 0; O: 1	0
		TA2.CCI2A	0	1
		TA2.2	1	1
P2.6/RTCCLK/DMAE0 ⁽²⁾	6	P2.6 (I/O)	I: 0; O: 1	0
		DMAE0	0	1
		RTCCLK	1	1
P2.7/UCB0STE/UCA0CLK	7	P2.7 (I/O)	I: 0; O: 1	0
		UCB0STE/UCA0CLK ^{(3) (4)}	X	1

(1) X = Don't care

(2) Not available on RGZ packages.

(3) The pin direction is controlled by the USCI module.

(4) UCA0CLK function takes precedence over UCB0STE function. If the pin is required as UCA0CLK input or output, USCI B0 is forced to 3-wire SPI mode if 4-wire SPI mode is selected.

6.10.3 Port P3 (P3.0 to P3.4) Input/Output With Schmitt Trigger

图 6-4 shows the port diagram. 表 6-45 summarizes the selection of the pin function.

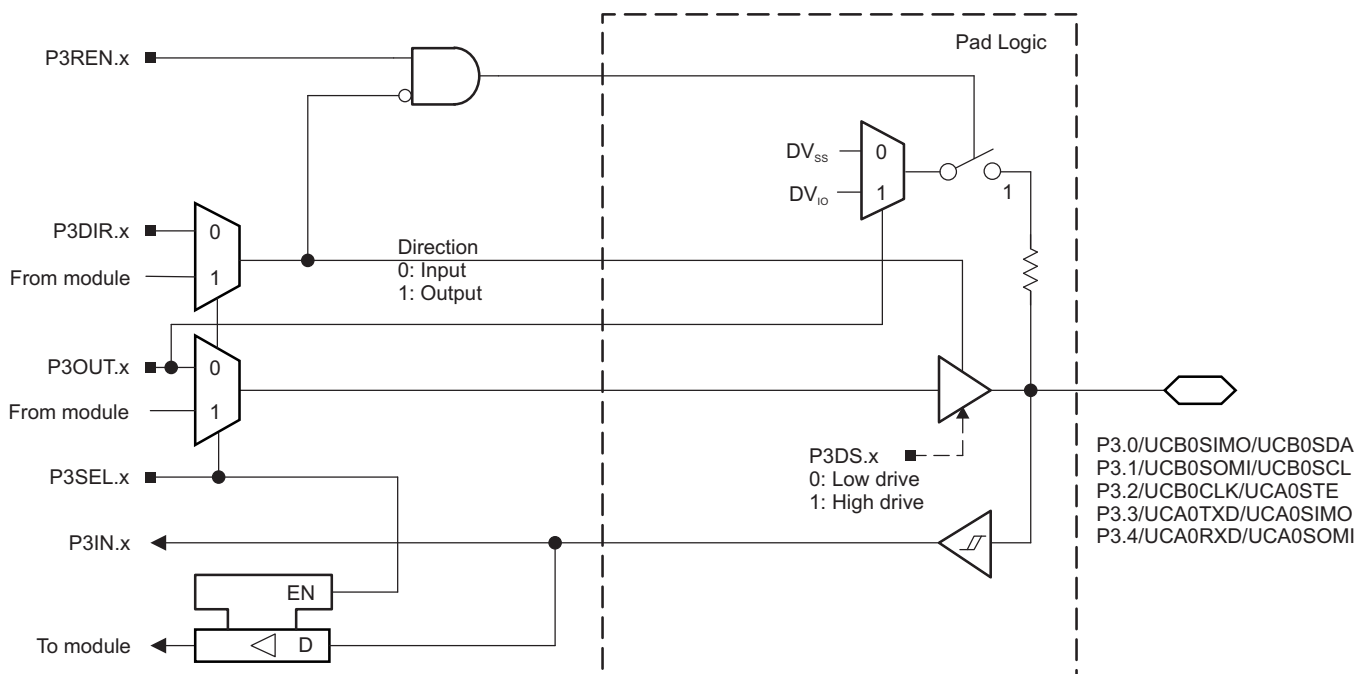


图 6-4. Port P3 (P3.0 to P3.4) Diagram

表 6-45. Port P3 (P3.0 to P3.4) Pin Functions

PIN NAME (P3.x)	x	FUNCTION	CONTROL BITS OR SIGNALS ⁽¹⁾	
			P3DIR.x	P3SEL.x
P3.0/UCB0SIMO/UCB0SDA	0	P3.0 (I/O)	I: 0; O: 1	0
		UCB0SIMO/UCB0SDA ^{(2) (3)}	X	1
P3.1/UCB0SOMI/UCB0SCL	1	P3.1 (I/O)	I: 0; O: 1	0
		UCB0SOMI/UCB0SCL ^{(2) (3)}	X	1
P3.2/UCB0CLK/UCA0STE	2	P3.2 (I/O)	I: 0; O: 1	0
		UCB0CLK/UCA0STE ^{(2) (4)}	X	1
P3.3/UCA0TXD/UCA0SIMO	3	P3.3 (I/O)	I: 0; O: 1	0
		UCA0TXD/UCA0SIMO ⁽²⁾	X	1
P3.4/UCA0RXD/UCA0SOMI	4	P3.4 (I/O)	I: 0; O: 1	0
		UCA0RXD/UCA0SOMI ⁽²⁾	X	1

(1) $X = \text{Don't care}$

(2) The pin direction is controlled by the USCI module.

(3) If the I²C functionality is selected, the output drives only the logical 0 to V_{SS} level.

(4) UCB0CLK function takes precedence over UCA0STE function. If the pin is required as UCB0CLK input or output, USC1_A0 is forced to 3-wire SPI mode if 4-wire SPI mode is selected.

6.10.4 Port P4 (P4.0 to P4.7) Input/Output With Schmitt Trigger

图 6-5 shows the port diagram. 表 6-46 summarizes the selection of the pin function.

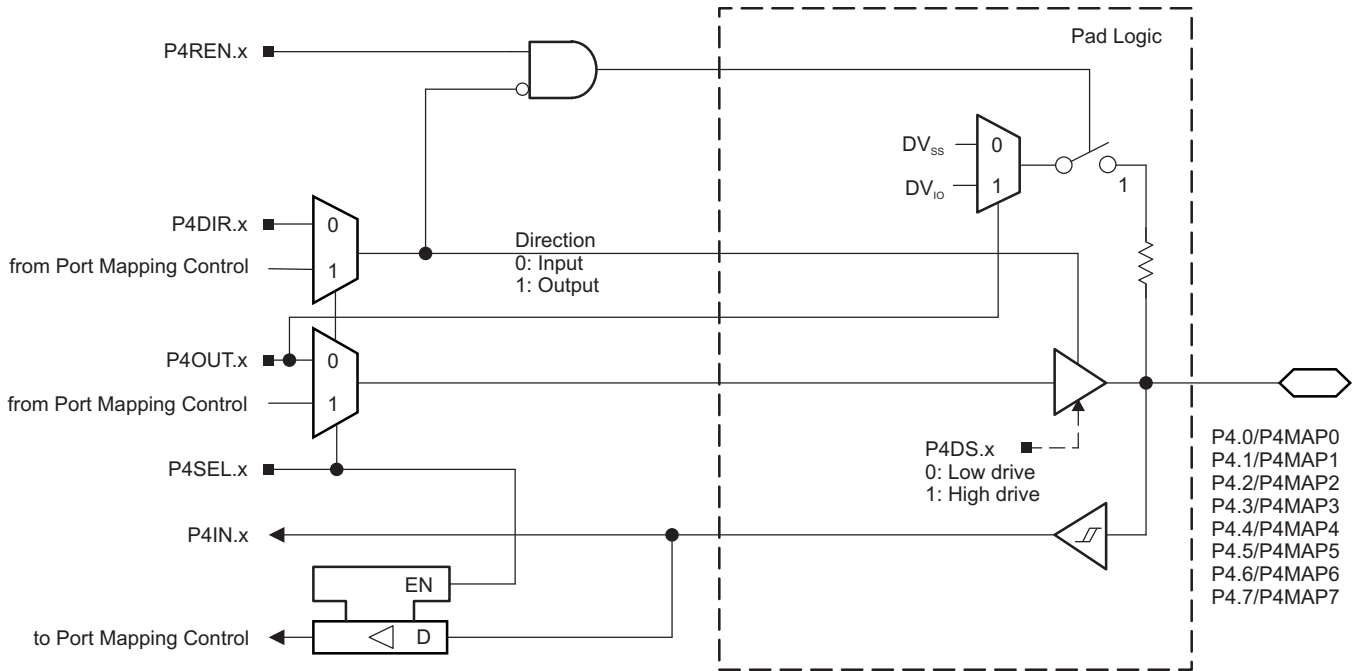


图 6-5. Port P4 (P4.0 to P4.7) Diagram

表 6-46. Port P4 (P4.0 to P4.7) Pin Functions

PIN NAME (P4.x)	x	FUNCTION	CONTROL BITS OR SIGNALS		
			P4DIR.x ⁽¹⁾	P4SEL.x	P4MAPx
P4.0/P4MAP0	0	P4.0 (I/O)	I: 0; O: 1	0	X
		Mapped secondary digital function	X	1	≤ 30
P4.1/P4MAP1	1	P4.1 (I/O)	I: 0; O: 1	0	X
		Mapped secondary digital function	X	1	≤ 30
P4.2/P4MAP2	2	P4.2 (I/O)	I: 0; O: 1	0	X
		Mapped secondary digital function	X	1	≤ 30
P4.3/P4MAP3	3	P4.3 (I/O)	I: 0; O: 1	0	X
		Mapped secondary digital function	X	1	≤ 30
P4.4/P4MAP4	4	P4.4 (I/O)	I: 0; O: 1	0	X
		Mapped secondary digital function	X	1	≤ 30
P4.5/P4MAP5	5	P4.5 (I/O)	I: 0; O: 1	0	X
		Mapped secondary digital function	X	1	≤ 30
P4.6/P4MAP6	6	P4.6 (I/O)	I: 0; O: 1	0	X
		Mapped secondary digital function	X	1	≤ 30
P4.7/P4MAP7 ⁽²⁾	7	P4.7 (I/O)	I: 0; O: 1	0	X
		Mapped secondary digital function	X	1	≤ 30

(1) The direction of some mapped secondary functions are controlled directly by the module. See 表 6-6 for specific direction control information of mapped secondary functions.

(2) Not available on RGZ packages.

6.10.5 Port P5 (P5.0 and P5.1) Input/Output With Schmitt Trigger

图 6-6 shows the port diagram. 表 6-47 summarizes the selection of the pin function.

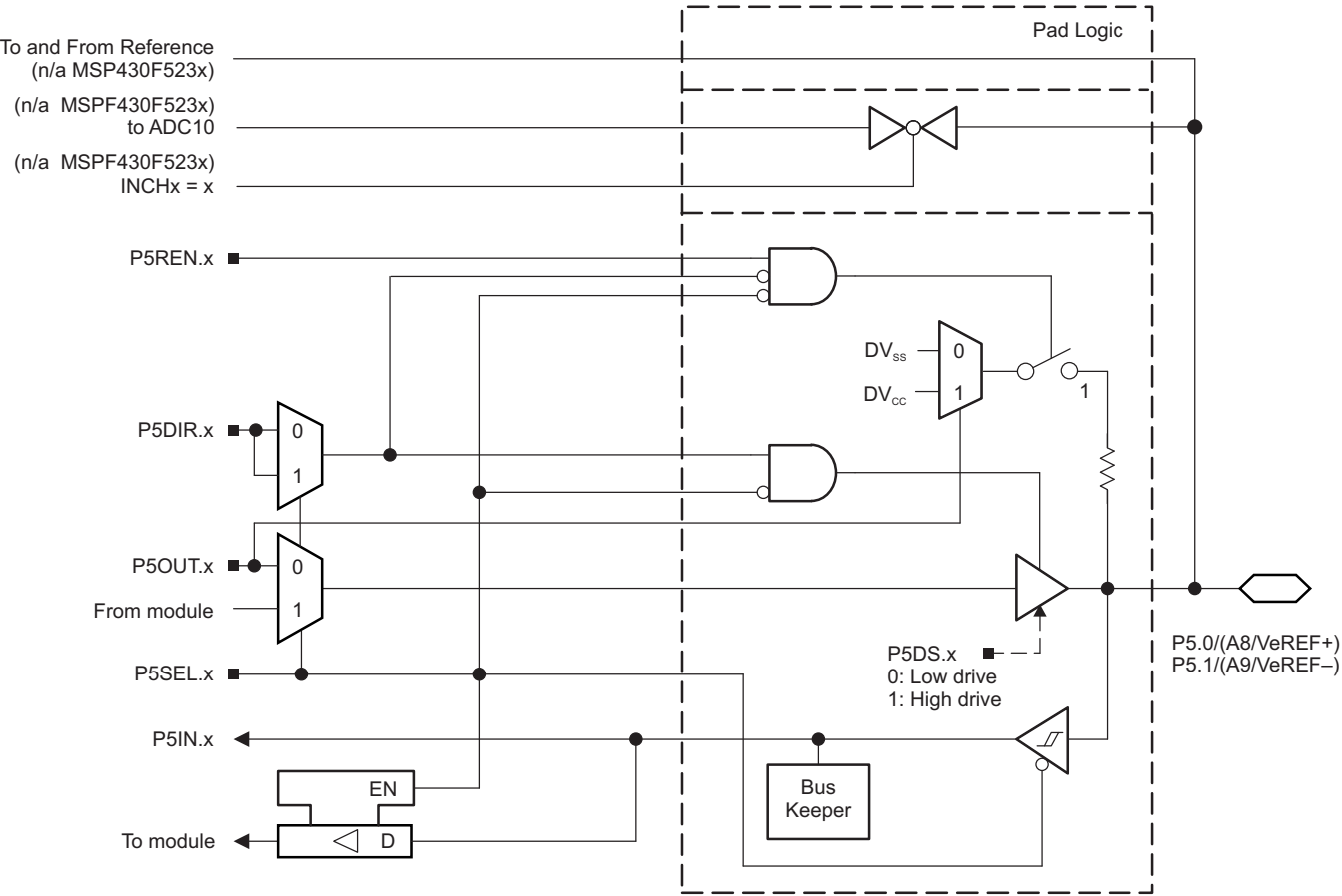


图 6-6. Port P5 (P5.0 and P5.1) Diagram

表 6-47. Port P5 (P5.0 and P5.1) Pin Functions

PIN NAME (P5.x)	x	FUNCTION	CONTROL BITS OR SIGNALS ⁽¹⁾		
			P5DIR.x	P5SEL.x	REFOUT ⁽²⁾
P5.0/A8/VeREF+	0	P5.0 (I/O) ⁽³⁾	I: 0; O: 1	0	X
		A8/VeREF+ ⁽⁴⁾	X	1	0
P5.1/A9/VeREF-	1	P5.1 (I/O) ⁽³⁾	I: 0; O: 1	0	X
		A9/VeREF- ⁽⁵⁾	X	1	0

- (1) X = Don't care
(2) REFOUT resides in the REF module.
(3) Default condition
(4) Setting the P5SEL.0 bit disables the output driver and the input Schmitt trigger to prevent parasitic cross currents when applying analog signals. An external voltage can be applied to VeREF+ and used as the reference for the ADC10_A. Channel A8, when selected with the INCHx bits, is connected to the VeREF+ pin.
(5) Setting the P5SEL.1 bit disables the output driver and the input Schmitt trigger to prevent parasitic cross currents when applying analog signals. An external voltage can be applied to VeREF- and used as the reference for the ADC10_A. Channel A9, when selected with the INCHx bits, is connected to the VeREF- pin.

6.10.6 Port P5 (P5.2 and P5.3) Input/Output With Schmitt Trigger

图 6-7 and 图 6-8 show the port diagrams. 表 6-48 summarizes the selection of the pin function.

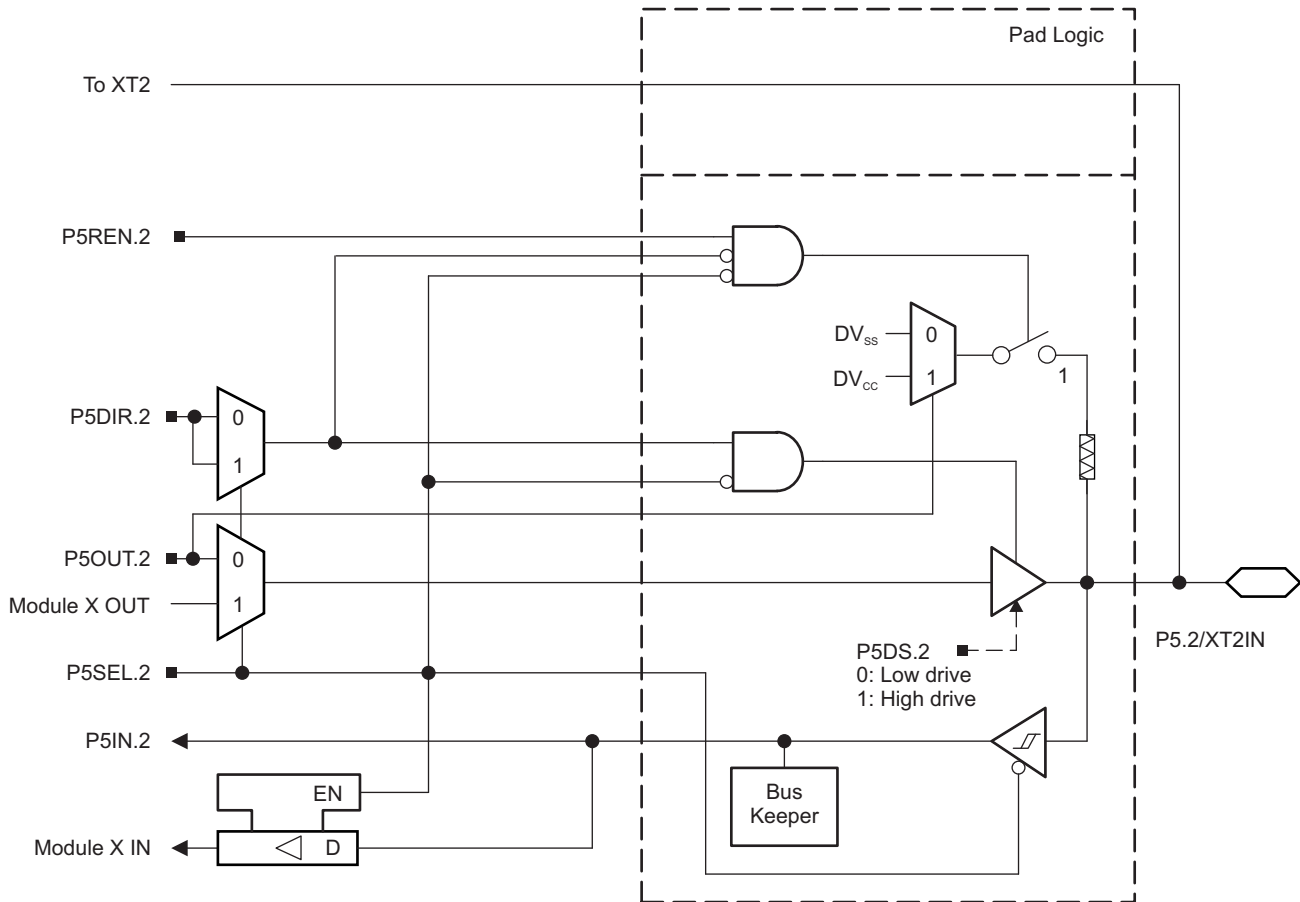


图 6-7. Port P5 (P5.2) Diagram

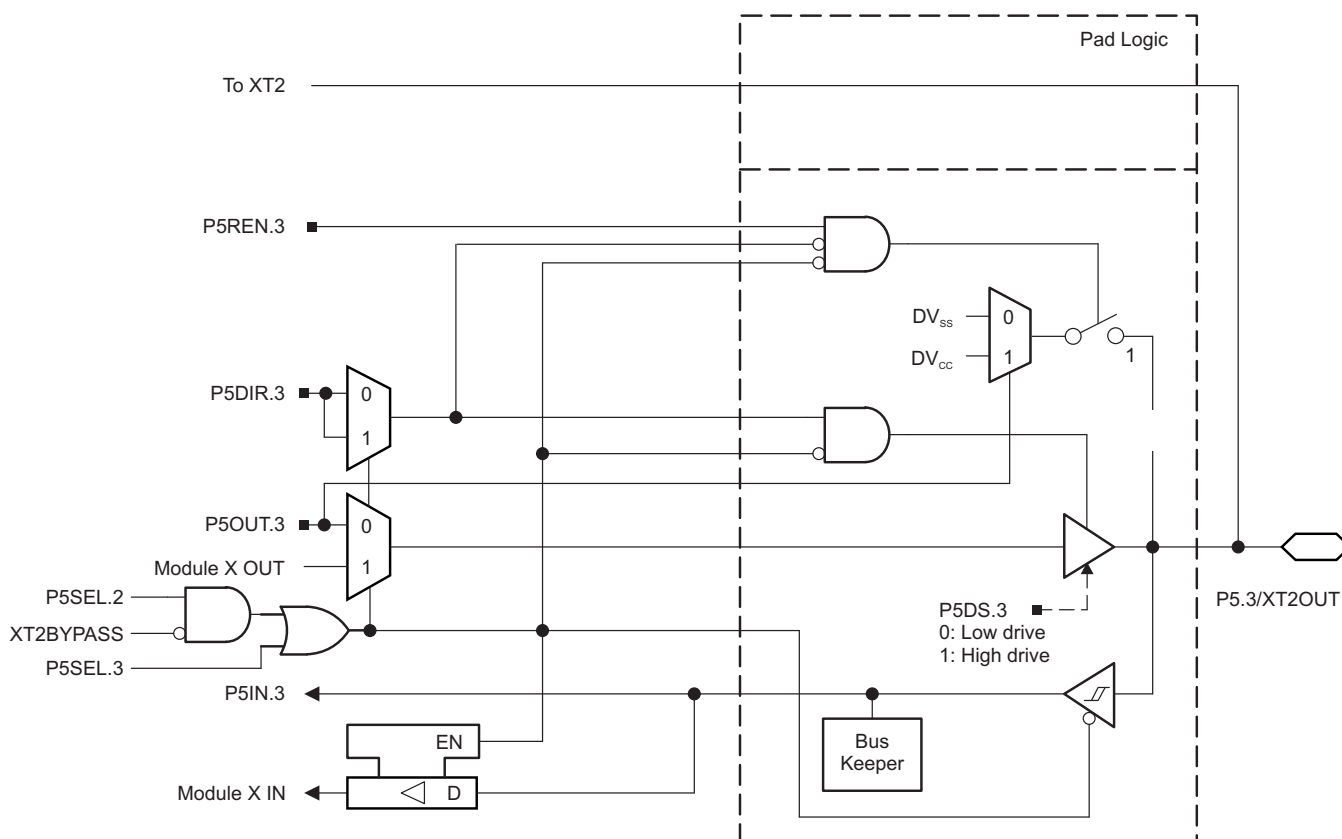


图 6-8. Port P5 (P5.3) Diagram

表 6-48. Port P5 (P5.2 and P5.3) Pin Functions

PIN NAME (P5.x)	x	FUNCTION	CONTROL BITS OR SIGNALS ⁽¹⁾			
			P5DIR.x	P5SEL.2	P5SEL.3	XT2BYPASS
P5.2/XT2IN	2	P5.2 (I/O)	I: 0; O: 1	0	X	X
		XT2IN crystal mode ⁽²⁾	X	1	X	0
		XT2IN bypass mode ⁽²⁾	X	1	X	1
P5.3/XT2OUT	3	P5.3 (I/O)	I: 0; O: 1	0	0	X
		XT2OUT crystal mode ⁽³⁾	X	1	X	0
		P5.3 (I/O) ⁽³⁾	X	1	0	1

(1) $X = \text{Don't care}$

(2) Setting P5SEL.2 causes the general-purpose I/O to be disabled. Pending the setting of XT2BYPASS, P5.2 is configured for crystal mode or bypass mode.

(3) Setting P5SEL.2 causes the general-purpose I/O to be disabled in crystal mode. When using bypass mode, P5.3 can be used as general-purpose I/O.

6.10.7 Port P5 (P5.4 and P5.5) Input/Output With Schmitt Trigger

图 6-9 和 图 6-10 show the port diagrams. 表 6-49 summarizes the selection of the pin function.

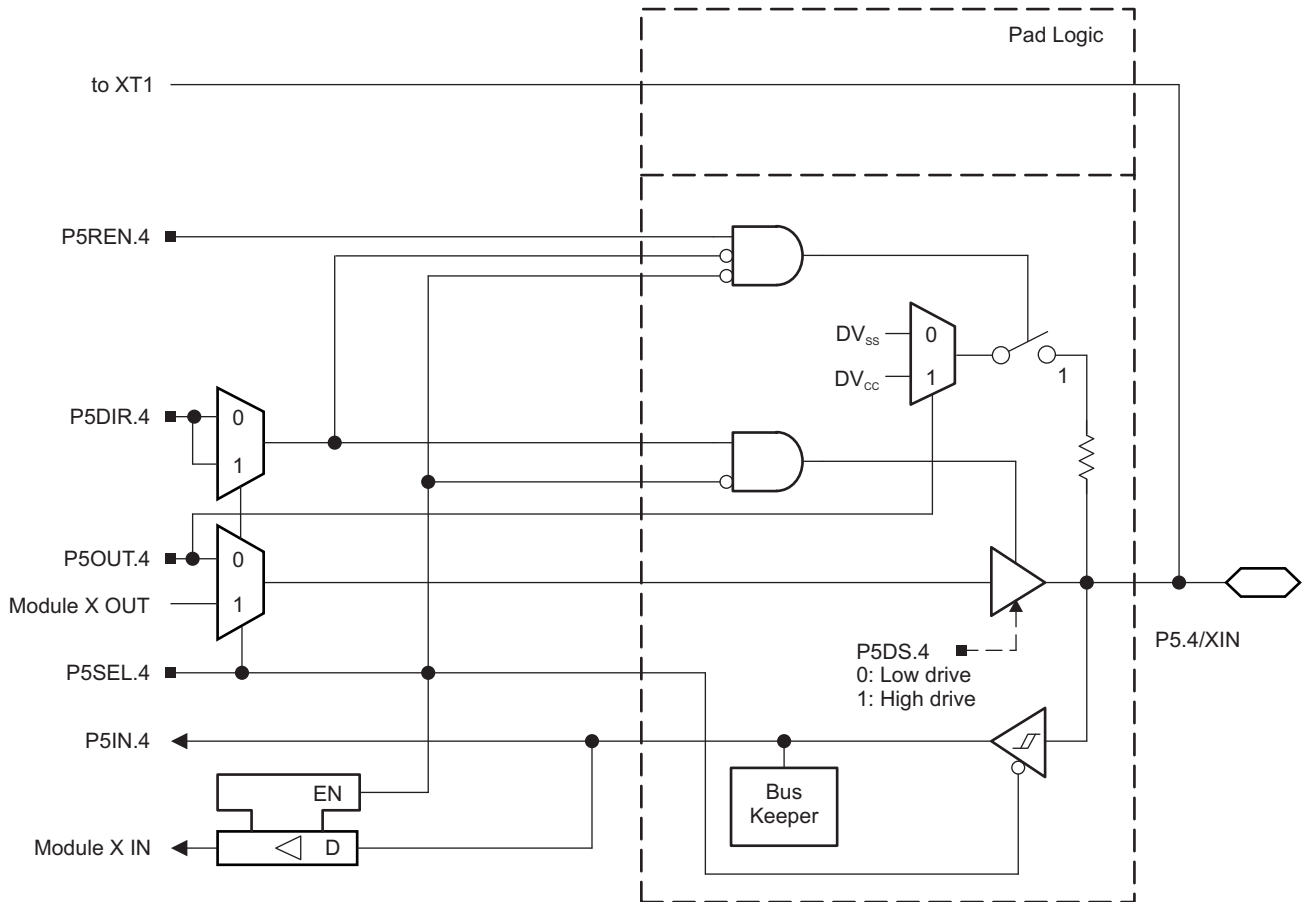


图 6-9. Port P5 (P5.4) Diagram

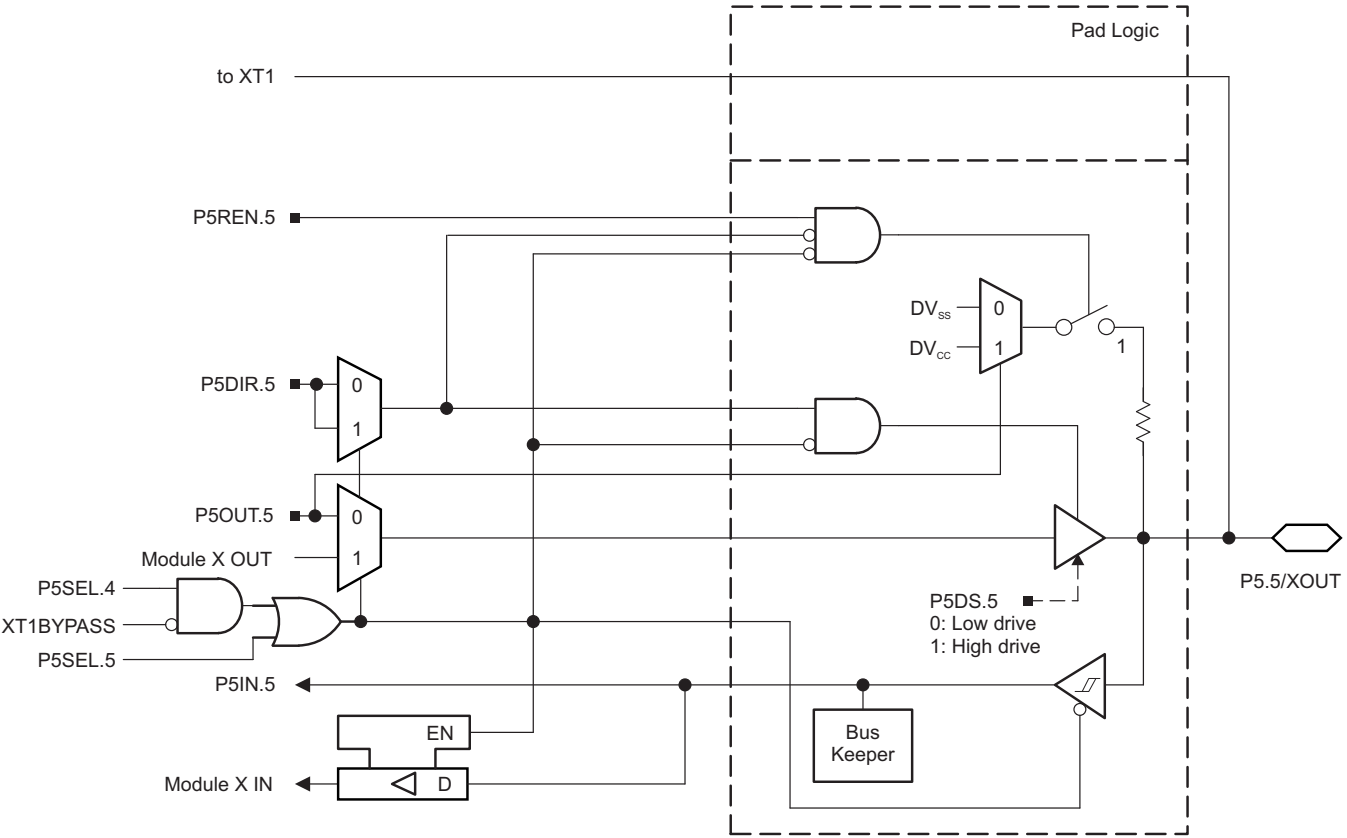


图 6-10. Port P5 (P5.5) Diagram

表 6-49. Port P5 (P5.4 and P5.5) Pin Functions

PIN NAME (P5.x)	x	FUNCTION	CONTROL BITS OR SIGNALS ⁽¹⁾			
			P5DIR.x	P5SEL.4	P5SEL.5	XT1BYPASS
P5.4/XIN	4	P5.4 (I/O)	I: 0; O: 1	0	X	X
		XIN crystal mode ⁽²⁾	X	1	X	0
		XIN bypass mode ⁽²⁾	X	1	X	1
P5.5/XOUT	5	P5.5 (I/O)	I: 0; O: 1	0	0	X
		XOUT crystal mode ⁽³⁾	X	1	X	0
		P5.5 (I/O) ⁽³⁾	X	1	0	1

- (1) X = Don't care
(2) Setting P5SEL.4 causes the general-purpose I/O to be disabled. Pending the setting of XT1BYPASS, P5.4 is configured for crystal mode or bypass mode.
(3) Setting P5SEL.4 causes the general-purpose I/O to be disabled in crystal mode. When using bypass mode, P5.5 can be used as general-purpose I/O.

6.10.8 Port P6 (P6.0 to P6.7) Input/Output With Schmitt Trigger

图 6-11 shows the port diagram. 表 6-50 summarizes the selection of the pin function.

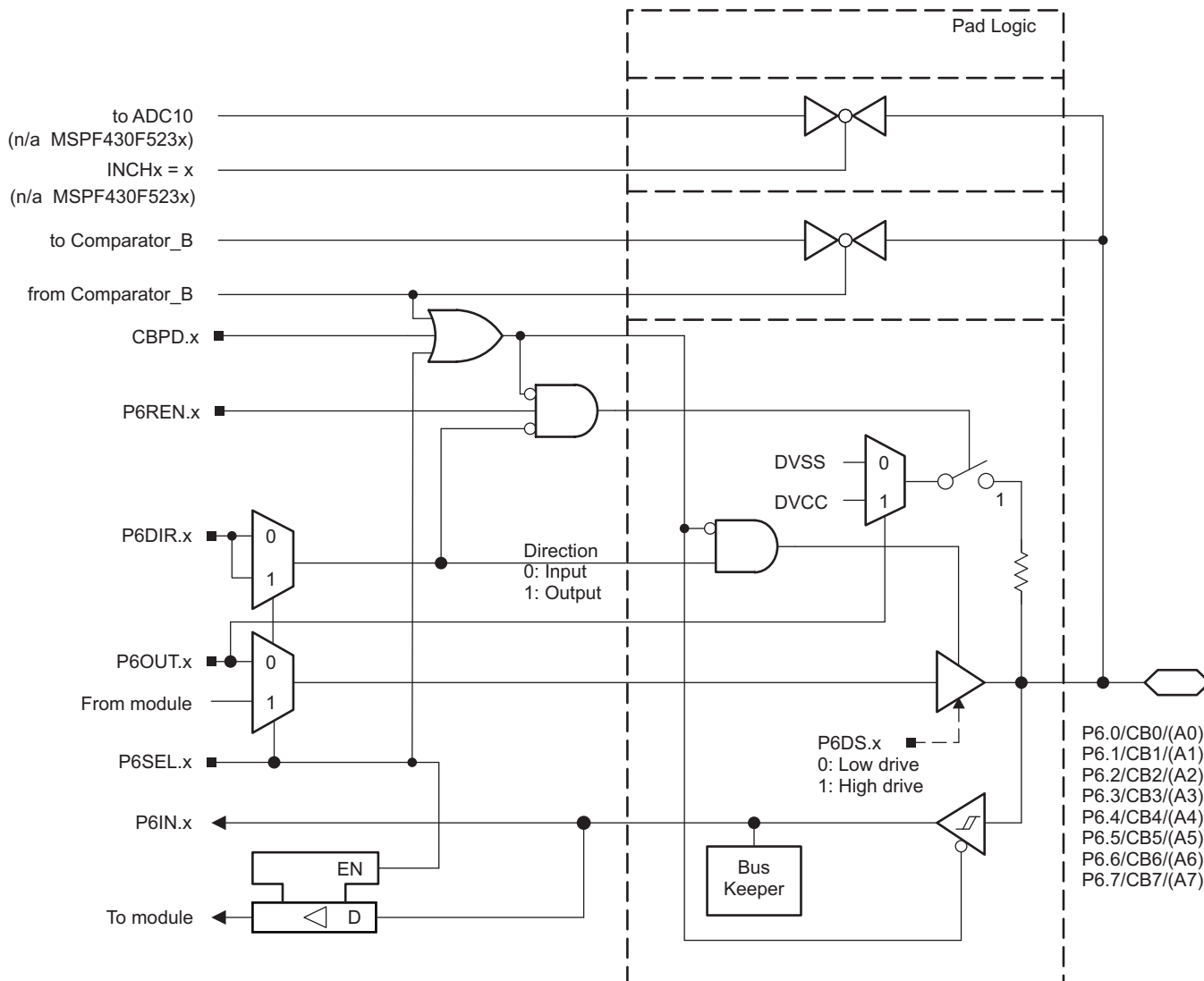


图 6-11. Port P6 (P6.0 to P6.7) Diagram

表 6-50. Port P6 (P6.0 to P6.7) Pin Functions

PIN NAME (P6.x)	x	FUNCTION	CONTROL BITS OR SIGNALS		
			P6DIR.x	P6SEL.x	CBPD
P6.0/CB0/(A0)	0	P6.0 (I/O)	I: 0; O: 1	0	0
		A0	X	1	X
		CB0 ⁽¹⁾	X	X	1
P6.1/CB1/(A1)	1	P6.1 (I/O)	I: 0; O: 1	0	0
		A1	X	1	X
		CB1 ⁽¹⁾	X	X	1
P6.2/CB2/(A2)	2	P6.2 (I/O)	I: 0; O: 1	0	0
		A2	X	1	X
		CB2 ⁽¹⁾	X	X	1
P6.3/CB3/(A3)	3	P6.3 (I/O)	I: 0; O: 1	0	0
		A3	X	1	X
		CB3 ⁽¹⁾	X	X	1
P6.4/CB4/(A4)	4	P6.4 (I/O)	I: 0; O: 1	0	0
		A4	X	1	X
		CB4 ⁽¹⁾	X	X	1
P6.5/CB5/(A5)	5	P6.5 (I/O)	I: 0; O: 1	0	0
		A5	X	1	X
		CB5 ⁽¹⁾	X	X	1
P6.6/CB6/(A6) ⁽²⁾	6	P6.6 (I/O)	I: 0; O: 1	0	0
		A6	X	1	X
		CB6 ⁽¹⁾	X	X	1
P6.7/CB7/(A7) ⁽²⁾	7	P6.7 (I/O)	I: 0; O: 1	0	0
		A7	X	1	X
		CB7 ⁽¹⁾	X	X	1

- (1) Setting the CBPD.x bit disables the output driver and the input Schmitt trigger to prevent parasitic cross currents when applying analog signals. Selecting the CBx input pin to the comparator multiplexer with the CBx bits automatically disables output driver and input buffer for that pin, regardless of the state of the associated CBPD.x bit.
- (2) Not available on RGZ packages.

6.10.9 Port P7 (P7.0 to P7.5) Input/Output With Schmitt Trigger

图 6-12 shows the port diagram. 表 6-51 summarizes the selection of the pin function.

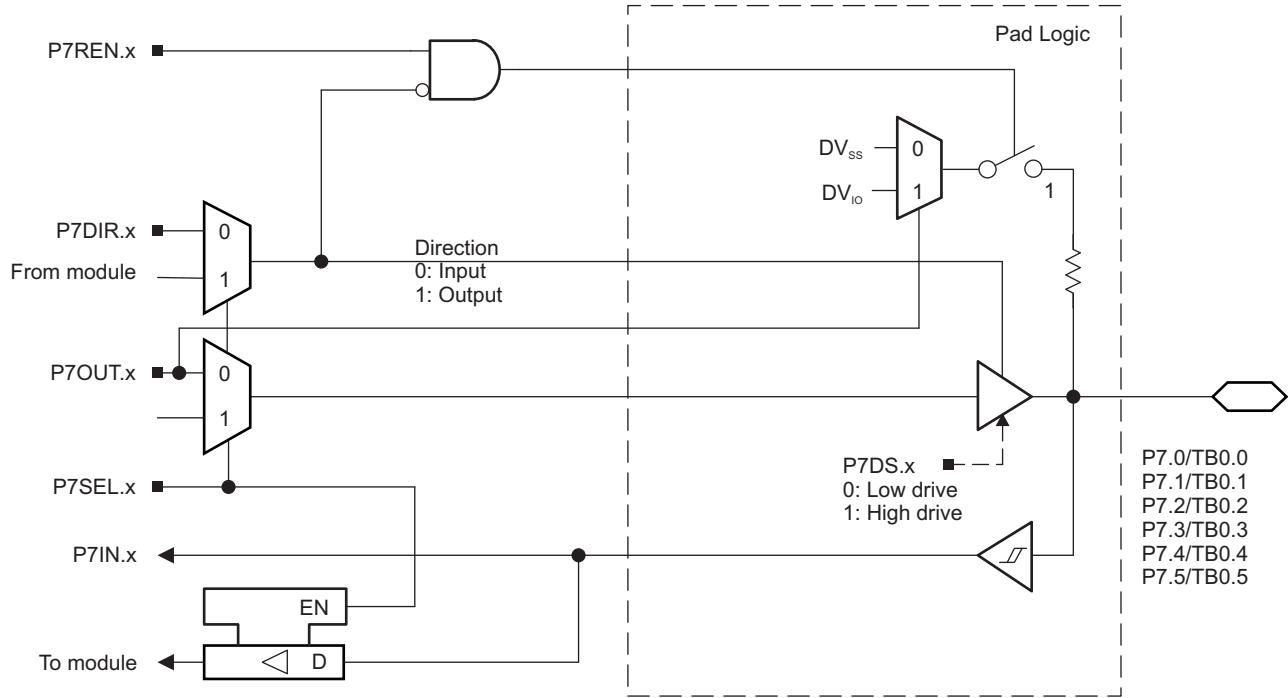


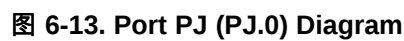
图 6-12. Port P7 (P7.0 to P7.5) Diagram

表 6-51. Port P7 (P7.0 to P7.5) Pin Functions

PIN NAME (P7.x)	x	FUNCTION	CONTROL BITS OR SIGNALS	
			P7DIR.x	P7SEL.x
P7.0/TB0.0 ⁽¹⁾	0	P7.0 (I/O)	I: 0; O: 1	0
		TB0.CCI0A	0	1
		TB0.0	1	1
P7.1/TB0.1 ⁽¹⁾	1	P7.1 (I/O)	I: 0; O: 1	0
		TB0.CCI1A	0	1
		TB0.1	1	1
P7.2/TB0.2 ⁽¹⁾	2	P7.2 (I/O)	I: 0; O: 1	0
		TB0.CCI2A	0	1
		TB0.2	1	1
P7.3/TB0.3 ⁽¹⁾	3	P7.3 (I/O)	I: 0; O: 1	0
		TB0.CCI3A	0	1
		TB0.3	1	1
P7.4/TB0.4 ⁽¹⁾	4	P7.4 (I/O)	I: 0; O: 1	0
		TB0.CCI4A	0	1
		TB0.4	1	1
P7.5/TB0.5 ⁽¹⁾	5	P7.5 (I/O)	I: 0; O: 1	0
		TB0.CCI5A	0	1
		TB0.5	1	1

(1) Not available on RGZ packages.

图 6-13 and 图 6-14 show the port diagrams. 表 6-52 summarizes the selection of the pin function.



6.10.11 Port J (PJ.1 to PJ.3) JTAG Pins TMS, TCK, TDI/TCLK, Input/Output With Schmitt Trigger or Output

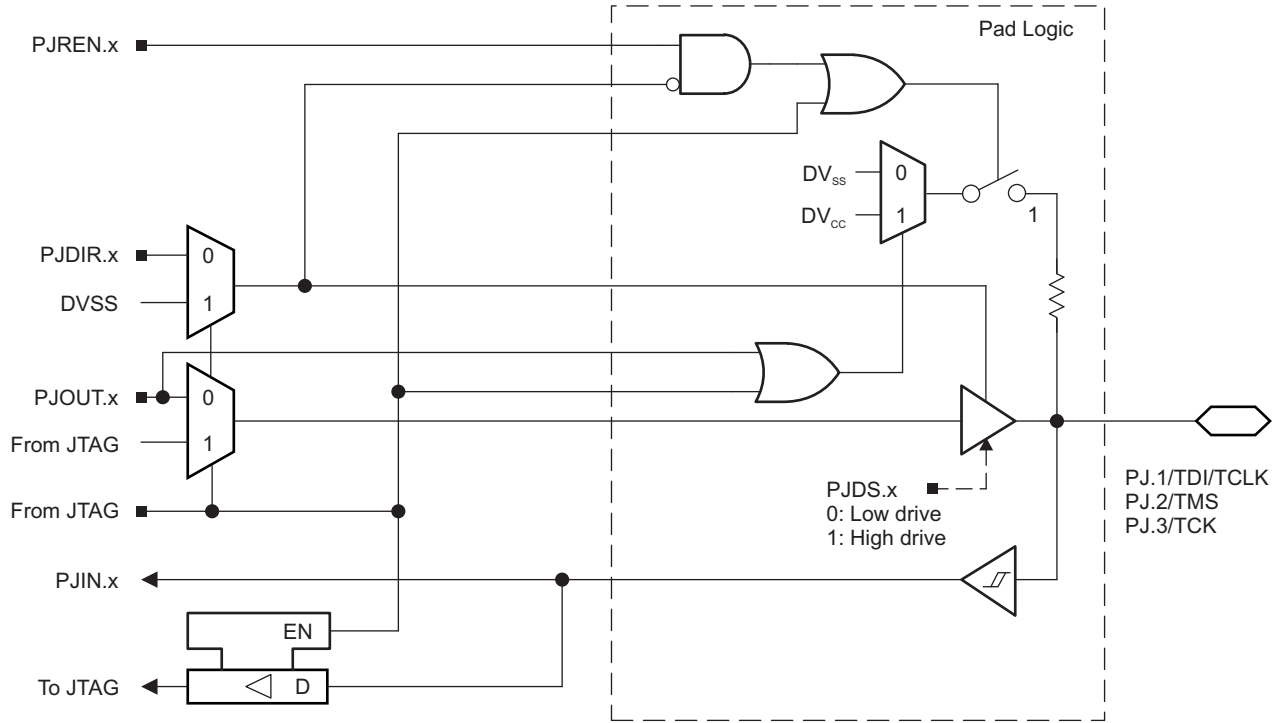


图 6-14. Port PJ (PJ.1 to PJ.3) Diagram

表 6-52. Port PJ (PJ.0 to PJ.3) Pin Functions

PIN NAME (PJ.x)	x	FUNCTION	CONTROL BITS OR SIGNALS ⁽¹⁾
			PJDIR.x
PJ.0/TDO	0	PJ.0 (I/O) ⁽²⁾	I: 0; O: 1
		TDO ⁽³⁾	X
PJ.1/TDI/TCLK	1	PJ.1 (I/O) ⁽²⁾	I: 0; O: 1
		TDI/TCLK ^{(3) (4)}	X
PJ.2/TMS	2	PJ.2 (I/O) ⁽²⁾	I: 0; O: 1
		TMS ^{(3) (4)}	X
PJ.3/TCK	3	PJ.3 (I/O) ⁽²⁾	I: 0; O: 1
		TCK ^{(3) (4)}	X

(1) X = Don't care

(2) Default condition

(3) The pin direction is controlled by the JTAG module.

(4) In JTAG mode, pullups are activated automatically on TMS, TCK, and TDI/TCLK. PJREN.x are don't care.

6.11 Device Descriptors

表 6-53 和 表 6-54 show the contents of the device descriptor tag-length-value (TLV) structure for each device type.

表 6-53. MSP430F524x Device Descriptor Table⁽¹⁾

DESCRIPTION		ADDRESS	SIZE (bytes)	VALUE			
				F5249	F5247	F5244	F5242
Info Block	Info length	01A00h	1	06h	06h	06h	06h
	CRC length	01A01h	1	06h	06h	06h	06h
	CRC value	01A02h	2	Per unit	Per unit	Per unit	Per unit
	Device ID	01A04h	1	F3h	F4h	F5h	F6h
	Device ID	01A05h	1	81h	81h	81h	81h
	Hardware revision	01A06h	1	Per unit	Per unit	Per unit	Per unit
	Firmware revision	01A07h	1	Per unit	Per unit	Per unit	Per unit
Die Record	Die record tag	01A08h	1	08h	08h	08h	08h
	Die record length	01A09h	1	0Ah	0Ah	0Ah	0Ah
	Lot/wafer ID	01A0Ah	4	Per unit	Per unit	Per unit	Per unit
	Die X position	01A0Eh	2	Per unit	Per unit	Per unit	Per unit
	Die Y position	01A10h	2	Per unit	Per unit	Per unit	Per unit
	Test results	01A12h	2	Per unit	Per unit	Per unit	Per unit
ADC10 Calibration	ADC10 calibration tag	01A14h	1	13h	13h	13h	13h
	ADC10 calibration length	01A15h	1	10h	10h	10h	10h
	ADC gain factor	01A16h	2	Per unit	Per unit	Per unit	Per unit
	ADC offset	01A18h	2	Per unit	Per unit	Per unit	Per unit
	ADC 1.5-V reference Temperature sensor 30°C	01A1Ah	2	Per unit	Per unit	Per unit	Per unit
	ADC 1.5-V reference Temperature sensor 85°C	01A1Ch	2	Per unit	Per unit	Per unit	Per unit
	ADC 2.0-V reference Temperature sensor 30°C	01A1Eh	2	Per unit	Per unit	Per unit	Per unit
	ADC 2.0-V reference Temperature sensor 85°C	01A20h	2	Per unit	Per unit	Per unit	Per unit
	ADC 2.5-V reference Temperature sensor 30°C	01A22h	2	Per unit	Per unit	Per unit	Per unit
	ADC 2.5-V reference Temperature sensor 85°C	01A24h	2	Per unit	Per unit	Per unit	Per unit
REF Calibration	REF calibration tag	01A26h	1	12h	12h	12h	12h
	REF calibration length	01A27h	1	06h	06h	06h	06h
	REF 1.5-V reference factor	01A28h	2	Per unit	Per unit	Per unit	Per unit
	REF 2.0-V reference factor	01A2Ah	2	Per unit	Per unit	Per unit	Per unit
	REF 2.5-V reference factor	01A2Ch	2	Per unit	Per unit	Per unit	Per unit

(1) N/A = Not applicable, blank = unused and reads FFh

表 6-53. MSP430F524x Device Descriptor Table⁽¹⁾ (continued)

DESCRIPTION	ADDRESS	SIZE (bytes)	VALUE			
			F5249	F5247	F5244	F5242
Peripheral Descriptor	Peripheral descriptor tag	01A2Eh	1	02h	02h	02h
	Peripheral descriptor length	01A2Fh	1	5Fh	5Fh	5Dh
	Memory 1		2	08h 8Ah	08h 8Ah	08h 8Ah
	Memory 2		2	0Ch 86h	0Ch 86h	0Ch 86h
	Memory 3		2	12h 2Eh	12h 2Eh	12h 2Eh
	Memory 4		2	22h 96h	22h 94h	22h 94h
	Memory 5		2	N/A	N/A	N/A
	Memory 6		1/2	N/A	N/A	N/A
	Delimiter		1	00h	00h	00h
	Peripheral count		1	20h	20h	1Fh
	MSP430CPUXV2		2	00h 23h	00h 23h	00h 23h
	JTAG		2	00h 09h	00h 09h	00h 09h
	SBW		2	00h 0Fh	00h 0Fh	00h 0Fh
	EEM-S		2	00h 03h	00h 03h	00h 05h
	TI BSL		2	00h FCh	00h FCh	00h FCh
	SFR		2	10h 41h	10h 41h	10h 41h
	PMM		2	02h 30h	02h 30h	02h 30h
	FCTL		2	02h 38h	02h 38h	02h 38h
	CRC16		2	01h 3Ch	01h 3Ch	01h 3Ch
	CRC16_RB		2	00h 3Dh	00h 3Dh	00h 3Dh
	RAMCTL		2	00h 44h	00h 44h	00h 44h
	WDT_A		2	00h 40h	00h 40h	00h 40h
	UCS		2	01h 48h	01h 48h	01h 48h
	SYS		2	02h 42h	02h 42h	02h 42h
	REF		2	03h A0h	03h A0h	03h A0h
	Port Mapping		2	01h 10h	01h 10h	01h 10h
	Port 1 and 2		2	04h 51h	04h 51h	04h 51h
	Port 3 and 4		2	02h 52h	02h 52h	02h 52h
	Port 5 and 6		2	02h 53h	02h 53h	02h 53h
	Port 7 and 8		2	02h 54h	02h 54h	N/A N/A

表 6-53. MSP430F524x Device Descriptor Table⁽¹⁾ (continued)

DESCRIPTION	ADDRESS	SIZE (bytes)	VALUE			
			F5249	F5247	F5244	F5242
Peripheral Descriptor (continued)	JTAG	2	0Ch 5Fh	0Ch 5Fh	0Eh 5Fh	0Eh 5Fh
	TA0	2	02h 62h	02h 62h	02h 62h	02h 62h
	TA1	2	04h 61h	04h 61h	04h 61h	04h 61h
	TB0	2	04h 67h	04h 67h	04h 67h	04h 67h
	TA2	2	04h 61h	04h 61h	04h 61h	04h 61h
	RTC	2	0Ah 68h	0Ah 68h	0Ah 68h	0Ah 68h
	MPY32	2	02h 85h	02h 85h	02h 85h	02h 85h
	DMA-3	2	04h 47h	04h 47h	04h 47h	04h 47h
	USCI_A and USCI_B	2	0Ch 90h	0Ch 90h	0Ch 90h	0Ch 90h
	USCI_A and USCI_B	2	04h 90h	04h 90h	04h 90h	04h 90h
	ADC10_A	2	14h D3h	14h D3h	14h D3h	14h D3h
	COMP_B	2	18h A8h	18h A8h	18h A8h	18h A8h
Interrupts	COMP_B	1	A8h	A8h	A8h	A8h
	TB0.CCIFG0	1	64h	64h	64h	64h
	TB0.CCIFG1...6	1	65h	65h	65h	65h
	WDTIFG	1	40h	40h	40h	40h
	USCI_A0	1	90h	90h	90h	90h
	USCI_B0	1	91h	91h	91h	91h
	ADC10_A	1	D0h	D0h	D0h	D0h
	TA0.CCIFG0	1	60h	60h	60h	60h
	TA0.CCIFG1...4	1	61h	61h	61h	61h
	Reserved	1	01h	01h	01h	01h
	DMA	1	46h	46h	46h	46h
	TA1.CCIFG0	1	62h	62h	62h	62h
	TA1.CCIFG1...2	1	63h	63h	63h	63h
	P1	1	50h	50h	50h	50h
	USCI_A1	1	92h	92h	92h	92h
	USCI_B1	1	93h	93h	93h	93h
	TA1.CCIFG0	1	66h	66h	66h	66h
	TA1.CCIFG1...2	1	67h	67h	67h	67h
	P2	1	51h	51h	51h	51h
	RTC_A	1	68h	68h	68h	68h
	delimiter	1	00h	00h	00h	00h

表 6-54. MSP430F523x Device Descriptor Table⁽¹⁾

DESCRIPTION		ADDRESS	SIZE (bytes)	VALUE			
				F5239	F5237	F5234	F5232
Info Block	Info length	01A00h	1	06h	06h	06h	06h
	CRC length	01A01h	1	06h	06h	06h	06h
	CRC value	01A02h	2	Per unit	Per unit	Per unit	Per unit
	Device ID	01A04h	1	F7h	F8h	F9h	FAh
	Device ID	01A05h	1	81h	81h	81h	81h
	Hardware revision	01A06h	1	Per unit	Per unit	Per unit	Per unit
	Firmware revision	01A07h	1	Per unit	Per unit	Per unit	Per unit
Die Record	Die record tag	01A08h	1	08h	08h	08h	08h
	Die record length	01A09h	1	0Ah	0Ah	0Ah	0Ah
	Lot/wafer ID	01A0Ah	4	Per unit	Per unit	Per unit	Per unit
	Die X position	01A0Eh	2	Per unit	Per unit	Per unit	Per unit
	Die Y position	01A10h	2	Per unit	Per unit	Per unit	Per unit
	Test results	01A12h	2	Per unit	Per unit	Per unit	Per unit
ADC10 Calibration	ADC10 calibration tag	01A14h	1	13h	13h	13h	13h
	ADC10 calibration length	01A15h	1	10h	10h	10h	10h
	ADC gain factor	01A16h	2	blank	blank	blank	blank
	ADC offset	01A18h	2	blank	blank	blank	blank
	ADC 1.5-V reference Temperature sensor 30°C	01A1Ah	2	blank	blank	blank	blank
	ADC 1.5-V reference Temperature sensor 85°C	01A1Ch	2	blank	blank	blank	blank
	ADC 2.0-V reference Temperature sensor 30°C	01A1Eh	2	blank	blank	blank	blank
	ADC 2.0-V reference Temperature sensor 85°C	01A20h	2	blank	blank	blank	blank
	ADC 2.5-V reference Temperature sensor 30°C	01A22h	2	blank	blank	blank	blank
	ADC 2.5-V reference Temperature sensor 85°C	01A24h	2	blank	blank	blank	blank
REF Calibration	REF calibration tag	01A26h	1	12h	12h	12h	12h
	REF calibration length	01A27h	1	06h	06h	06h	06h
	REF 1.5-V reference factor	01A28h	2	Per unit	Per unit	Per unit	Per unit
	REF 2.0-V reference factor	01A2Ah	2	Per unit	Per unit	Per unit	Per unit
	REF 2.5-V reference factor	01A2Ch	2	Per unit	Per unit	Per unit	Per unit

(1) N/A = Not applicable, blank = unused and reads FFh

表 6-54. MSP430F523x Device Descriptor Table⁽¹⁾ (continued)

DESCRIPTION		ADDRESS	SIZE (bytes)	VALUE			
				F5239	F5237	F5234	F5232
Peripheral Descriptor	Peripheral descriptor tag	01A2Eh	1	02h	02h	02h	02h
	Peripheral descriptor length	01A2Fh	1	5Dh	5Dh	5Bh	5Bh
	Memory 1		2	08h 8Ah	08h 8Ah	08h 8Ah	08h 8Ah
	Memory 2		2	0Ch 86h	0Ch 86h	0Ch 86h	0Ch 86h
	Memory 3		2	12h 2Eh	12h 2Eh	12h 2Eh	12h 2Eh
	Memory 4		2	22h 96h	22h 94h	22h 96h	22h 94h
	Memory 5		2	N/A	N/A	N/A	N/A
	Memory 6		1/2	N/A	N/A	N/A	N/A
	Delimiter		1	00h	00h	00h	00h
	Peripheral count		1	1Fh	1Fh	1Eh	1Eh
	MSP430CPUXV2		2	00h 23h	00h 23h	00h 23h	00h 23h
	JTAG		2	00h 09h	00h 09h	00h 09h	00h 09h
	SBW		2	00h 0Fh	00h 0Fh	00h 0Fh	00h 0Fh
	EEM-S		2	00h 03h	00h 03h	00h 03h	00h 05h
	TI BSL		2	00h FCh	00h FCh	00h FCh	00h FCh
	SFR		2	10h 41h	10h 41h	10h 41h	10h 41h
	PMM		2	02h 30h	02h 30h	02h 30h	02h 30h
	FCTL		2	02h 38h	02h 38h	02h 38h	02h 38h
	CRC16		2	01h 3Ch	01h 3Ch	01h 3Ch	01h 3Ch
	CRC16_RB		2	00h 3Dh	00h 3Dh	00h 3Dh	00h 3Dh
	RAMCTL		2	00h 44h	00h 44h	00h 44h	00h 44h
	WDT_A		2	00h 40h	00h 40h	00h 40h	00h 40h
	UCS		2	01h 48h	01h 48h	01h 48h	01h 48h
	SYS		2	02h 42h	02h 42h	02h 42h	02h 42h
	REF		2	03h A0h	03h A0h	03h A0h	03h A0h
	Port mapping		2	01h 10h	01h 10h	01h 10h	01h 10h
	Port 1 and 2		2	04h 51h	04h 51h	04h 51h	04h 51h
	Port 3 and 4		2	02h 52h	02h 52h	02h 52h	02h 52h
	Port 5 and 6		2	02h 53h	02h 53h	02h 53h	02h 53h
	Port 7 and 8		2	02h 54h	02h 54h	N/A	N/A

表 6-54. MSP430F523x Device Descriptor Table⁽¹⁾ (continued)

DESCRIPTION	ADDRESS	SIZE (bytes)	VALUE			
			F5239	F5237	F5234	F5232
Peripheral Descriptor (continued)	JTAG	2	0Ch 5Fh	0Ch 5Fh	0Eh 5Fh	0Eh 5Fh
	TA0	2	02h 62h	02h 62h	02h 62h	02h 62h
	TA1	2	04h 61h	04h 61h	04h 61h	04h 61h
	TB0	2	04h 67h	04h 67h	04h 67h	04h 67h
	TA2	2	04h 61h	04h 61h	04h 61h	04h 61h
	RTC	2	0Ah 68h	0Ah 68h	0Ah 68h	0Ah 68h
	MPY32	2	02h 85h	02h 85h	02h 85h	02h 85h
	DMA-3	2	04h 47h	04h 47h	04h 47h	04h 47h
	USCI_A and USCI_B	2	0Ch 90h	0Ch 90h	0Ch 90h	0Ch 90h
	USCI_A and USCI_B	2	04h 90h	04h 90h	04h 90h	04h 90h
	ADC10_A	2	N/A	N/A	N/A	N/A
	COMP_B	2	2Ch A8h	2Ch A8h	2Ch A8h	2Ch A8h
Interrupts	COMP_B	1	A8h	A8h	A8h	A8h
	TB0.CCIFG0	1	64h	64h	64h	64h
	TB0.CCIFG1...6	1	65h	65h	65h	65h
	WDTIFG	1	40h	40h	40h	40h
	USCI_A0	1	90h	90h	90h	90h
	USCI_B0	1	91h	91h	91h	91h
	Reserved	1	01h	01h	01h	01h
	TA0.CCIFG0	1	60h	60h	60h	60h
	TA0.CCIFG1...4	1	61h	61h	61h	61h
	Reserved	1	01h	01h	01h	01h
	DMA	1	46h	46h	46h	46h
	TA1.CCIFG0	1	62h	62h	62h	62h
	TA1.CCIFG1...2	1	63h	63h	63h	63h
	P1	1	50h	50h	50h	50h
	USCI_A1	1	92h	92h	92h	92h
	USCI_B1	1	93h	93h	93h	93h
	TA2.CCIFG0	1	66h	66h	66h	66h
	TA2.CCIFG1...2	1	67h	67h	67h	67h
	P2	1	51h	51h	51h	51h
	RTC_A	1	68h	68h	68h	68h
	Delimiter	1	00h	00h	00h	00h

7 器件和文档支持

7.1 入门和后续步骤

有关 MSP430™ 系列器件以及开发协助工具和库的更多信息，请访问 [MSP430 超低功耗传感和测量 MCU 概述](#)。

7.2 Device Nomenclature

To designate the stages in the product development cycle, TI assigns prefixes to the part numbers of all MSP MCU devices. Each MSP MCU commercial family member has one of two prefixes: MSP or XMS. These prefixes represent evolutionary stages of product development from engineering prototypes (XMS) through fully qualified production devices (MSP).

XMS – Experimental device that is not necessarily representative of the final device's electrical specifications

MSP – Fully qualified production device

XMS devices are shipped against the following disclaimer:

"Developmental product is intended for internal evaluation purposes."

MSP devices have been characterized fully, and the quality and reliability of the device have been demonstrated fully. TI's standard warranty applies.

Predictions show that prototype devices (XMS) have a greater failure rate than the standard production devices. TI recommends that these devices not be used in any production system because their expected end-use failure rate still is undefined. Only qualified production devices are to be used.

TI device nomenclature also includes a suffix with the device family name. This suffix indicates the temperature range, package type, and distribution format. [图 7-1](#) provides a legend for reading the complete device name.

MSP 430 F 5 438 A I ZQW T -EP		
Processor Family	MCU Platform	Optional: Additional Features
Device Type	Series	Optional: Tape and Reel
Feature Set	Optional: Temperature Range	Packaging
Optional: A = Revision		
Processor Family	CC = Embedded RF Radio MSP = Mixed-Signal Processor XMS = Experimental Silicon PMS = Prototype Device	
MCU Platform	430 = MSP430 low-power microcontroller platform	
Device Type	Memory Type C = ROM F = Flash FR = FRAM G = Flash or FRAM (Value Line) L = No Nonvolatile Memory	Specialized Application AFE = Analog Front End BQ = Contactless Power CG = ROM Medical FE = Flash Energy Meter FG = Flash Medical FW = Flash Electronic Flow Meter
Series	1 = Up to 8 MHz 2 = Up to 16 MHz 3 = Legacy 4 = Up to 16 MHz with LCD	5 = Up to 25 MHz 6 = Up to 25 MHz with LCD 0 = Low-Voltage Series
Feature Set	Various levels of integration within a series	
Optional: A = Revision	N/A	
Optional: Temperature Range	S = 0°C to 50°C C = 0°C to 70°C I = –40°C to 85°C T = –40°C to 105°C	
Packaging	http://www.ti.com/packaging	
Optional: Tape and Reel	T = Small reel R = Large reel No markings = Tube or tray	
Optional: Additional Features	-EP = Enhanced Product (–40°C to 105°C) -HT = Extreme Temperature Parts (–55°C to 150°C) -Q1 = Automotive Q100 Qualified	

图 7-1. Device Nomenclature

7.3 工具与软件

所有 MSP 微控制器均受多种软件和硬件开发工具的支持。相关工具由 TI 以及多家第三方供应商提供。请参阅 [MSP430 超低功耗 MCU – 工具与软件](#)，了解所有工具。

表 7-1 列出了 MSP430F522x MCU 的调试功能。请参阅《适用于 MSP430 的 Code Composer Studio 用户指南》，以了解可用功能的详细信息。

表 7-1. 硬件调试特性

MSP430 架构	四线制 JTAG	两线制 JTAG	断点 (N)	范围断点	时钟控制	状态序列发生器	跟踪缓冲器	LPMx.5 调试支持
MSP430Xv2	有	有	3	有	是	否	否	否

设计套件与评估模块

适用于 MSP430F5x MCU 的 64 引脚目标开发板和 MSP-FET 编程器捆绑包 MSP-FET430U64C 是一款功能强大的工具，其中包含了完成大部分应用开发工作所需的硬件和软件。只需按几下键即可在数秒钟内擦除闪存并对其进行编程，此外，由于 MSP430 闪存的功耗极低，因此无需外部电源。

适用于 MSP430F5x MCU 的 64 引脚目标开发板 MSP-TS430RGC64C 是一款独立的 64 引脚 ZIF 插座目标板，用于通过 JTAG 接口或 Spy-Bi-Wire（两线制 JTAG）协议在系统内对 MSP430 MCU 进行编程和调试。

软件

MSP430Ware™ 软件 MSP430Ware 软件集合了所有 MSP430 器件的代码示例、数据表以及其他设计资源，打包提供给用户。除了提供已有 MSP430 MCU 设计资源的完整集合外，MSP430Ware 软件还包含名为 MSP 驱动程序库的高级 API。借助该库可以轻松地对 MSP430 硬件进行编程。MSP430Ware 软件以 CCS 组件或独立软件包两种形式提供。

MSP430F524x、MSP430F523x 代码示例 根据不同应用需求配置各集成外设的 C 代码示例。

MSP 驱动程序库 驱动程序库的抽象化 API 通过提供易于使用的函数调用使您不再拘泥于 MSP430 硬件的细节。完整的文档通过具有帮助意义的 API 指南交付，其中包括有关每个函数调用和经过验证的参数的详细信息。开发人员可以使用驱动程序库功能，以最低开销编写完整项目。

MSP EnergyTrace™ 技术 适用于 MSP430 微控制器的 EnergyTrace 技术是基于电能的代码分析工具，用于测量和显示应用的电能系统配置并帮助优化应用以实现超低功耗。

ULP（超低功耗）Advisor ULP Advisor™ 软件是一款辅助工具，旨在指导开发人员编写更为高效的代码，从而充分利用 MSP 和 MSP432 微控制器独特的超低功耗功能。ULP Advisor 的目标人群是微控制器的资深开发者和开发新手，可以根据详尽的 ULP 检验表检查代码，以便最大限度地利用应用程序。在编译时，ULP Advisor 会提供通知和备注以突出显示代码中可以进一步优化的区域，进而实现更低功耗。

IEC60730 软件包 IEC60730 MSP430 软件包经过专门开发，用于协助客户达到 IEC 60730-1:2010（家用及类似用途的自动化电气控制 - 第 1 部分：一般要求）B 类产品的要求。其中涵盖家用电器、电弧检测器、电源转换器、电动工具、电动自行车及其他诸多产品。IEC60730 MSP430 软件包可以嵌入在 MSP430 中运行的客户应用，从而帮助客户简化其消费类器件在功能安全方面遵循 IEC 60730-1:2010 B 类规范的认证工作。

适用于 MSP 的定点数学库 MSP IQmath 和 Qmath 库是为 C 语言开发者提供的一套经过高度优化的高精度数学运算函数集合，能够将浮点算法无缝嵌入 MSP430 和 MSP432 器件的定点代码中。这些例程通常用于计算密集型实时应用，而优化的执行速度、高精度以及超低能耗通常是影响这些实时应用的关键因素。与使用浮点数学算法编写的同等代码相比，使用 IQmath 和 Qmath 库可以大幅提高执行速度并显著降低能耗。

适用于 MSP430 的浮点数学运算库 TI 在低功耗和低成本微控制器领域锐意创新，为您提供 MSPMATHLIB。这是标量函数的浮点数学运算库，能够充分利用器件的智能外设，使性能提升高达 26 倍。Mathlib 能够轻松集成到您的设计中。该运算库免费使用并集成在 Code Composer Studio 和 IAR IDE 中。如需深入了解该数学运算库及相关基准，请阅读用户指南。

开发工具

适用于 MSP 微控制器的 Code Composer Studio™ 集成开发环境 Code Composer Studio 是一种集成开发环境 (IDE)，支持所有 MSP 微控制器。Code Composer Studio 包含一整套开发和调试嵌入式应用的嵌入式软件实用程序的工具。它包含了优化的 C/C++ 编译器、源代码编辑器、项目构建环境、调试器、描述器以及其他多种功能。直观的 IDE 提供了单个用户界面，有助于完成应用程序开发流程的每个步骤。熟悉的实用程序和界面可提升用户的入门速度。Code Composer Studio 将 Eclipse 软件框架的优点和 TI 先进的嵌入式调试功能相结合，为嵌入式开发人员提供了一种功能丰富的优异开发环境。

命令行编程器 MSP Flasher 是一款基于 shell 的开源接口，可使用 JTAG 或 Spy-Bi-Wire (SBW) 通信通过 FET 编程器或 eZ430 对 MSP 微控制器进行编程。MSP Flasher 可用于将二进制文件 (.txt 或 .hex 文件) 直接下载到 MSP 微控制器，而无需使用 IDE。

MSP MCU 编程器和调试器 MSP-FET 是一款强大的仿真开发工具（通常称为调试探针），可帮助用户在 MSP 低功耗微控制器 (MCU) 中快速开发应用。创建 MCU 软件通常需要将生成的二进制程序下载到 MSP 器件，以进行验证和调试。MSP-FET 在主机和目标 MSP 间提供调试通信通道。此外，MSP-FET 还可在计算机的 USB 接口和 MSP UART 间提供反向通道 UART 连接。这为 MSP 编程器提供了一种在 MSP 和计算机上运行的终端之间进行串行通信的便捷方法。

MSP-GANG 生产编程器 MSP Gang 编程器是一款 MSP430 或 MSP432 器件编程器，可同时对多达八个完全相同的 MSP430 或 MSP432 闪存或 FRAM 器件进行编程。MSP Gang 编程器可使用标准的 RS-232 或 USB 连接与主机 PC 相连并提供灵活的编程选项，允许用户完全自定义流程。MSP Gang 编程器配有扩展板，即“Gang 分离器”，可在 MSP Gang 编程器和多个目标器件间实施互连。提供了八条电缆，用于将扩展板与八个目标器件相连（通过 JTAG 或 SPY-Bi-Wire 连接器）。编程工作可在 PC 或独立设备上完成。

7.4 文档支持

以下文档对 MSP430F524x 和 MPS430F543x 器件进行了介绍。www.ti.com.cn 网站上提供了这些文档的副本。

接收文档更新通知

要接收文档更新通知（包括芯片勘误表），请转至 ti.com.cn 上您的器件对应的产品文件夹（关于产品文件夹的链接，请参见节 7.5）。请单击右上角的“通知我”按钮。点击注册后，即可收到产品信息更改每周摘要（如有）。有关更改的详细信息，请查阅已修订文档的修订历史记录。

勘误

- 《[MSP430F5249 器件勘误表](#)》 介绍功能规格的已知例外情况。
- 《[MSP430F5247 器件勘误表](#)》 介绍功能规格的已知例外情况。
- 《[MSP430F5244 器件勘误表](#)》 介绍功能规格的已知例外情况。
- 《[MSP430F5242 器件勘误表](#)》 介绍功能规格的已知例外情况。
- 《[MSP430F5239 器件勘误表](#)》 介绍功能规格的已知例外情况。
- 《[MSP430F5237 器件勘误表](#)》 介绍功能规格的已知例外情况。
- 《[MSP430F5234 器件勘误表](#)》 介绍功能规格的已知例外情况。
- 《[MSP430F5232 器件勘误表](#)》 介绍功能规格的已知例外情况。

用户指南

- 《[MSP430F5xx 和 MSP430F6xx 系列用户指南](#)》 详细介绍了该器件系列提供的模块和外设。
- 《[MSP430 闪存器件引导加载程序 \(BSL\) 用户指南](#)》 MSP430 引导加载程序 (BSL，之前称为引导装载程序) 方便用户在原型建模阶段、最终生产和维修期间与 MSP430 微控制器中的嵌入式存储器进行通信。可编程存储器 (闪存) 和数据存储器 (RAM) 能够按照要求进行变更。不要将此处的引导加载程序与某些数字信号处理器 (DSP) 中将外部存储器中的程序代码 (和数据) 自动加载到 DSP 内部存储器的引导装载程序混为一谈。
- 《[通过 JTAG 接口对 MSP430 进行编程](#)》 此文档介绍了使用 JTAG 通信端口擦除、编程和验证基于 MSP430 闪存和 FRAM 的微控制器系列的存储器模块所需的功能。此外，该文档还介绍了如何编程所有 MSP430 器件上均具备的 JTAG 访问安全保险丝。此文档介绍了使用标准四线制 JTAG 接口和两线制 JTAG 接口 (也称为 Spy-Bi-Wire (SBW)) 的器件访问。
- 《[MSP430 硬件工具用户指南](#)》 此手册介绍了 TI MSP-FET430 闪存仿真工具 (FET) 的硬件。FET 是针对 MSP430 超低功耗微控制器的程序开发工具。文中对提供的接口类型，即并行端口接口和 USB 接口进行了说明。

应用报告

- 《[MSP430 32kHz 晶体振荡器](#)》 选择合适的晶体、正确的负载电路和适当的电路板布局是实现稳定的晶体振荡器的关键。该应用报告总结了晶体振荡器的功能，介绍了用于选择合适的晶体以实现 MSP430 超低功耗运行的参数。此外，还给出了正确电路板布局的提示和示例。此外，为了确保振荡器在大规模生产后能够稳定运行，还可能需要进行一些振荡器测试，该文档中提供了有关这些测试的详细信息。
- 《[MSP430 系统级 ESD 注意事项](#)》 随着芯片技术向更低电压方向发展以及设计具有成本效益的超低功耗组件的需求的出现，系统级 ESD 要求变得越来越苛刻。该应用报告阐述了三个不同的 ESD 主题，以帮助电路板设计人员和 OEM 了解并实现强大的系统级设计：(1) 组件级 ESD 测试和系统级 ESD 测试；(2) 实现系统级 ESD 保护的通用设计指南；(3) 系统高效 ESD 设计 (SEED) 简介，这是一种板载和片上 ESD 保护协同设计方法。

7.5 相关链接

表 7-2 列出了快速访问链接。类别包括技术文档、支持与社区资源、工具和软件，以及申请样片或购买产品的快速链接。

表 7-2. 相关链接

器件	产品文件夹	立即订购	技术文档	工具与软件	支持和社区
MSP430F5249	请单击此处	请单击此处	请单击此处	请单击此处	请单击此处

表 7-2. 相关链接 (continued)

器件	产品文件夹	立即订购	技术文档	工具与软件	支持和社区
MSP430F5247	请单击此处	请单击此处	请单击此处	请单击此处	请单击此处
MSP430F5244	请单击此处	请单击此处	请单击此处	请单击此处	请单击此处
MSP430F5242	请单击此处	请单击此处	请单击此处	请单击此处	请单击此处
MSP430F5239	请单击此处	请单击此处	请单击此处	请单击此处	请单击此处
MSP430F5237	请单击此处	请单击此处	请单击此处	请单击此处	请单击此处
MSP430F5234	请单击此处	请单击此处	请单击此处	请单击此处	请单击此处
MSP430F5232	请单击此处	请单击此处	请单击此处	请单击此处	请单击此处

7.6 社区资源

下列链接提供到 TI 社区资源的连接。链接的内容由各个分销商“按照原样”提供。这些内容并不构成 TI 技术规范，并且不一定反映 TI 的观点；请参见 TI 的《使用条款》。

TI E2E™ 社区

TI 的工程师交流 (E2E) 社区。此社区的创建目的是为了促进工程师之间协作。在 e2e.ti.com 中，您可以提问、共享知识、拓展思路，在同领域工程师的帮助下解决问题。

TI 嵌入式处理器维基网页

德州仪器 (TI) 嵌入式处理器维基网页。此网站的建立是为了帮助开发人员熟悉德州仪器 (TI) 的嵌入式处理器，并且也为了促进与这些器件相关的硬件和软件的总体知识的创新和增长。

7.7 商标

MSP430, MSP430Ware, EnergyTrace, ULP Advisor, 适用于 MSP 微控制器的 Code Composer Studio, E2E are trademarks of Texas Instruments.

All other trademarks are the property of their respective owners.

7.8 静电放电警告



ESD 可能会损坏该集成电路。德州仪器 (TI) 建议通过适当的预防措施处理所有集成电路。如果不遵守正确的处理措施和安装程序，可能会损坏集成电路。

ESD 的损坏小至导致微小的性能降级，大至整个器件故障。精密的集成电路可能更容易受到损坏，这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

7.9 Export Control Notice

Recipient agrees to not knowingly export or re-export, directly or indirectly, any product or technical data (as defined by the U.S., EU, and other Export Administration Regulations) including software, or any controlled product restricted by other applicable national regulations, received from disclosing party under nondisclosure obligations (if any), or any direct product of such technology, to any destination to which such export or re-export is restricted or prohibited by U.S. or other applicable laws, without obtaining prior authorization from U.S. Department of Commerce and other competent Government authorities to the extent required by those laws.

7.10 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

8 机械、封装和可订购信息

以下页中包括机械、封装和可订购信息。这些信息是指定器件的最新可用数据。数据如有变更，恕不另行通知，且不会对此文档进行修订。如需获取此数据表的浏览器版本，请查阅左侧的导航栏。

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
MSP430F5232IRGZR	ACTIVE	VQFN	RGZ	48	2500	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5232	Samples
MSP430F5232IRGZT	ACTIVE	VQFN	RGZ	48	250	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5232	Samples
MSP430F5234IRGZR	ACTIVE	VQFN	RGZ	48	2500	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5234	Samples
MSP430F5234IRGZT	ACTIVE	VQFN	RGZ	48	250	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5234	Samples
MSP430F5237IRGCR	ACTIVE	VQFN	RGC	64	2000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5237	Samples
MSP430F5237IRGCT	ACTIVE	VQFN	RGC	64	250	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5237	Samples
MSP430F5239IRGCR	ACTIVE	VQFN	RGC	64	2000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5239	Samples
MSP430F5239IRGCT	ACTIVE	VQFN	RGC	64	250	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5239	Samples
MSP430F5242IRGZR	ACTIVE	VQFN	RGZ	48	2500	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5242	Samples
MSP430F5242IRGZT	ACTIVE	VQFN	RGZ	48	250	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5242	Samples
MSP430F5244IRGZR	ACTIVE	VQFN	RGZ	48	2500	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5244	Samples
MSP430F5244IRGZT	ACTIVE	VQFN	RGZ	48	250	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5244	Samples
MSP430F5247IRGCR	ACTIVE	VQFN	RGC	64	2000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5247	Samples
MSP430F5247IRGCT	ACTIVE	VQFN	RGC	64	250	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5247	Samples
MSP430F5249IRGCR	ACTIVE	VQFN	RGC	64	2000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5249	Samples
MSP430F5249IRGCT	ACTIVE	VQFN	RGC	64	250	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	F5249	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of ≤ 1000 ppm threshold. Antimony trioxide based flame retardants must also meet the ≤ 1000 ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

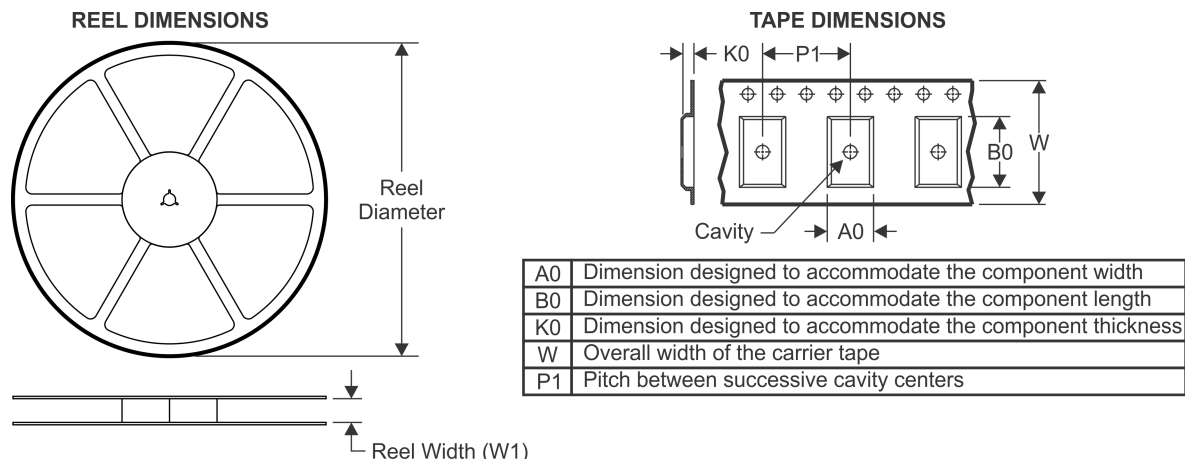
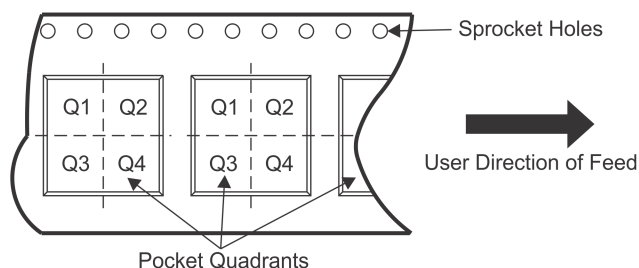
⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

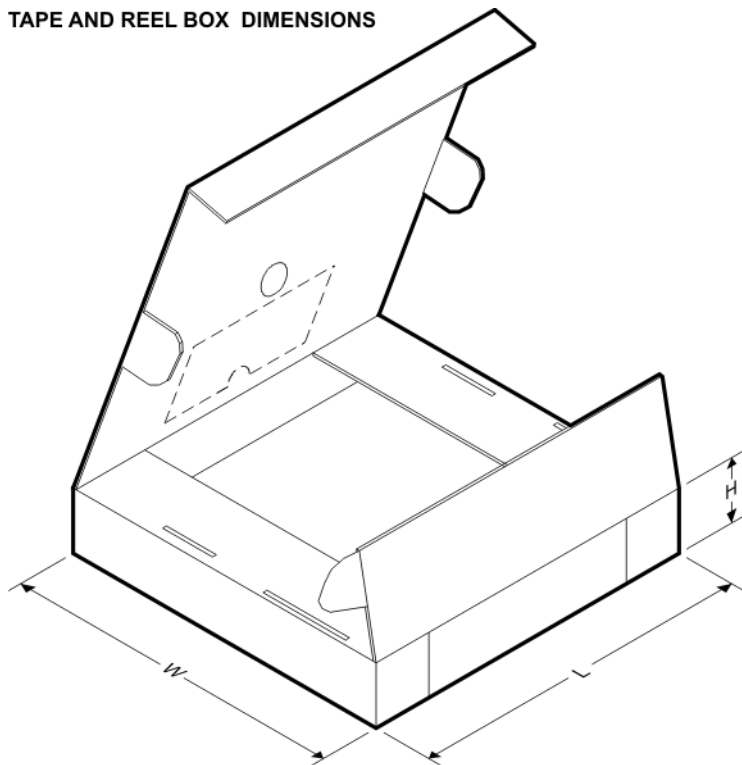
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

TAPE AND REEL INFORMATION

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
MSP430F5232IRGZR	VQFN	RGZ	48	2500	330.0	16.4	7.3	7.3	1.1	12.0	16.0	Q2
MSP430F5232IRGZT	VQFN	RGZ	48	250	180.0	16.4	7.3	7.3	1.1	12.0	16.0	Q2
MSP430F5234IRGZR	VQFN	RGZ	48	2500	330.0	16.4	7.3	7.3	1.1	12.0	16.0	Q2
MSP430F5234IRGZT	VQFN	RGZ	48	250	180.0	16.4	7.3	7.3	1.1	12.0	16.0	Q2
MSP430F5237IRGCR	VQFN	RGC	64	2000	330.0	16.4	9.3	9.3	1.1	12.0	16.0	Q2
MSP430F5237IRGCT	VQFN	RGC	64	250	180.0	16.4	9.3	9.3	1.1	12.0	16.0	Q2
MSP430F5239IRGCR	VQFN	RGC	64	2000	330.0	16.4	9.3	9.3	1.1	12.0	16.0	Q2
MSP430F5239IRGCT	VQFN	RGC	64	250	180.0	16.4	9.3	9.3	1.1	12.0	16.0	Q2
MSP430F5242IRGZR	VQFN	RGZ	48	2500	330.0	16.4	7.3	7.3	1.1	12.0	16.0	Q2
MSP430F5242IRGZT	VQFN	RGZ	48	250	180.0	16.4	7.3	7.3	1.1	12.0	16.0	Q2
MSP430F5244IRGZR	VQFN	RGZ	48	2500	330.0	16.4	7.3	7.3	1.1	12.0	16.0	Q2
MSP430F5244IRGZT	VQFN	RGZ	48	250	180.0	16.4	7.3	7.3	1.1	12.0	16.0	Q2
MSP430F5247IRGCR	VQFN	RGC	64	2000	330.0	16.4	9.3	9.3	1.1	12.0	16.0	Q2
MSP430F5247IRGCT	VQFN	RGC	64	250	180.0	16.4	9.3	9.3	1.1	12.0	16.0	Q2
MSP430F5249IRGCR	VQFN	RGC	64	2000	330.0	16.4	9.3	9.3	1.1	12.0	16.0	Q2
MSP430F5249IRGCT	VQFN	RGC	64	250	180.0	16.4	9.3	9.3	1.1	12.0	16.0	Q2

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
MSP430F5232IRGZR	VQFN	RGZ	48	2500	367.0	367.0	38.0
MSP430F5232IRGZT	VQFN	RGZ	48	250	210.0	185.0	35.0
MSP430F5234IRGZR	VQFN	RGZ	48	2500	367.0	367.0	38.0
MSP430F5234IRGZT	VQFN	RGZ	48	250	210.0	185.0	35.0
MSP430F5237IRGCR	VQFN	RGC	64	2000	367.0	367.0	38.0
MSP430F5237IRGCT	VQFN	RGC	64	250	210.0	185.0	35.0
MSP430F5239IRGCR	VQFN	RGC	64	2000	367.0	367.0	38.0
MSP430F5239IRGCT	VQFN	RGC	64	250	210.0	185.0	35.0
MSP430F5242IRGZR	VQFN	RGZ	48	2500	367.0	367.0	38.0
MSP430F5242IRGZT	VQFN	RGZ	48	250	210.0	185.0	35.0
MSP430F5244IRGZR	VQFN	RGZ	48	2500	367.0	367.0	38.0
MSP430F5244IRGZT	VQFN	RGZ	48	250	210.0	185.0	35.0
MSP430F5247IRGCR	VQFN	RGC	64	2000	367.0	367.0	38.0
MSP430F5247IRGCT	VQFN	RGC	64	250	210.0	185.0	35.0
MSP430F5249IRGCR	VQFN	RGC	64	2000	367.0	367.0	38.0
MSP430F5249IRGCT	VQFN	RGC	64	250	210.0	185.0	35.0

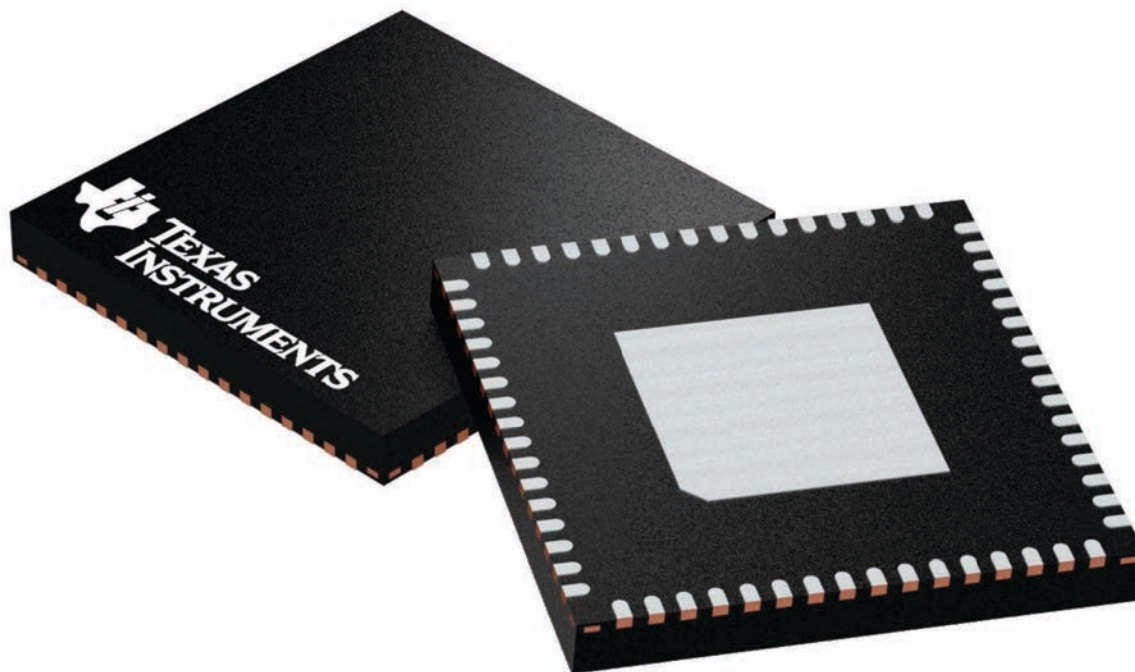
GENERIC PACKAGE VIEW

RGC 64

VQFN - 1 mm max height

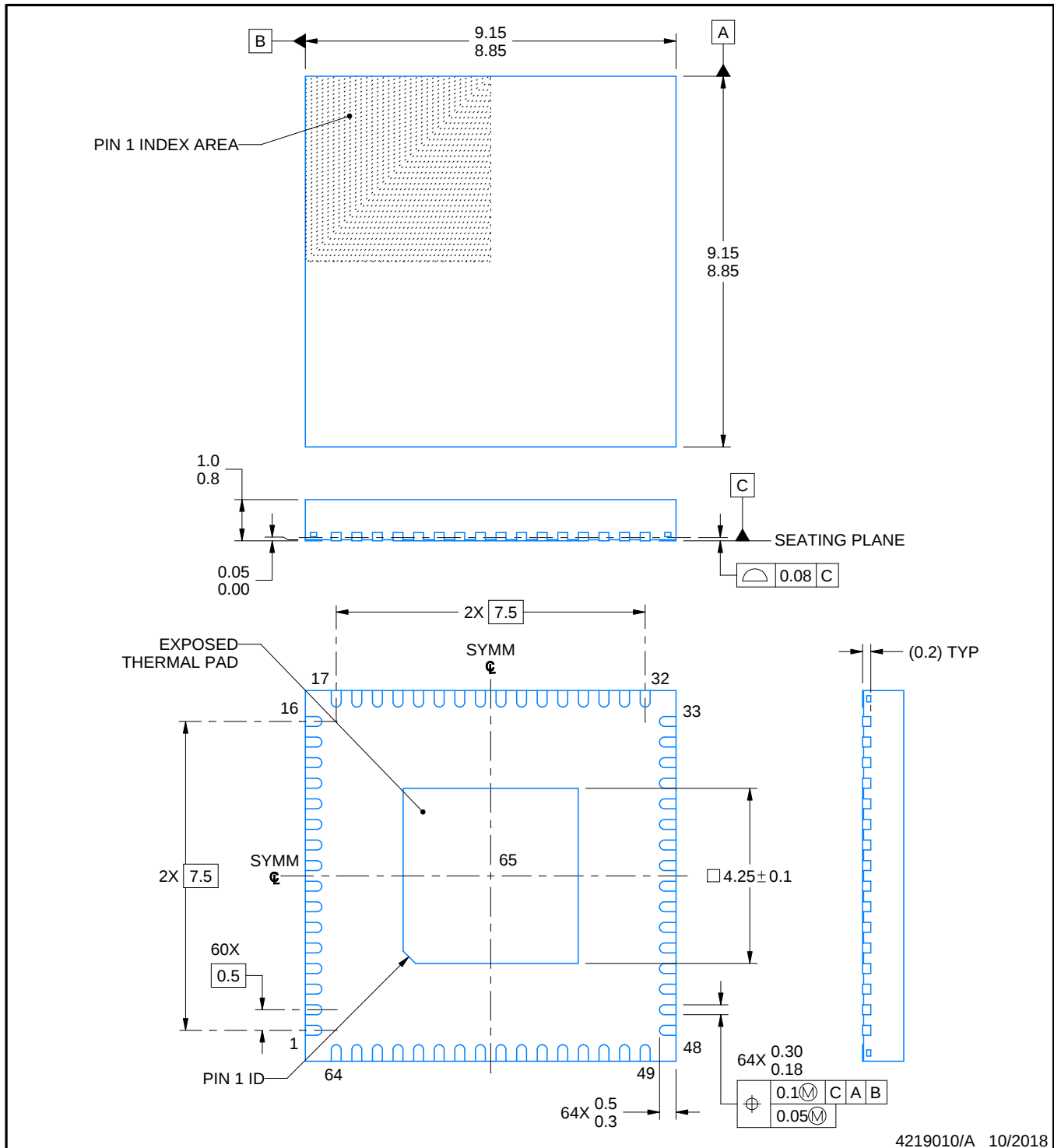
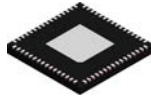
9 x 9, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD



Images above are just a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.

4224597/A



NOTES:

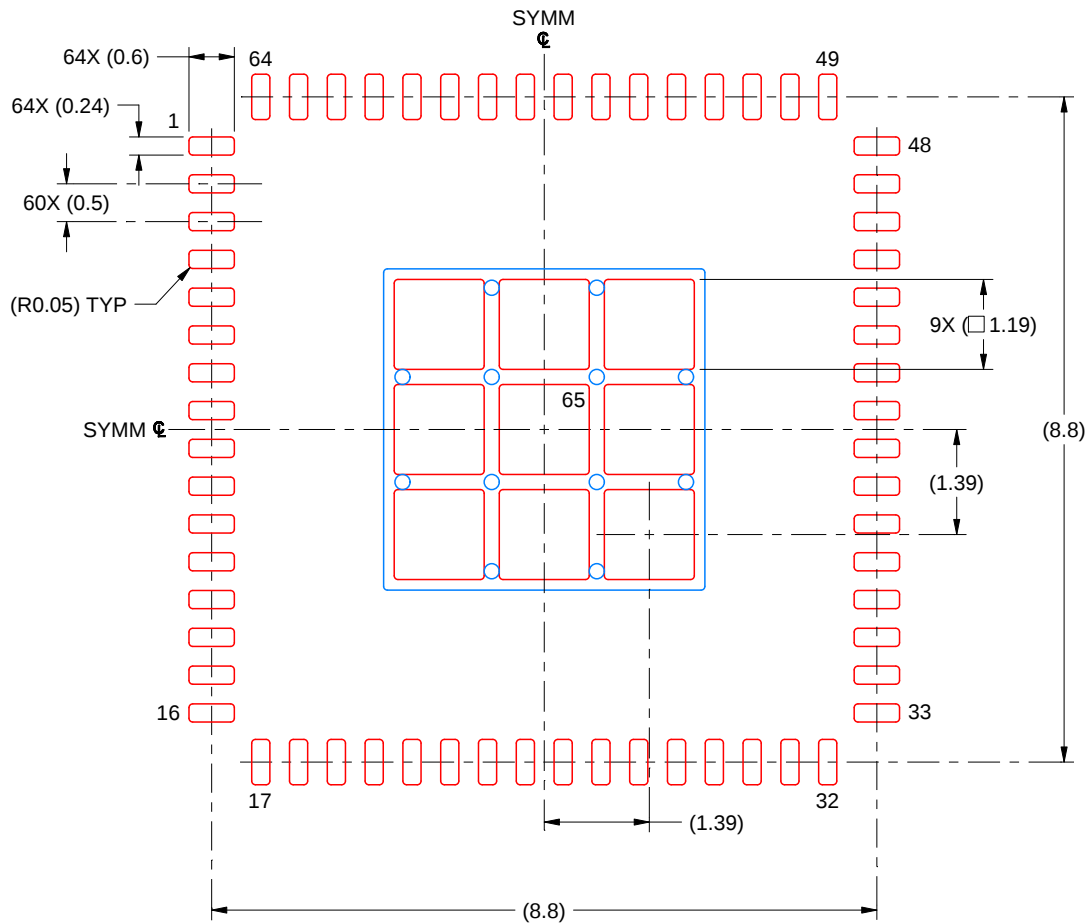
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

EXAMPLE STENCIL DESIGN

RGC0064B

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



SOLDER PASTE EXAMPLE
 BASED ON 0.125 MM THICK STENCIL
 SCALE: 10X

EXPOSED PAD 65
 71% PRINTED SOLDER COVERAGE BY AREA UNDER PACKAGE

4219010/A 10/2018

NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

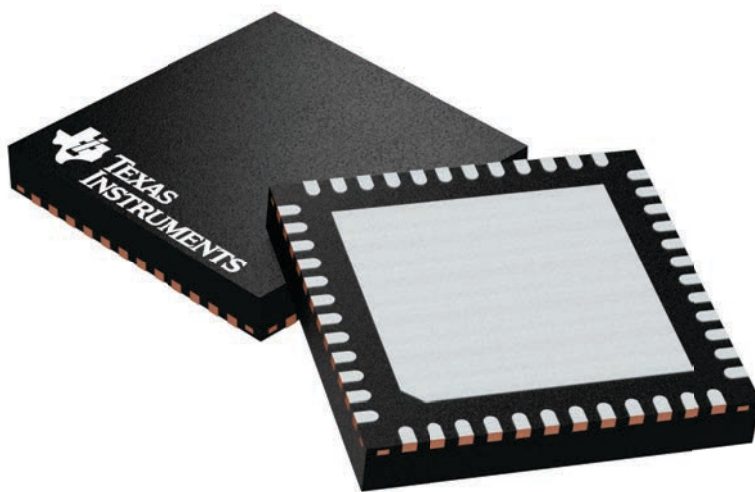
GENERIC PACKAGE VIEW

RGZ 48

VQFN - 1 mm max height

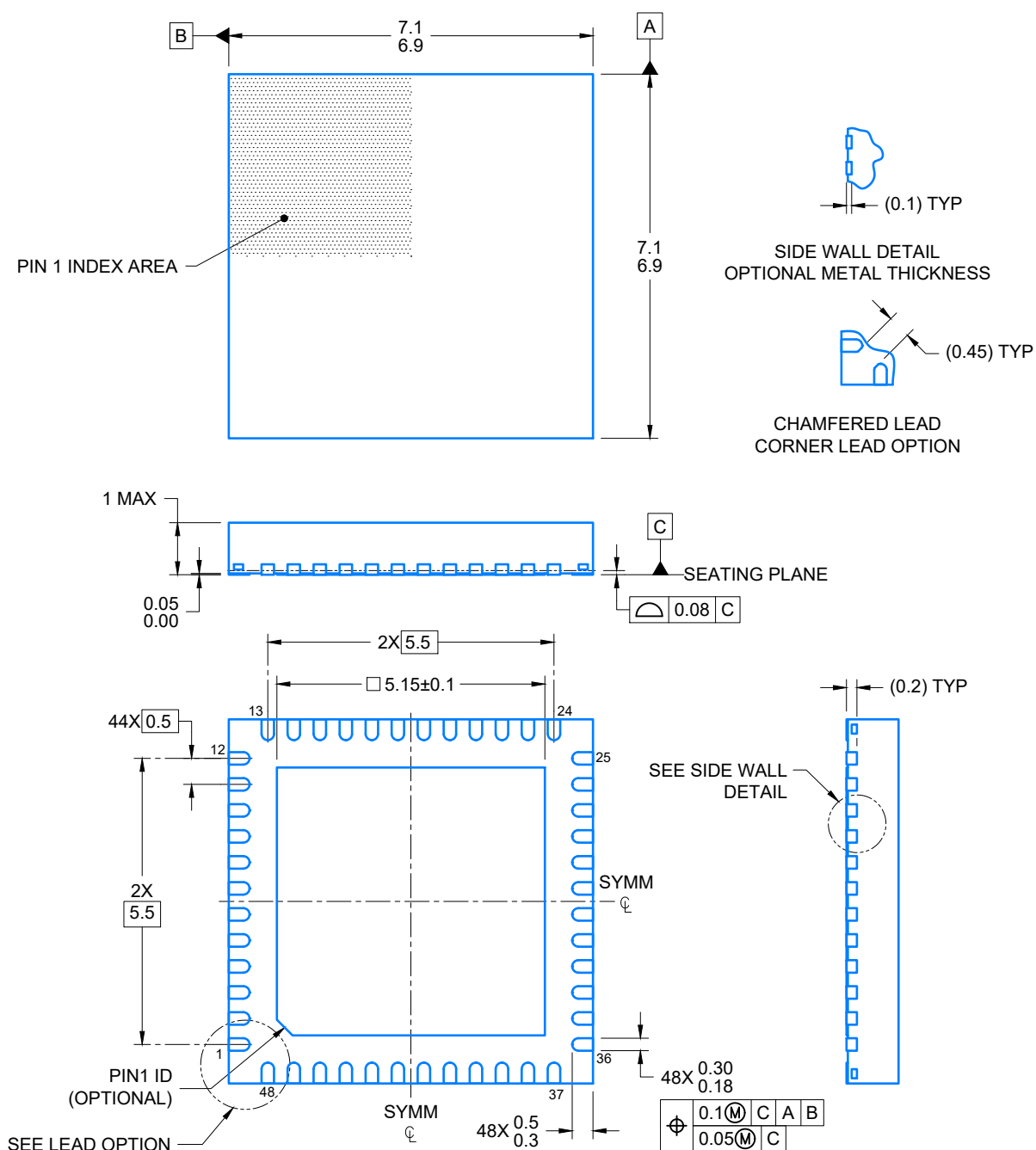
7 x 7, 0.5 mm pitch

PLASTIC QUADFLAT PACK- NO LEAD



Images above are just a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.

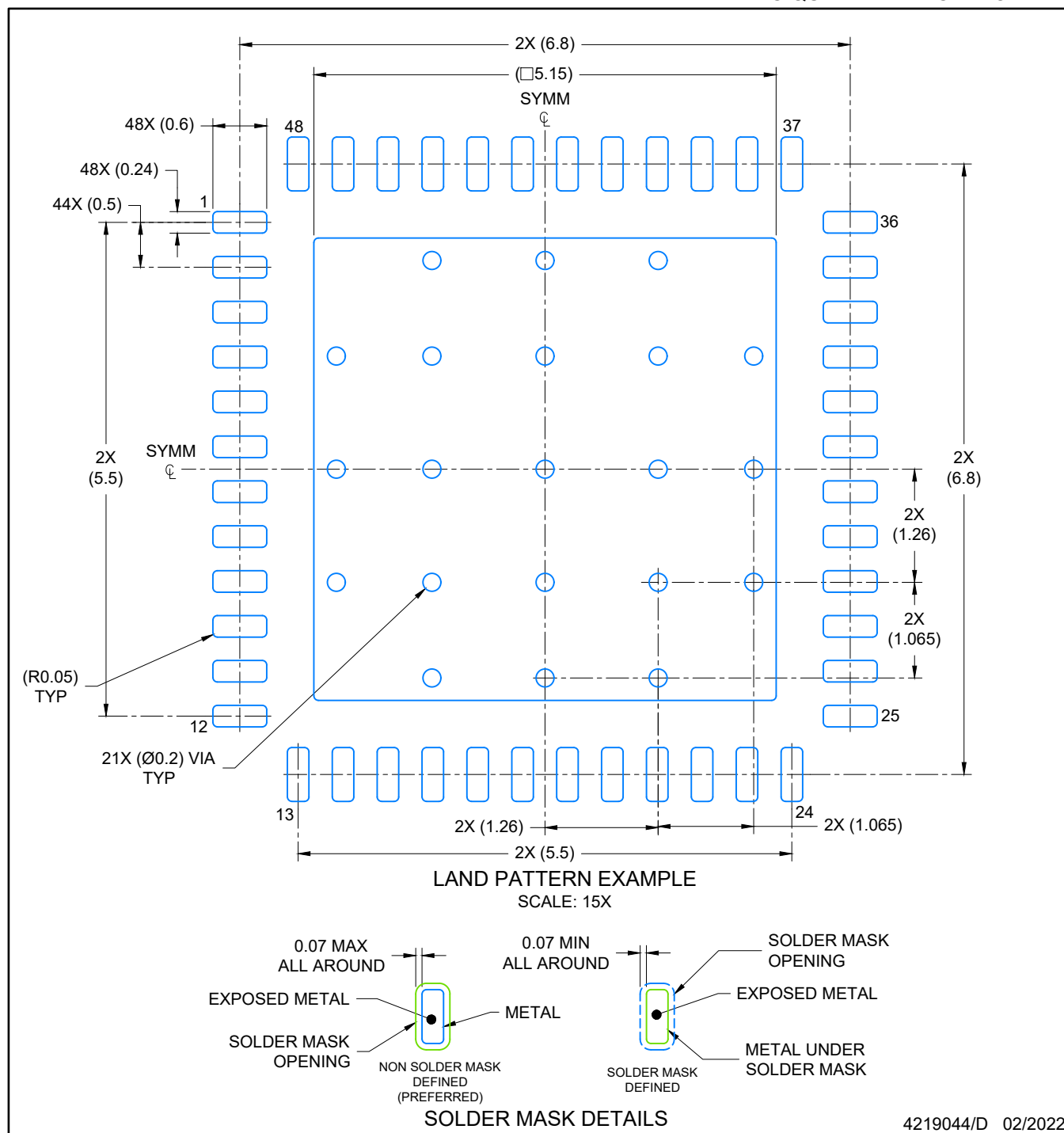
4224671/A



4219044/D 02/2022

NOTES:

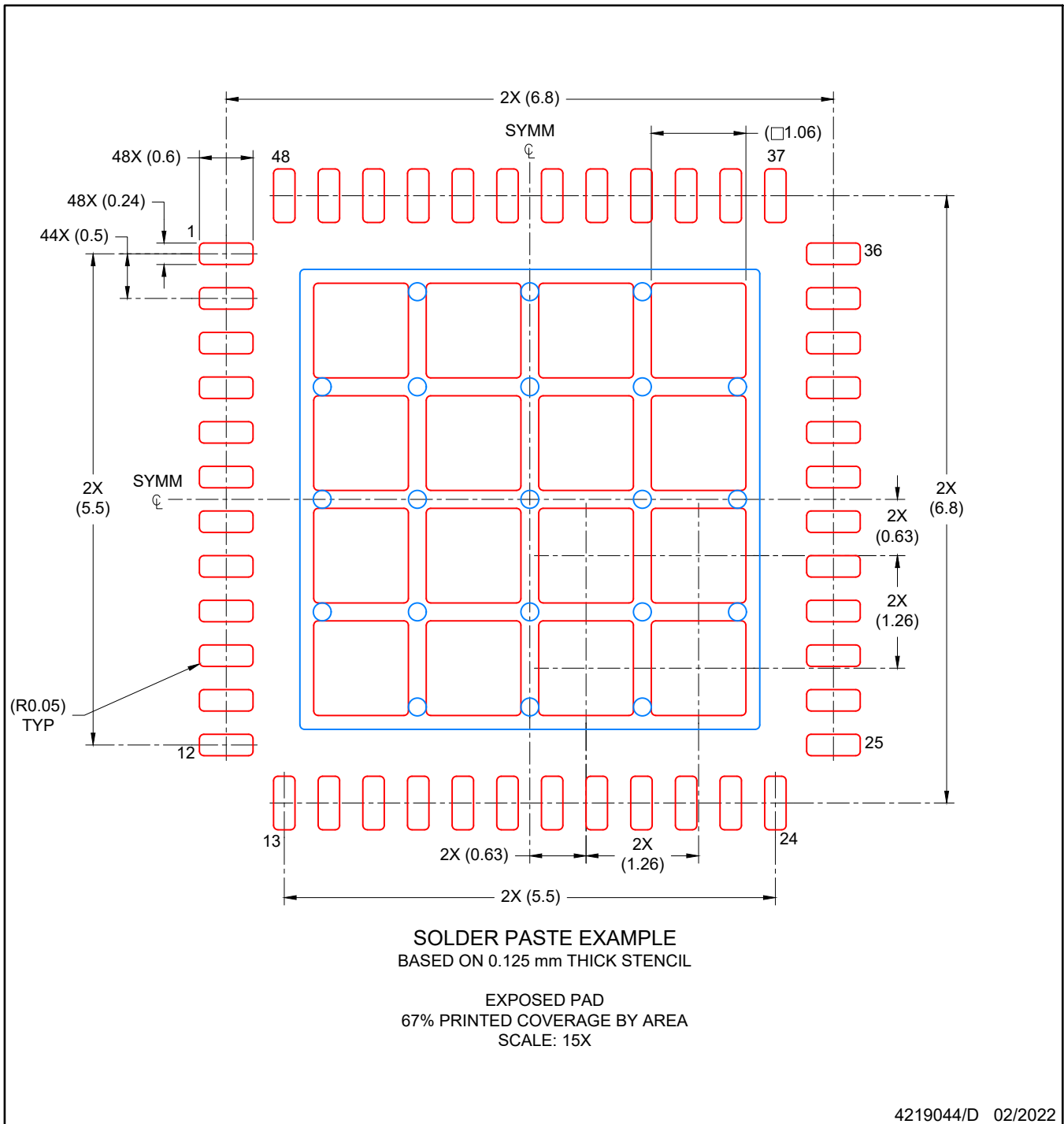
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



4219044/D 02/2022

NOTES: (continued)

- This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/sluea271).
- Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

重要声明和免责声明

TI“按原样”提供技术和可靠性数据（包括数据表）、设计资源（包括参考设计）、应用或其他设计建议、网络工具、安全信息和其他资源，不保证没有瑕疵且不做任何明示或暗示的担保，包括但不限于对适销性、某特定用途方面的适用性或不侵犯任何第三方知识产权的暗示担保。

这些资源可供使用 TI 产品进行设计的熟练开发人员使用。您将自行承担以下全部责任：(1) 针对您的应用选择合适的 TI 产品，(2) 设计、验证并测试您的应用，(3) 确保您的应用满足相应标准以及任何其他功能安全、信息安全、监管或其他要求。

这些资源如有变更，恕不另行通知。TI 授权您仅可将这些资源用于研发本资源所述的 TI 产品的应用。严禁对这些资源进行其他复制或展示。您无权使用任何其他 TI 知识产权或任何第三方知识产权。您应全额赔偿因在这些资源的使用中对 TI 及其代表造成的任何索赔、损害、成本、损失和债务，TI 对此概不负责。

TI 提供的产品受 [TI 的销售条款](#) 或 [ti.com](#) 上其他适用条款/TI 产品随附的其他适用条款的约束。TI 提供这些资源并不会扩展或以其他方式更改 TI 针对 TI 产品发布的适用的担保或担保免责声明。

TI 反对并拒绝您可能提出的任何其他或不同的条款。

邮寄地址：Texas Instruments, Post Office Box 655303, Dallas, Texas 75265

Copyright © 2022，德州仪器 (TI) 公司